



Advanced Methods of Electron Microscopy in Catalysis Research

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Contents

1. Introduction	280
2. STEM and TEM	280
2.1. The Principles of TEM and STEM Imaging	282
2.2. HAADF-STEM	285
2.3. Aberrations	287
2.4. Practical Guide for STEM Imaging	291
3. Examples of Applications to Catalyst Characterization	294
3.1. Metal Catalysts on a Crystalline Substrate	294
3.2. Metals on a Noncrystalline Substrate	299
3.3. Metals on γ -Al ₂ O ₃	301
3.4. Bimetallic Nanoparticles and Clusters	304
3.5. Understanding the Structure of Bimetallic Nanoparticles and Clusters Using Advanced Electron Microscopic Techniques	305
3.6. <i>In Situ</i> Heating Experiments of Bimetallic Nanoparticles and Clusters	316
3.7. Multimetallic Systems	318
3.8. Conclusions	318
4. Electron Microscopy of Layered Materials	319
4.1. Introduction	319
4.2. MoS ₂ Nanowire Catalysts	320
4.3. Co-Doped MoS ₂ /WS ₂ Nanowire Catalysts	326
4.4. MoS ₂ Nanoplates	334
4.5. Conclusions	337
Acknowledgments	338
References	338



1. INTRODUCTION

The study of catalytic systems has been one of the most active areas of application of electron microscopy. Indeed, a typical catalyst is made of small particles—in the size interval of nanometers to even single atoms—and a substrate that is usually polycrystalline or, in a few cases, amorphous. The catalytic particles are made either of noble or transition metals, or oxides that strongly scatter electrons and therefore produce a high contrast in the micrograph.

Most of the commercially interesting supports are also oxides or semi-graphitic carbon, which also produce high contrast; therefore, the problem of the observation of a catalytic nanoparticle through an electron microscope is reduced to separate its contrast from that of the substrate. In a few important cases, the catalysts are not even nanoparticles but are *nanoribbons*, such as those made of MoS₂, that in principle are expected to behave as semiconductors.



2. STEM AND TEM

Conventional transmission electron microscopy (TEM) is a beam characterization technique with almost 80 years since the development of the first microscope. In TEM, a large area of the specimen is illuminated, the magnification is performed by the lens system underneath the specimen, and subsequently the whole image is registered instantaneously. Conventional scanning electron microscopy (SEM) was designed after the TEM and has been widely used for surface analyses in biological and materials sciences. Scanning transmission electron microscopy (STEM) combines both operational modes. In STEM mode, a convergent electron beam is focused to a small area of the sample. To register an image, the electron probe is raster-scanned and subsequently propagated through the sample. Due to the electron-matter interaction, the trajectory of the electrons is scattered and different kinds of signals are registered in sync with the electron probe scanning. STEM resolution is determined primarily by the size of the probe. One of the main advantages of STEM over TEM is that the images generated by the electrons scattered out to high angles on a high-angle annular dark-field (HAADF) detector are chemically sensitive, and a sample with a definite crystalline arrangement is not necessarily a requirement. The capacity of STEM to generate these

different levels of contrast is commonly known as *Z-contrast*; the contrast dependence goes approximately as Z^2 , with Z corresponding to the atomic weight of the element that caused the scattering of the electrons (Pennycook, 1989).

TEM and STEM operational modes are necessary for the study of nanoparticles. The appropriate generation and interpretation of electron micrographs is crucial for this purpose. The interpretation of the electron micrographs is not always straightforward because the intensity signal that correlates with the atomic positions depends not just on the length of the atomic columns parallel to the direction of the electron beam, but also on the chemical species and the microscope's parameters at which the micrograph was obtained. In this way, the problem of extracting a third dimension from the information contained in a strictly two-dimensional (2D) image requires the comparison of the observed images against simple models acquired by previous experience or inherited, and in many cases a theoretical model of the structure is necessary.

In TEM, the information transfer in phase-contrast imaging is determined by the objective lens and the size of its aperture, which are directly related to the temporal and spatial coherence of the electrons. In Figure 4.1, a conventional high-resolution transmission electron microscopy (HR-TEM) micrograph of a bimetallic nanoparticle 2 nm in diameter shows the interatomic distances; however, the contrast is not directly related with the different atomic positions in the bimetallic nanoparticle (Corthey *et al.*, 2010) proposed by the theoretical model shown in Figure 4.1b.

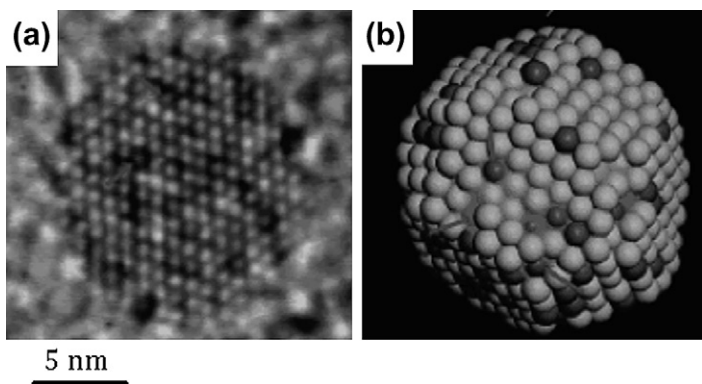


Figure 4.1 (a) HR-TEM image of a bimetallic gold-palladium nanoparticle. (b) Theoretical model of the bimetallic nanoparticle.

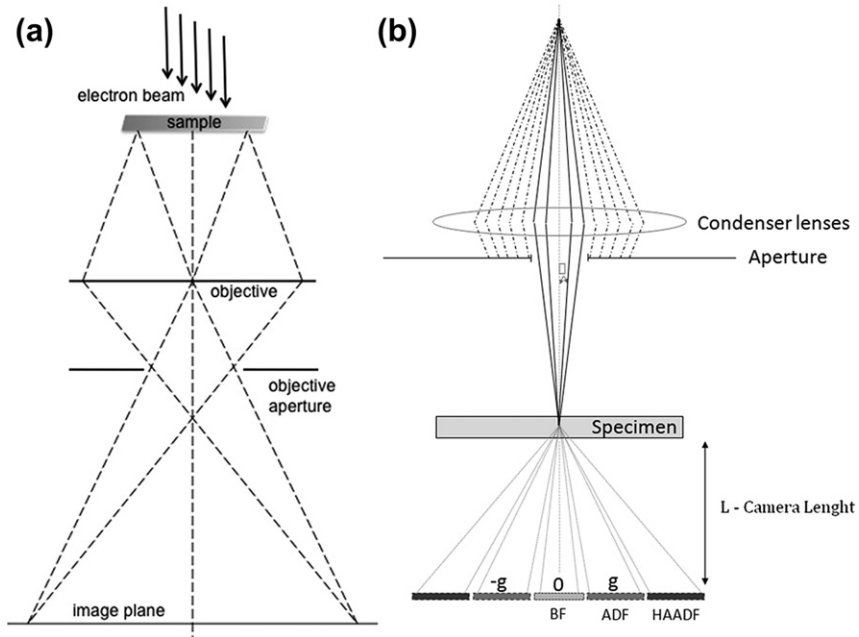


Figure 4.2 Simplified diagram of the (a) TEM and (b) STEM operational modes.

The optical arrangement of a conventional TEM compared with the STEM configuration is illustrated in the schematic diagram shown in Figure 4.2.

2.1. The Principles of TEM and STEM Imaging

Unlike macroscopic objects, whose structural properties can be inferred directly by investigating how a *beam of light* interacts with the object, the study of matter at the nanoscale requires investigating how a *beam of electrons* interacts with the sample, since wavelengths on the order of Ångströms (or even smaller) are required to reach this level of resolution. This electron beam is produced by accelerating the electrons by applying a potential difference of several kilovolts to an emitter, usually a field emission cold cathode; other electron sources use thermionic emission to overcome the work function of the cathode. Originally, the beam is not monochromatic but an energy-selecting spectrometer can be added to the electron gun, at the price of diminishing the beam current. A first electrostatic lens called Wehnelt makes the beam reaching the anode more convergent (Rose, 1990). An aperture on the anode plate allows

the beam to actually get into the microscope. A field emission gun (FEG) actually has two anodes: the first one in charge of producing the beam, the second one in charge of accelerating the electrons (Reimer and Kohl, 2008).

When the beam produced by the electron gun interacts with a sample, different signals are generated. Most of the electrons are transmitted through the sample with just a small deviation from the optic axis (the original trajectory of the electron beam); when collected, this signal is used to produce bright-field (BF) images. Signals transmitted at higher angles can be collected using an angular detector to produce dark-field (annular dark-field [ADF], HAADF) images or the energy of the electrons can be measured to generate electron energy-loss spectroscopy (EELS) maps. The chemical composition of the sample can be investigated by analyzing the X-rays generated when the electrons in the sample are excited by the beam—what is called *energy-dispersive X-ray* (EDX) spectroscopy. Auger electrons can be generated by a somewhat complex process: The beam causes the ejection of an inner-shell electron of the specimen; the formed vacancy is filled by an electron of a higher level and the excess energy liberates a third electron, called an Auger electron.

TEM is a powerful technique to characterize the structure and chemical composition of condensed matter. Conventional TEM (CTEM) includes basically three operation modes: diffraction contrast (BF and dark-field [DF]), phase-contrast (HR-TEM), and electron diffraction (ED). These three operating modes provide information about the crystalline structure in the materials, morphology, structural defects, and even chemical composition. Complementing CTEM, it is also possible to use STEM. Figure 4.2 shows the trajectory of the electrons in a TEM for both the TEM and STEM modes. Both modes are based on the interaction of an electron beam, generated by an electron gun at the top of the microscope, with the lenses and the specimen.

BF-CTEM is the simplest and most frequently used mode of operation of a TEM. In this mode, the images are formed by the direct (nondiffracted) electron beam, while an aperture blocks the diffracted beam. In these images, regions with no particles (and maybe just the carbon grid) appear as bright. DF images are generated by a detector that collects only the diffracted electrons. The regions with no particles appear dark—hence the name *dark field*. While in DF micrographs contrast is enhanced, BF images require a less-intense beam; thus this technique is less intrusive.

In high-resolution electron microscopy, the image can be considered the result of the interference of the transmitted and the diffracted beams after the interaction with the sample. Thus, the sample must be thin enough to transmit the electrons. When nanoparticles are being prepared for analysis by TEM or STEM, it is common to prepare the specimen by placing the nanoparticles on holey carbon copper grids. In some synthesis procedures, the nanoparticles are covered with a layer of organic ligands (Corthey *et al.*, 2010); if required, this organic layer can be removed by exposing the specimen to a beam shower for a few minutes before placing it in the microscope.

At the range of operating voltages of modern electron microscopes, the electron's momentum is very large—large enough that it is necessary to take into account relativistic corrections to describe correctly the interactions (Carter and Williams, 2009). The equation that considers the interaction of the electrons with the specimen and lenses requires some adjustments on the values of mass and wavelength. In a strict formalism, the equation that governs these interactions is the relativistic Dirac equation, but it is customary to use instead the approximated, easier-to-manipulate Schrödinger equation since the Dirac equation is very difficult to deal with, even in the simplest cases. In its most basic version, the role of the specimen is represented in the Schrödinger equation by its projected electrostatic potential. For sake of simplicity in this brief description, we can assume a periodicity condition in this potential (as if being produced by a periodic crystal). Let this potential be represented by $\Phi(r)$. The specific details of $\Phi(r)$ depend mainly on the chemical composition and structural features of the specimen, but a better description would also include thermal effects. The Schrödinger equation that describes the interaction of this potential with an electron of mass m and charge e coming from the source is

$$\left[-\frac{\hbar^2}{8\pi^2 m} \nabla^2 - e\phi(r) \right] \Psi(r) = E\Psi(r),$$

and the wave function of the electron wave *before* interacting with the specimen can be described by using a simple plane wave:

$$\Psi_0(r) = \exp\{i(\omega t - 2\pi k_0 \cdot r)\}.$$

The solution to Eq. (1) describes the electron wave function *after* the interaction of the beam with the specimen. In practice, the task of finding a solution requires a set of approximations in addition to the periodicity

assumption and the plane wave nature of the incoming beam, such as assuming that the specimen is not very thick.

The objective lens is positioned just after the sample in a TEM and it focuses the electron beam; the role of the objective lens can be described mathematically by the Fourier transform of the electron beam wave at the exit of the sample. Unlike the lenses used in visible light microscopes, both the objective and corrector lenses in the electron microscope are made of a magnetic field generated by an electric current circulating a coil, which affects the trajectory of the electron beam. In an ideal microscope with no aberrations, the image observed will be directly related to the squared modulus of the image-plane wave function (Reimer and Kohl, 2008). But in the real world, the objective lens is not perfect and introduces aberrations in the image-plane wave function. The most recent models of high-resolution microscopes include in their design additional coils that act as aberration correctors that make sub-Ångstrom resolution possible.

2.2. HAADF-STEM

From the standpoint of the electron beam, a STEM is an inverted TEM in the sense that the trajectory followed by the beam through the optical components of the STEM is the same as in the TEM but in the opposite direction. The reciprocity theorem states that the propagation of the beam is time reversible, and thus if in the TEM the detector is exchanged with the FEG, the system becomes basically a BF-STEM. A consequence of this equivalence is that, unlike with CTEM, the electron beam interacts with only a small section of the sample at a time (a pixel in the image), and so a scan process, made by deflecting the beam using a set of coils, must be used to generate the image of the entire specimen. The width of the beam (the *probe*) greatly determines the resolution of the STEM, and C_s correction is mandatory to obtain sub-Ångstrom resolution.

The scattered electrons in STEM mode can be registered by three different detectors. The BF detector collects the electrons transmitted in the path of the beam close to the optical axis, the BF electrons containing the total beam current. The annular dark-field (ADF) and the HAADF detectors are used to record the electrons scattered out of the path of the beam. In the STEM, the objective lens—and all the relevant optics—are positioned before the specimen. The scattered angle of the ADF detector is set around ~ 40 mrad and the outer angle is set around 60–200 mrad

(see Figure 4.2). STEM differs from CTEM in that the electron beam interacts with only a small section of the sample; the scanning process is the one in charge of generating the image as a whole, whereas in TEM, a broad beam is interacting instantaneously with the sample. X-ray energy-dispersive spectroscopy (EDS) attached to the STEM mode provides an elemental analysis directly from the point or line raster-scanned in the sample. Therefore, the imaging using the BF or HAADF detectors in a complementary way can be matched to the EDS information, and the elemental mapping at atomic resolution is obtained. Figure 4.3 shows the setup of the STEM mode including the detectors previously mentioned. HAADF and BF images are indicated on the right side of Figure 4.3, and both can be acquired simultaneously. L corresponds to the camera length, which is the effective distance or magnification between the specimen and the detector plane position. The X-ray detector is included in Figure 4.3; the spectra can be collected at the same they are line scanned to register the STEM images.

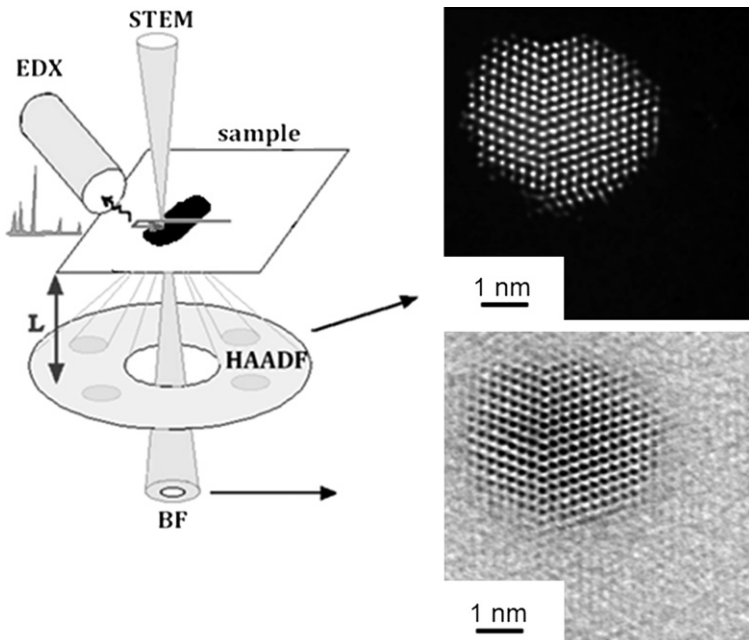


Figure 4.3 STEM setup, including the EDS spectrum detector. L corresponds to the camera length.

2.3. Aberrations

Aberrations are artifacts produced by the imperfections on the equipment. We have already described correction of chromatic aberration before the interaction of the electron beam with the specimen. Astigmatism and coma can be easily corrected using magnetic quadrupoles (Koch, 2002). Spherical aberrations, denoted C_s , are far harder to correct, but the corrections are necessary to produce images of atomic resolution. The objective lens, located behind the specimen in a TEM, focuses the electron beam, which mathematically can be described by the Fourier transform of the wave at the exit of the sample. Imperfections in the objective lens are the source of C_s , and additional optics is needed after this element to make the appropriate corrections.

The effect of C_s can be appropriately explained in terms of the contrast transfer function (CTF). In short, the CTF is used to determine how the different spatial frequencies will be represented in a TEM image. The electron wave function at the image plane will be related to the CTF applied to the wave function only at the exit of the sample. In a spatial frequency range where the CTF is approximately constant, the distances and sizes of objects will be represented directly on the micrograph, while in a range of spatial frequencies where the CTF varies greatly, it would be quite difficult to determine whether a bright spot in the micrograph corresponds to the presence or absence of an atom. Objective apertures, the spatial coherence of the electron beam, and its wavelength will affect the CTF. Its definition is

$$CTF(k) = -\sin\left[\frac{\pi}{2} C_s \lambda^3 k^4 + \pi \Delta z \lambda k^2\right].$$

Here, C_s is the spherical aberration of the objective lens and Δz is its defocus. A setting of particular interest is

$$\Delta z = -\sqrt[4]{\frac{3}{2}} C_s \lambda.$$

called the *Scherzer condition*. At the Scherzer defocus, the CTF does not change its sign in a large spatial frequency range; hence all distances in this range can be interpreted directly as they appear in the image (Reimer and Kohl, 2008; Carter and Williams, 2009).

Figure 4.4 shows the results of conventional HR-TEM simulations of a section of a gold lattice at different values of defocus, Scherzer included (-50 \AA). The voltage was 200 kV in all cases, and a small aberration of

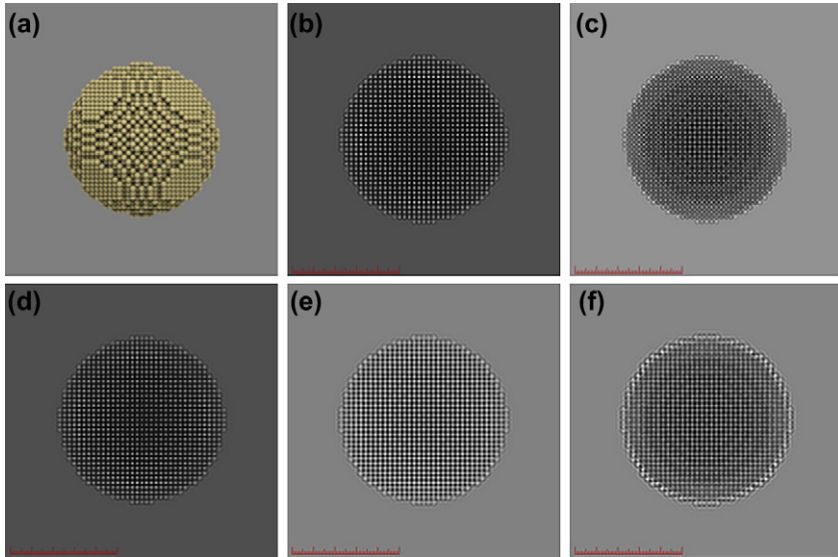


Figure 4.4 HR-TEM simulations of a spherical fcc gold nanostructure, calculated at different defocus values. (a) Model of the particle; (b) $\Delta z = -100\text{\AA}$; (c) $\Delta z = -50\text{\AA}$; (d) $\Delta z = 0\text{\AA}$; (e) $\Delta z = 50\text{\AA}$; (f) $\Delta z = 100\text{\AA}$; The image labeled as (c) corresponds to the Scherzer defocus. (See the color plate).

0.01 mm was used with zero astigmatism. At Scherzer defocus, the atomic columns are completely resolved, even at the surface of the structure.

Aberration correction in TEM highly enhances the spatial resolution to such a degree that it is even possible to reach sub-Ångstrom level. The implementation of multipole corrector lenses in the electron optics system was developed in the 1990s, when the first correctors of the spherical and chromatic aberrations appeared. Probably the best way to acquire a sense of the need for C_s correction to reach sub-Ångstrom resolution is by comparing micrographs obtained under the same conditions except for the spherical aberration. This is, of course, impossible to do in practice, but it is possible instead to compare the results of TEM simulations at different values of C_s . Figure 4.5 shows a comparison that illustrates this.

The Z-contrast technique works remarkably well in metal nanoparticles because the intensity dependence on atomic number is close to $Z^{3/2}$, with minimum dependence on microscope defocus (Wall, 1974). This is definitely different from what is expected of BF imaging, where the signal varies

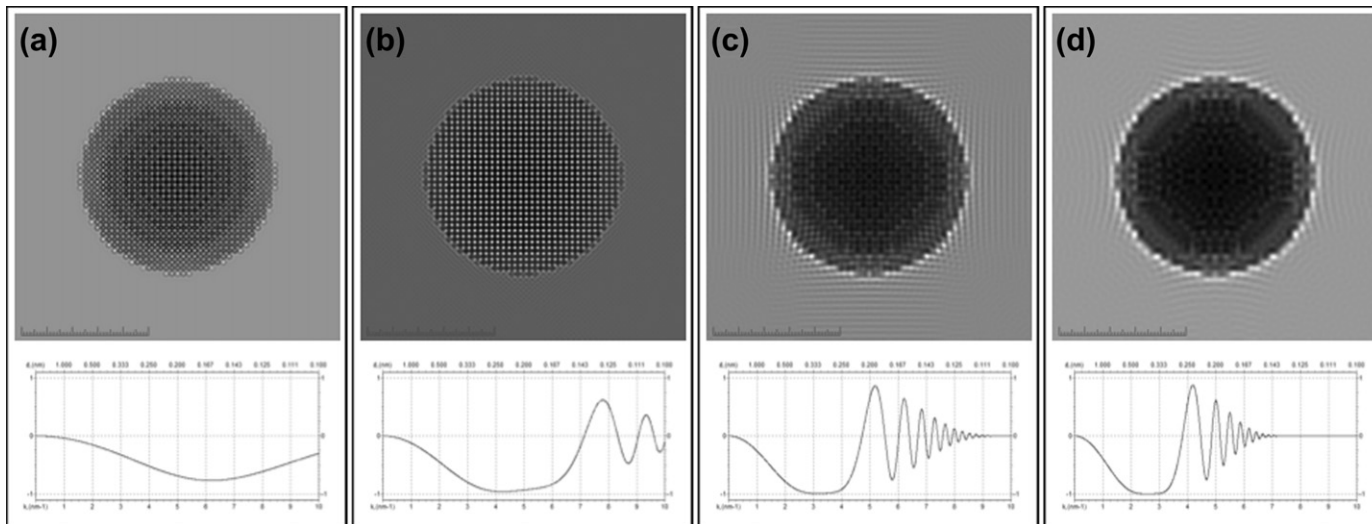


Figure 4.5 Simulated TEM micrographs calculated at several values of C_s and their corresponding contrast transfer functions. (a) 0.01 mm; (b) 0.1 mm; (c) 0.5 mm; (d) 1.2 mm.

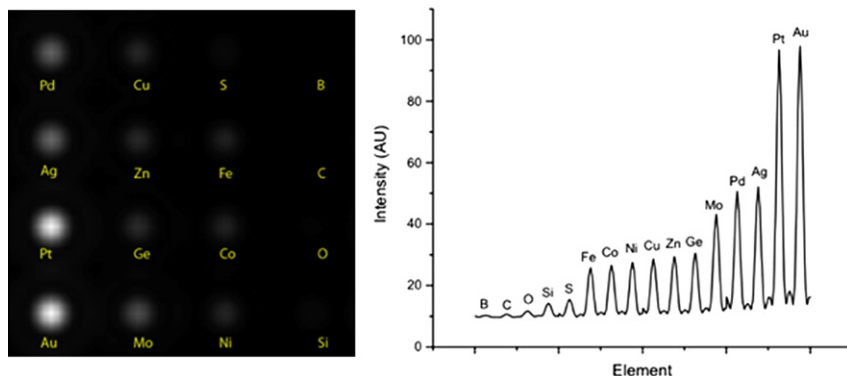


Figure 4.6 Profiles of intensity obtained from a series of HR-TEM simulated images (at a defocus of -41 nm). Note the intensity variation with the different elements. In each case, the columns of elements have the same number of atoms. (For color version of this figure, the reader is referred to the online version of this book).

weakly and nonmonotonically with Z . In HAADF-STEM, the differences among metals are evident. Figure 4.6 shows a Z -contrast STEM simulation of single atoms of different elements arranged in a 4×4 matrix. The line scan through the center of the atomic positions is shown at the right of the simulated image. The trend follows approximately a $Z^{1.46}$ relation, very close to the dependence expected by Pennycook and Boatner (Pennycook, 1998).

When used to image metal nanoparticles, 200 kV is a common operation voltage in an HAADF-STEM, although lower voltages would allow investigation of the presence of molecules on the nanoparticle surface and a deeper understanding of the structure of the support matrix surrounding the nanoparticle. The HAADF detector is set normally at an inner angle ~ 50 mrad, and the outer angle is set ~ 100 – 200 mrad.

STEM-HAADF is extremely useful for size determinations in catalysts. This is exemplified in Figure 4.7. Several STEM micrographs of gold nanoparticles were used to generate a histogram of sizes. Figure 4.7a shows one of these micrographs. The particles, well distributed on the substrate, are easily recognized by the software once a threshold value of intensity and a minimum particle size are defined; Figure 4.7b shows the histogram. In this example, the statistics gave a mean size of 2.3 nm, with a standard deviation of 0.49 nm. Several factors may affect the confidence on the size measurements, such as out-of-focus regions in the image or a low contrast level. This kind of procedure is extremely useful in catalytic research.

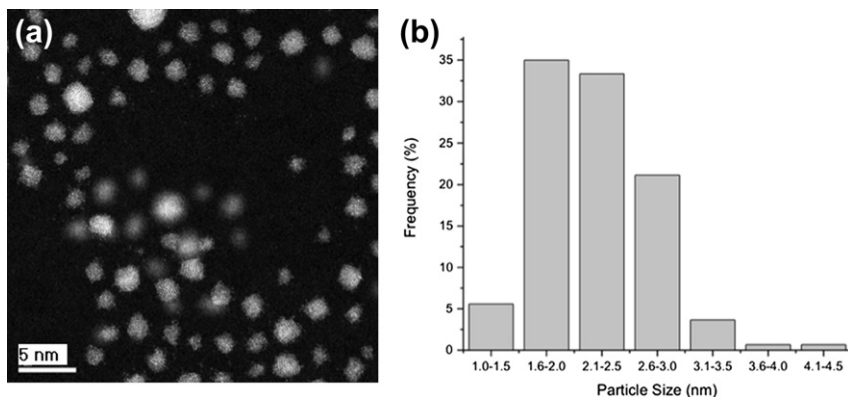


Figure 4.7 Histogram of sizes of gold particles obtained using STEM-HAADF images. Since no delocalization is produced on the image, the size distribution is more accurate.

2.4. Practical Guide for STEM Imaging

The basic parameters described in this section are used to register high-resolution STEM images. The process must be started in TEM mode for the selection of the field of view and to adjust the crystal orientation, if needed. The eucentric focus must be adjusted with the z -control. By following the TEM initial setup, the system can be switched to STEM. The illumination focused on the sample must be adjusted by varying the size of the condensed aperture, the spot size, and the camera length (L). Camera length is the effective distance or magnification between the specimen and the detector plane position. The collection angle depends on microscope camera length. Typical collection angle values for ADF and HAADF detectors are close to 40 and 200 mrad, respectively.

The resolution in STEM depends on the spot size of the electron beam. Spot size and the aperture of the condenser lens influence the beam current density in the sample and, as a consequence, on the resolution of the instrument. The beam current density in the sample can be increased either by a large aperture of the condenser lens or by using a lower spot size. Figure 4.8 shows two sketches for the rays under two different settings for STEM. Increasing the spot size (spot number) leads to increased demagnification of the source and a decreased current in the beam. Increasing the spot number leads to a reduction of the beam current.

Changing the size of the condenser lenses CL1 and CL2 also changes the beam current. Figure 4.9 sketches the rays corresponding to two

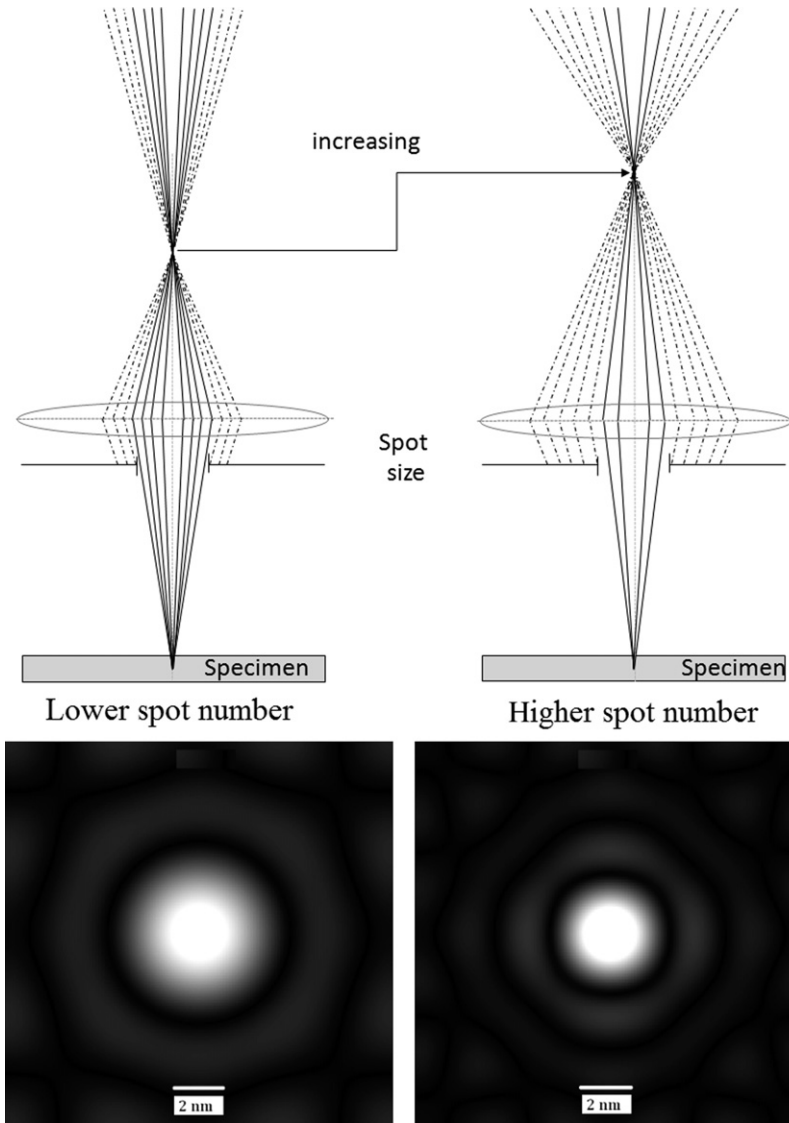


Figure 4.8 Electron beam sketches varying the spot size and the potential projected simulated depending on the spot size.

different sizes of the condenser apertures. The selected aperture must be centered in the ronchigram (described in next section) as shown in Figure 4.9.

Spot size and aperture of the condenser lens determine the resolution of the microscope in STEM mode. The spot size, measured in

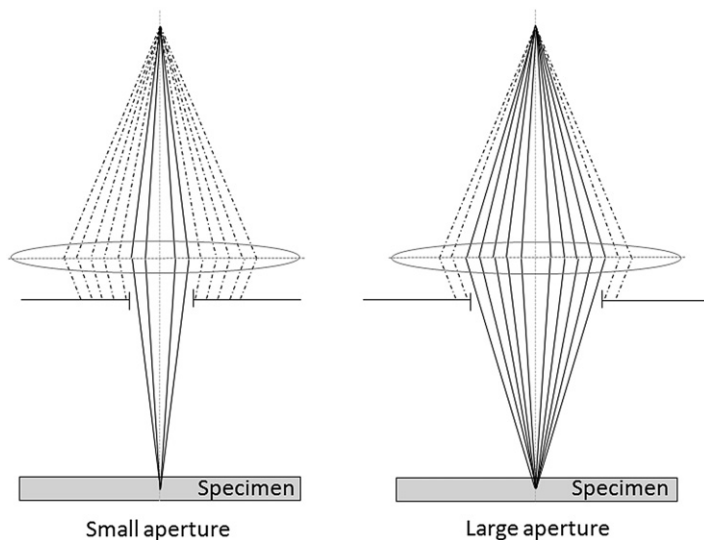


Figure 4.9 Electron beam trajectories by varying the condenser lens apertures.

nanometers, can be simulated as a function of the parameters of the microscope (Zuo, 2008).

A very useful tool is the ronchigram, which is a shadow image formed by a focused and stationary electron probe on amorphous material. The quality and resolution of the STEM images depend directly on the proper alignment of the ronchigram. It is easily observable in FEG microscopes, but it might be difficult to obtain when lanthanum hexaboride (LaB_6) filament sources are used because the effective probe size is too large; therefore both the spatial resolution and the brightness decrease dramatically even with microscopes with voltages exceeding 200 kV. All the parameters that affect contrast and spatial resolution also affect the ronchigram. The ronchigram can be registered in a charge-coupled device camera. The ronchigram is also known as the Gabor hologram, or as the central zero-order disk of the convergent beam electron diffraction (CBED) pattern. The ronchigram from an amorphous region should look as in Figures 4.10a and 4.10c. The shape of the ronchigram can be simulated using the parameters of the microscope (Zuo, 2008).

In the ronchigram, the focus spot must be represented in the center of the shadow image as a region of infinite magnification. Overfocus, in-focus, and underfocus ronchigrams and the beam incident on the sample are illustrated in Figure 4.11.

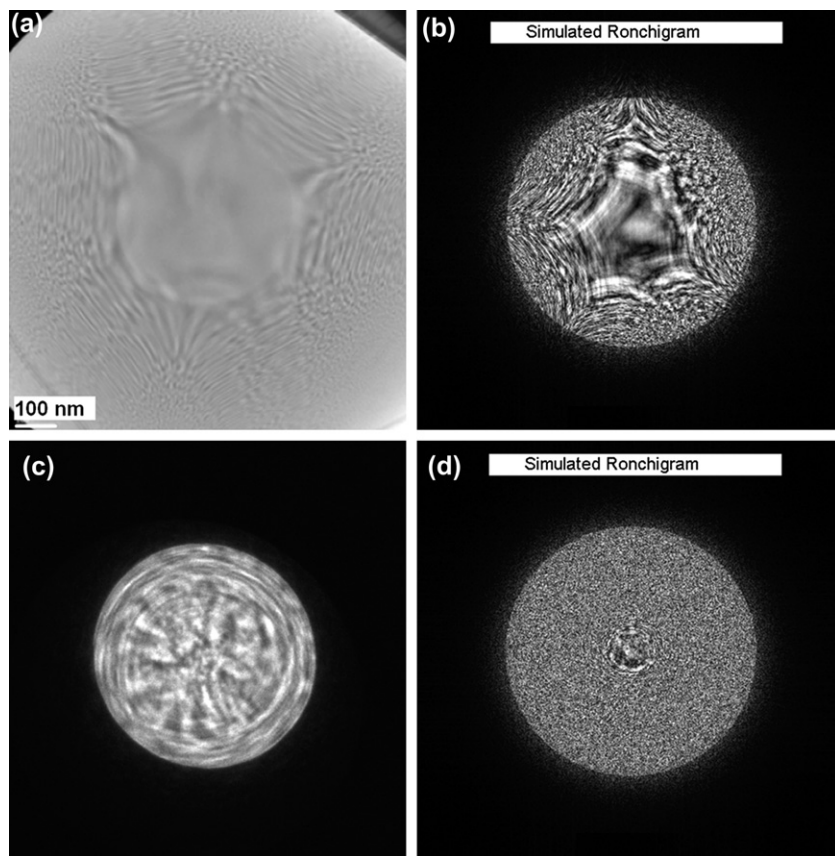


Figure 4.10 Aberration-corrected (a) experimental ronchigram from an amorphous material. (b) Calculated ronchigram. (c) aberration-uncorrected experimental ronchigram from an amorphous material. (d) Calculated ronchigram.



3. EXAMPLES OF APPLICATIONS TO CATALYST CHARACTERIZATION

3.1. Metal Catalysts on a Crystalline Substrate

For metal catalysts supported on a crystalline substrate, the best technique to observe the nanoparticles is STEM–HAADF, because with this technique the reflections of the metal and the substrate are clearly separated on the reciprocal space and it is straightforward to visualize the nanoparticles. A very common support for metal nanocatalysts is TiO_2 , which is very easy to grow and has been used extensively (Diebol, 2003). Figure 4.13a shows an example from the laboratory of Dr. Gabriela Diaz at the Institute of

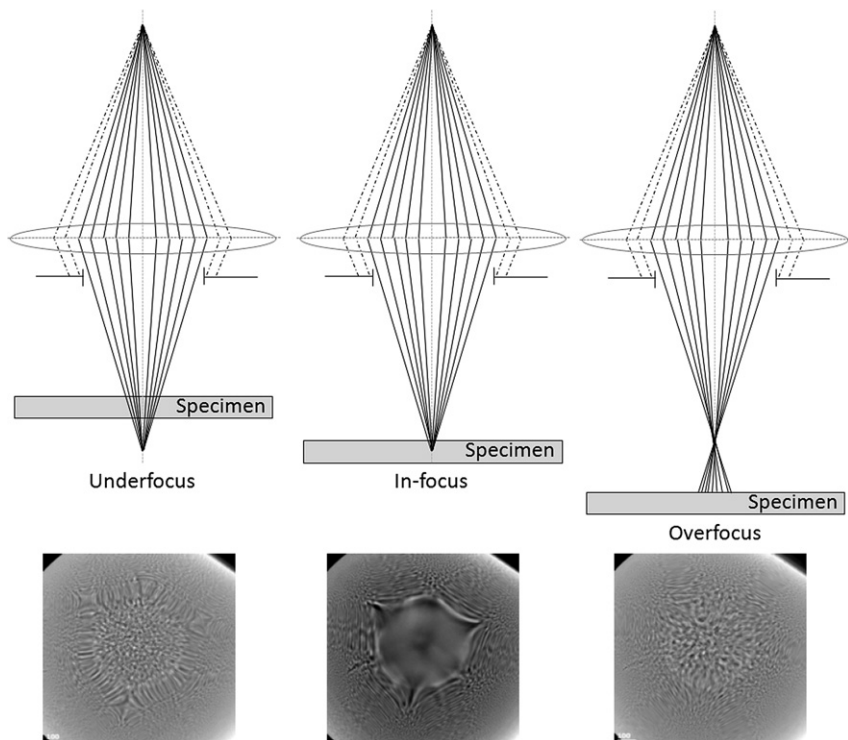


Figure 4.11 Ronchigram for different focus conditions.

Physics at the National Autonomous University of Mexico (UNAM). The micrograph corresponds to an iridium metal supported on a TiO_2 (anatase) substrate. The metal clusters are clearly seen as formed white spots, each representing an atomic column. To further demonstrate the potential of the technique we can measure the intensity profile of the spots, and since there is only one metal on the sample, the intensity should be proportional to the number of atoms on the column. Figure 4.12b shows the intensity profile for the cluster marked with an arrow in Figure 4.12a. The profile indicates that the four columns have the same number of atoms indicating a flat or “raft” shape (Jang *et al.*, 2009). A further calibration of the intensity is required if the exact number of atoms is to be determined. In this case, we must first filter the substrate contribution and find a suitable region with isolated atoms. In any case, the relevant information for catalysis is that the atoms will expose a (100) facet to the reactant species. A cube-shaped iridium metal (Figure 4.12c) is not expected to be stable by itself but the presence of the crystalline surface makes it stable.

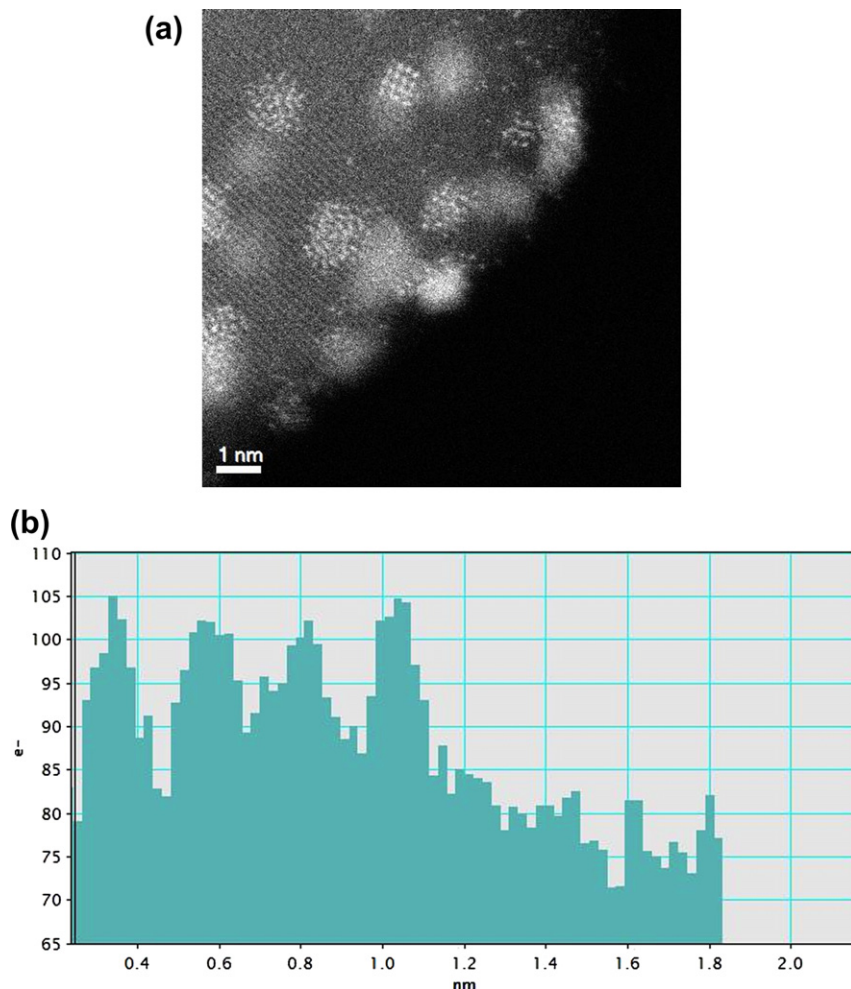


Figure 4.12 (a) STEM-HAADF image of an iridium supported on a TiO₂ crystalline substrate. The clusters of metal are apparent. (b) Intensity profile of the atomic columns of the cluster marked with an arrow in (a). (See the color plate).

Figure 4.13 shows the dramatic difference between bright (STEM) and HAADF-STEM for an Au/TiO₂ catalyst. In the BF mode only the crystal structure of the catalyst can be observed. However, in the DF image not only clusters but also single atoms can be observed. Clearly, STEM-HAADF should be used when possible. The question that now arises is: Can some chemical information be obtained about clusters this size? The first point that should be very clear in this chapter is that while X-ray EDS and EELS

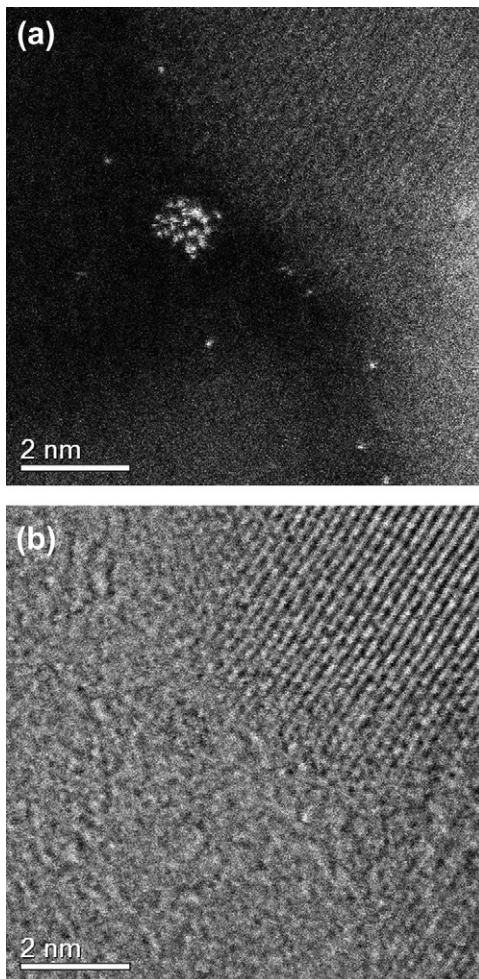


Figure 4.13 Images of an Au/TiO₂ catalyst showing the contrast of the two techniques: (a) HAADF and (b) BF-STEM of the same area.

(Friel and Lyman, 2006; Stroppa *et al.*, 2012) are great techniques to accomplish chemical mapping and can be used in catalysis, as shown in other sections of this work, they are very limited for small clusters. Indeed, in many relevant cases the catalysts will be ultra-dispersed—that is, they will contain a few atoms or their size will be a few nanometers. This allows the catalyst to have a large number of atoms at the surface (or even in an ideal case, all the atoms in the surface). However, the number of X-rays emitted by the clusters during a microanalysis study will be low and the signal-to-noise ratio will be unacceptable. Often a catalyst researcher not fully familiar with the

TEM technique expects the chemical composition of its clusters to be determined atom by atom. This certainly can be done in larger samples such as thin films or grain boundaries and even in nanoparticles larger than ~ 5 nm. However, it is not possible for particles < 5 nm.

The same situation applies to EELS analysis. Is this the end of the road for chemical identification in very small clusters? The answer is no. STEM-HAADF can yield important information. Figure 4.14 shows an

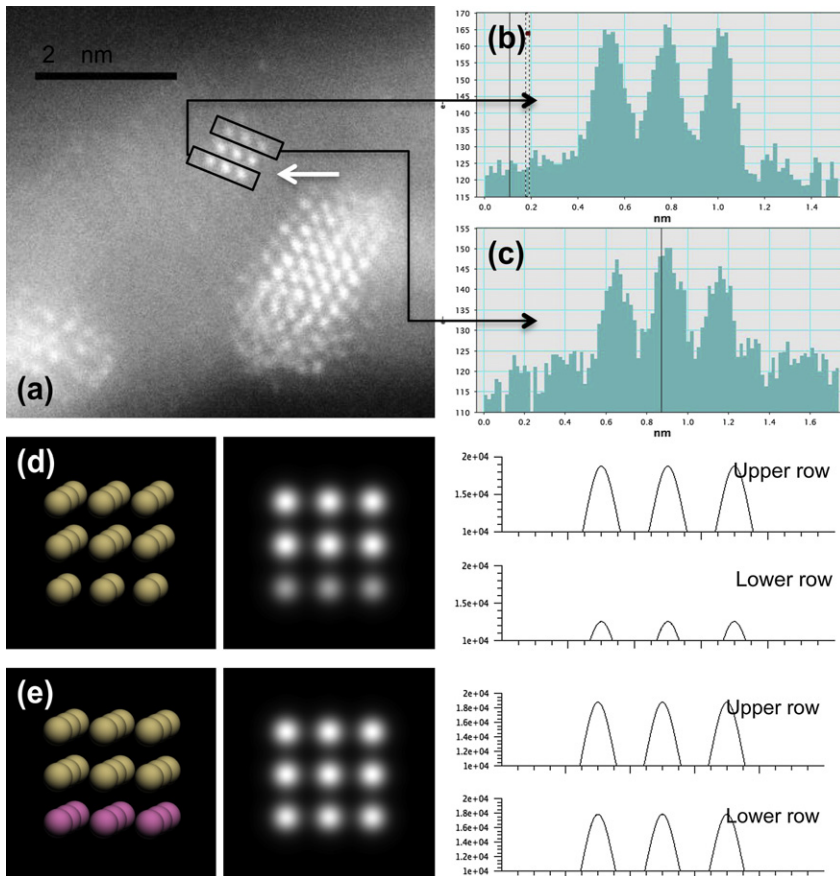


Figure 4.14 (a) STEM-HAADF Image of a Au/Ir alloy supported in TiO_2 . The cluster marked with an arrow formed by 3×3 columns of atoms is analyzed. (b) Intensity profile of the first (bottom) row. (c) Profile of the third (top) row. Two possible models that are consistent with the data: (d) a stepped structure and (e) the Janus or “eutectic” type of structure. On the right, the simulated STEM micrographs and intensity profiles (arbitrary units) for the models in (d) and (e) are also shown. (See the color plate).

example of a gold-iridium alloy supported on TiO_2 . Figure 4.14a shows the HAADF-STEM image of these clusters. If we analyze the rectangular cluster marked by a white arrow, we can obtain the signal intensity for each column of atoms. Figure 4.14b shows the profile for the row of atoms at the bottom. The profile for the next row is similar to the one of Figure 4.14b. However, the row at the top has the same profile but with a lower value of the intensity shown in Figure 4.14c. There are two possible explanations. The first is that all the atomic columns are thicker than one monolayer and all atoms have the same atomic number. In that case, the decrease in intensity would have to be explained as a step on the structure (as shown in Figure 4.14d). The other situation can be obtained by noting that the ratio of the intensities is 0.94 and if we assume that the last column is iridium and the first two are gold, then the ratio of the STEM signals according equations described before is 0.94. Therefore, a very plausible model is the one shown in Figure 4.14e in which one row corresponds to iridium atoms and two rows correspond to gold atoms. This is the Janus-type particle. Of course, this is not a definite proof and additional data are required. A careful calibration of intensities for a more involved model can be made to obtain intensities using the methods described in Kotaka (2010) and Recnik (2005).

3.2. Metals on a Noncrystalline Substrate

A second relevant case concerns particles supported in an amorphous or semi-amorphous substrate. In this case, the contrast is more complicated since the substrate also has incoherent electrons scattered at high angles, thus increasing the signal-to-noise ratio. Therefore, a more careful interpretation is needed. A typical case is that of the metals supported on Vulcan carbon. Figure 4.15 shows such an example for iridium. Clearly, the HAADF-STEM image can be used to very accurately determine the particle size in large areas (and the particle size distribution). The fact that no delocalization effect, which is very pronounced on field emission microscopes, is present on this type of images (Carter and Williams, 2009) makes the size determination very accurate.

In some special cases, the Z-contrast can be nicely combined with BF images to complete the picture. Figure 4.16 shows an example in which a platinum nanoparticle is supported in a carbon fullerene onion (CNO). The images, both BF and DF, allow the location of particle on the graphitic structure. It is clear that the particle is located in the interlayer zone of the

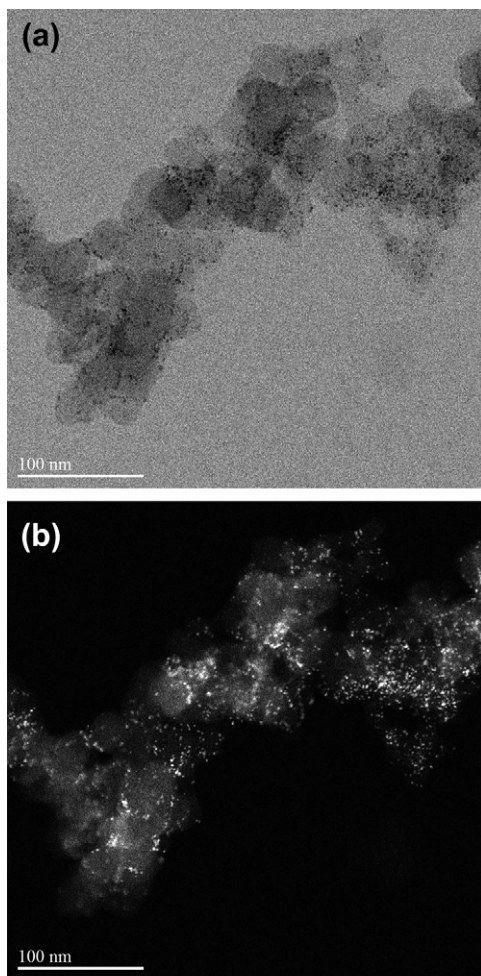


Figure 4.15 Example of contrast of iridium supported on Vulcan carbon. The images of the particles in STEM-HAADF are ideal for size distribution determination. (a) DF- and (b) BF-STEM bright field.

onion (Figure 4.16b). In this case, the background from the substrate acted in favor of a more complete characterization.

In some cases, amorphous carbon produces too much noise on the Z-contrast images, and often it is better to use HREM TEM in the transmission mode. This is more important when the catalysts are ultra-dispersed and the nanoparticles contain very few atoms. Figure 4.17 shows an example for a palladium catalyst supported on Vulcan carbon.

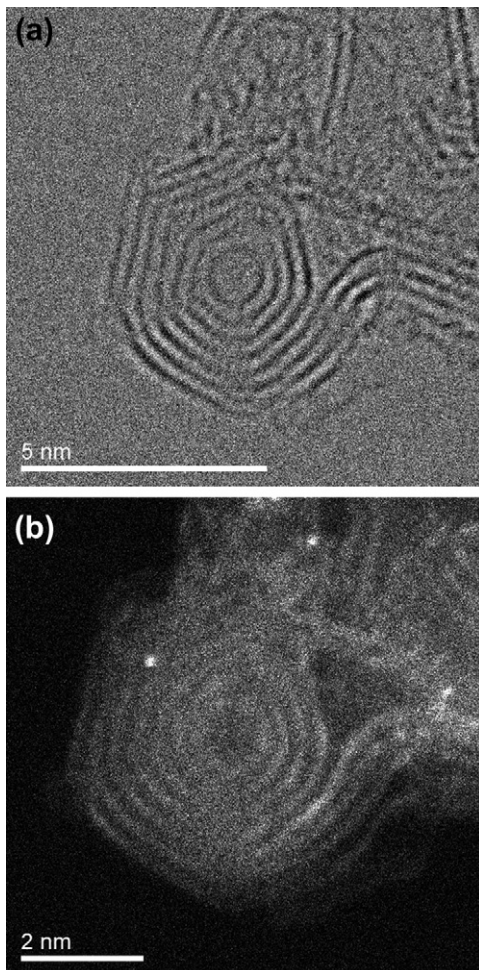


Figure 4.16 Pair of STEM-HAADF images. (a) DF and (b) BF of a CNO onion structure with a platinum particle.

In this case, the aberration-corrected image show clusters consisting of a few atoms. There is no doubt that BF-TEM works much better for this particular case.

3.3. Metals on $\gamma\text{-Al}_2\text{O}_3$

Some of the most important catalysts on petroleum refining are noble metals such as platinum, palladium, ruthenium, rhodium, and recently even gold supported on $\gamma\text{-Al}_2\text{O}_3$ (Frenkel *et al.*, 2001; Rioux, 2006; Ahmed *et al.*, 2009). The alumina is a porous support with a face-centered cubic (FCC)

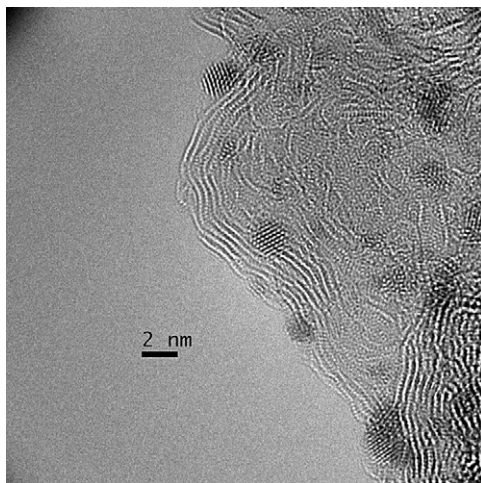


Figure 4.17 HR-TEM image using an aberration corrected TEM of palladium nanoparticles supported on Vulcan carbon. Atomic resolution of the clusters can be clearly observed. In this case, the signal-to-noise ratio is very good to distinguish nanoparticles from the support.

structure $a = 7.90 \text{ \AA}$. The structure of the metal has been the subject of vast investigation (Ahmed *et al.*, 2009). The point is whether the cluster is flat (rafts or 3D in shape). Aberration-corrected STEM-HAADF can offer clues. Figure 4.18a shows an image of a Pt/ γ -Al₂O₃ catalyst. The profile of the cluster marked with A is shown in Figure 4.18b. The particle is clearly 3D because of the Gaussian shape, and its size is about 1 nm. One structure consistent with this size and shape is the on 13-atom icosahedron. The diffraction from these planes falls in reciprocal space very close to the high-angle scattering of the metal. Therefore, it is possible to see single atoms intercalated on the planes. If we calibrate the intensity of a single atom in the same figure and consider the ratio with the maximum intensity of the cluster, we find that N (the number of atoms in the cluster) is ~ 2.8 for the maximum value of intensity; this is again consistent with the icosahedral shape. So it appears that the idea of rafts is not valid in this case, but the catalyst seems to have most of the atoms on the surface. A 13-atom icosahedron is a possibility. However, a new important possibility for metals was recently found by Longo and Gallego (2006), who reported that for platinum a buckled planar structure is more stable than the icosahedron. This structure, which also has 13 atoms, is shown in Figure 18c and will have all its atoms on the surface. This appears quite consistent with the experimental

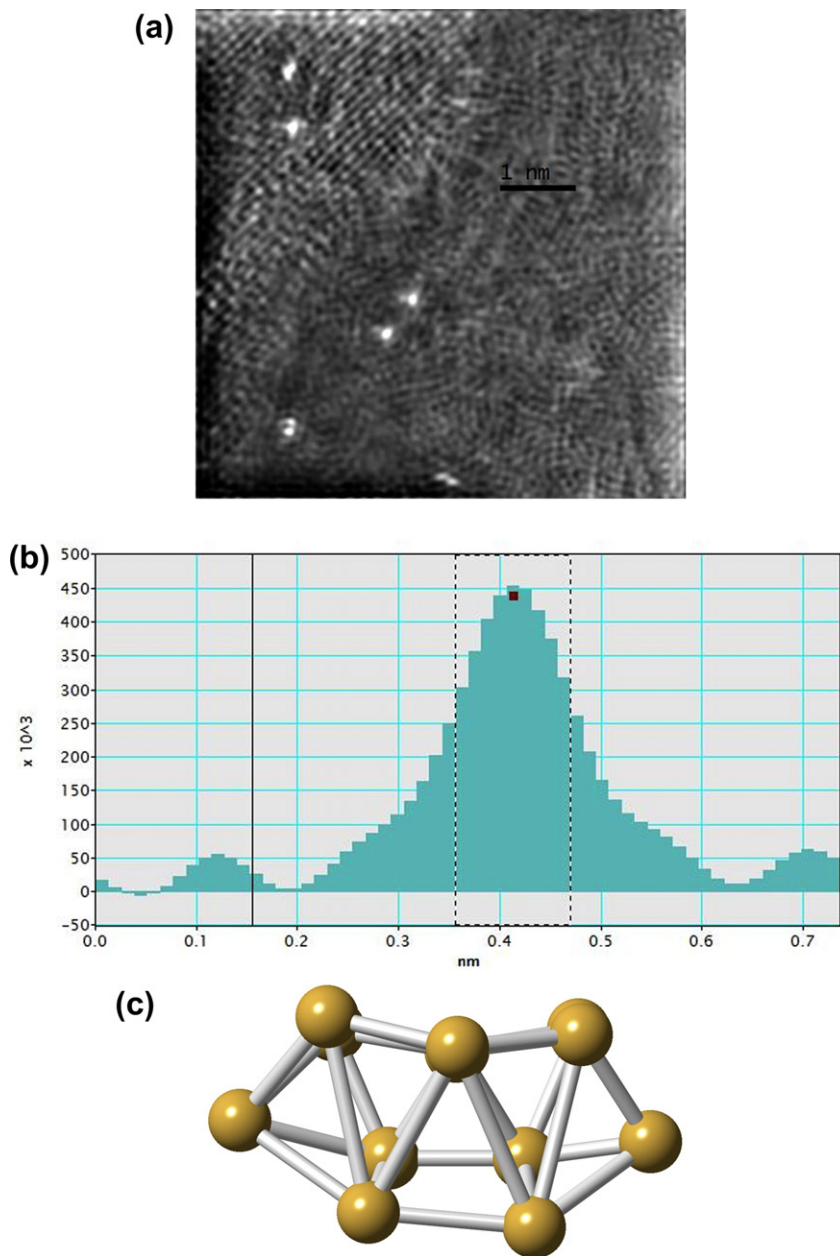


Figure 4.18 (a) TEM-HAADF image of a Pt/γ-Al₂O₃ catalyst. The (444) lattice lines of the alumina can be observed. The bright dots correspond to clusters and to single atoms. (b) Intensity profile of the cluster marked with an arrow in a 3D shape is not consistent with the structure of a raft. (c) A 13-atom optimized cluster is shown that might correspond to the shape observed. (For color version of this figure, the reader is referred to the online version of this book).

observations since the intensity profile will be consistent with two layers. The other platinum metal on the catalysts will be present as individual atoms.

A conclusion from the previous discussion is that flat or raft types of structures seem to be stable only when there is a strong metal–substrate interaction as in the case of metal–TiO₂. In the case of weakly interacting substrates such as γ -Al₂O₃, pseudo-spherical shapes are preferred.

3.4. Bimetallic Nanoparticles and Clusters

Bimetallic nanoparticles are a combination of two individual metallic systems that come together to form an alloy. This combination serves as a platform to enhance both their individual and collective properties. Thus, compared with monometallic systems, bimetallic systems have greatly improved properties; a typical case, for example, is their improved reactivity in catalysis for many varied reactions. For bimetallic nanoparticle alloys, the synergy in the hybrid material can presumably be attributed to the electronic coupling of the individual metals and in addition to the geometric effects that may be caused by the different lattice constants (Stamenkovic *et al.*, 2007). The concept of bimetallic nanoparticles goes back to the 1970s where it was used in catalysis of two different metals such as gold and palladium in the same nanoparticle (Sinfelt, 1983). This idea was developed by Toshima's group, (Harada *et al.*, 1993) who used polyvinylpyrrolidone (PVP) to stabilize core-shell bimetallic gold-palladium nanoparticles—for instance, nanoparticles in which the core is gold but palladium atoms are located on the shell (He *et al.*, 2003). Subsequent to coreduction, this structure is controlled by the order of reduction potentials of both ions and the coordination abilities of both atoms to PVP. The location of gold in the core and palladium on the shell was demonstrated by extended X-ray absorption fine structure, and it was shown that such heterobimetallic gold-core palladium nanoparticles are more active in catalysis than simple PVP-stabilized palladium nanoparticles. Thus, the gold core enhances the catalytic properties of palladium nanoparticles at the palladium nanoparticle surface (Toshima, 1996). Conversely, design strategies can lead to the opposite core-shell structure (palladium core, gold shell), and specific catalytic properties were obtained for methylacrylate hydrogenation (He *et al.*, 2003). Thus, with the observation of a remarkable enhancement in the properties of bimetallic nanoparticles, they have continued to evoke vigorous scientific interest.

3.5. Understanding the Structure of Bimetallic Nanoparticles and Clusters Using Advanced Electron Microscopic Techniques

Direct microscopic studies of various bimetallic nanoparticles have been performed using HR-TEM (Perez-Tijerina *et al.*, 2008; Perez-Tijerina *et al.*, 2010; Mejia-Rosales *et al.*, 2006). However, this method is limited because of the small difference in the lattice constant involved. TEM can produce chemical contrast due to different electron beam extinction distances. This has been applied successfully to image bimetallic nanoparticles down to 10 nm in diameter. Since the particles need to be in a low-index zone orientation, this method is not easy to use in practice (Srnová-Šloufová *et al.*, 2000). A novel approach to study this type of particles is based on the use of an HAADF technique in a TEM, which allows the observation of the interfaces between layers of different elements due to differences in atomic number, densities, or the presence of strain fields due to differences in lattice parameters. However, in recent times the study of bimetallic nanoparticles has been greatly improved with the use of aberration-corrected scanning/transmission electron microscopy (S/TEM), which yields a new level of understanding of the behavior of these systems at the atomic scale. A combination of the HAADF imaging mode in an aberration-corrected STEM/TEM reveals a wealth of information about these systems. It is well established that, when recorded under appropriate illumination and collection geometries, incoherent HAADF-STEM images are compositionally sensitive and provide direct information on atomic positions, which is crucial in the differentiation of variation in the atomic compositions while imaging.

The conventional understanding of bimetallic nanoparticles is that they have one of four fundamental structures: (1) alloys, (2) core-shell, (c) onion, or (d) Janus (Figure 4.19).

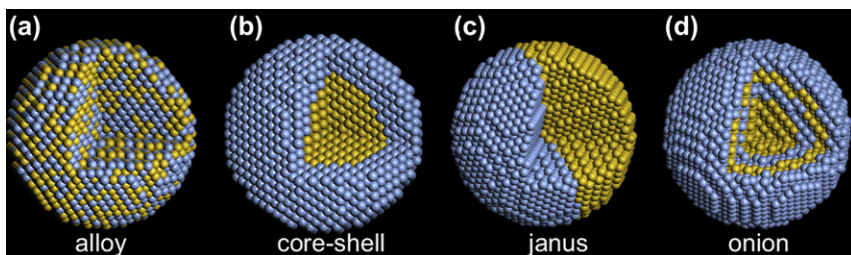


Figure 4.19 The four main types of structures on bimetallic nanoparticles: (a) alloys, (b) core-shell, (c) Janus structure, or (d) onion structure. (See the color plate).

Several factors play a role in determining which of the four alternatives is more likely to occur. These factors include the solubility of the metals, the relative surface energy, the kinetics of the synthesis, and several others. In the case of gold-palladium nanoparticles, both types of structures can be formed. Gold-palladium is a particularly interesting system because of its applications as hydrogenation catalysts and the two metals are fully soluble in bulk. Hence, both alloy nanoparticles, as well as core-shell gold-palladium nanoparticles, can be obtained depending on how the individual metal ions themselves are reduced (Mizukoshi *et al.*, 2000). Figure 4.20 shows the probe aberration HAADF images of nanoparticles of AuPd₃ with the alloyed structure. It is clear that some atomic columns are significantly brighter than adjacent columns, as shown by the contrast of the atom row with arrows in the inset of Figure 4.20b. The top of Figure 4.20c shows intensity traces over two single atoms labeled atom 1 and atom 2. These are typical of several such traces in Figure 4.20b and suggest that the higher-intensity atom is gold and the lower one is palladium. Since the intensity is proportional to $Z^{1.6}$, the relative single-atom intensities should be $791.6/461.6 = 1087/458 = 2.37$. It is very reasonable to assume that the more-intense atoms correspond to gold and the less intense atoms correspond to palladium since the intensity ratio is 1.8, a reasonable approximation of the expected ratio of 2.37, given the low sampling and low signal above background. With regard to the bright central column, if it is all palladium, then it represents an unreasonable number (at least three) of the palladium atoms extending above the general

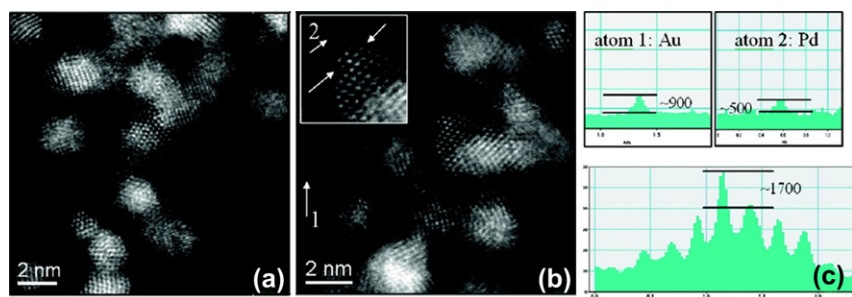


Figure 4.20 (a) and (b) HAADF images of typical AuPd₃ nanoparticles. Single-atom traces (top of (c)) suggest a palladium intensity of 500 counts versus a gold intensity of 900 counts. The profile of the atom row indicated on the inset (c, bottom) shows a central column roughly triple the intensity of the adjacent column, presuming all palladium atoms. This suggests the presence of one or more gold atoms in the central column. (Reprinted with permission from Mejia-Rosales *et al.* (2006). Copyright (2007) American Chemical Society). (See the color plate).

surface. This is not favored energetically; it is likely therefore that one or more gold atoms contribute to the intensity of this column. The roughness of the surface, due to the presence of extended point defects, can also be seen clearly.

A different situation can be seen for gold–palladium nanoparticles which were obtained by successive reduction of metal ions. In this case it was found that when particles (with different gold and palladium compositions) were synthesized by chemical methods, a much more complex situation arises, in which the nanoparticles show a structure with three alloyed layers and with different compositions (Ferrer *et al.*, 2008). Figure 4.21 shows the ultra–high–resolution HAADF images of the gold–palladium nanoparticles obtained in a probe aberration–corrected STEM. From Figure 4.21a it can be seen that the three layers in the nanoparticle are clearly evident. The diameter of the nanoparticles is ~ 8 nm. This consists of a palladium core (A ~ 2 nm), gold–rich first shell (B ~ 3 nm), and palladium–rich outer shell (C ~ 3 nm) (shown from the contrasts in the HAADF images in Figure 4.21a). The HAADF intensity is considered to be proportional to $Z^{1.6}$ and hence the difference in atomic number (Z) that exists between gold and palladium is clearly revealed in the three-layer nanoparticles (gold, $Z = 79$; palladium, $Z = 46$). The shape of this particle corresponds to

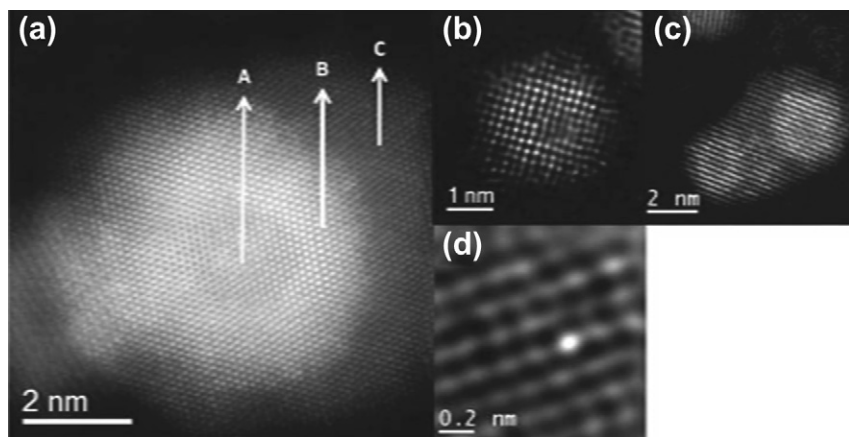


Figure 4.21 Aberration-corrected STEM images of the three-layer Au/Pd nanoparticles. (a) Atomic-resolution HAADF-STEM image of a truncated cuboctahedral Au/Pd nanoparticle. The contrast of the three distinct regions (marked A (palladium), B (gold), and C (palladium)) can be clearly identified. (b) Nanoparticles with rough surface and distortions at the core. (c) and (d) Gold intercalation into the palladium layer. (Reprinted with permission from Deepak *et al.* (2011a). Copyright (2011) Elsevier).

a truncated octahedron, which has (111) and (100) facets. Figure 21b shows a three-layer particle with the (100) orientation where roughness on the surface and distortion in the core of the nanoparticle can be seen. In some nanoparticles, it may also be seen that the gold atoms are indeed diffused into the palladium-rich outermost shell as seen from the bright atom contrast in the palladium layer. Figures 21c and 21d show the atom-by-atom intercalation of gold in the palladium layer. This shows how gold can be present in the palladium layers and is not entirely rigid. So the layers indeed are alloys of different concentrations (Deepak *et al.*, 2011a).

The energy dispersive analysis of X-ray (EDAX) for the three-layer gold-palladium-gold nanoparticles reveals the following interesting features (Figure 4.22a). The palladium L-shell and the gold L- and M-shell signals can be clearly be used to identify the individual palladium and gold layers (Figure 4.22b). Figure 4.23 shows the chemical maps of the gold-palladium nanoparticles. It can be seen from the figure that the maps for the palladium (K and L shells) and gold (L and M shells) clearly reveal the presence of the individual elemental contrasts in the three-layer core-shell structure of the nanoparticles. With the information obtained from the EDAX line scans and elemental maps of the individual nanoparticles, the presence of the palladium core, gold first shell, and palladium outer shell is clearly confirmed without any ambiguity.

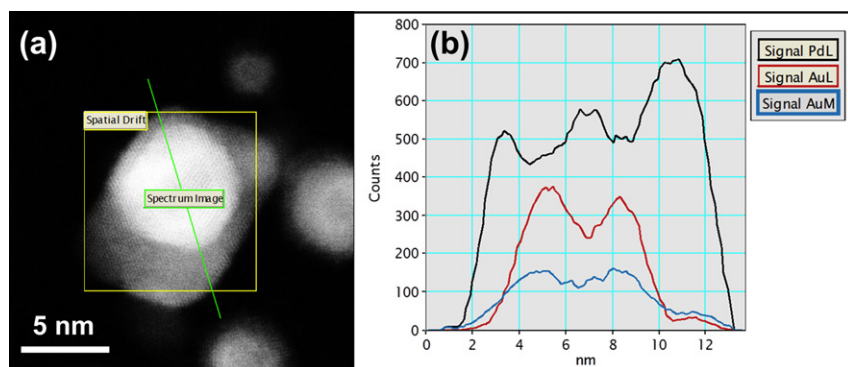


Figure 4.22 (a) and (b) Characterization of the gold and palladium elemental distribution across the nanoparticle by STEM-EDAX line-scanning technique across the individual three-layer nanoparticle. The Pd-L and the Au-L,M line scan signals (b) can be clearly seen varying in intensity along the different regions of the nanoparticles. (a) The analyzed area and the direction of analysis. (Reprinted with permission from Deepak *et al.* (2011a). Copyright (2011) Elsevier). (See the color plate).

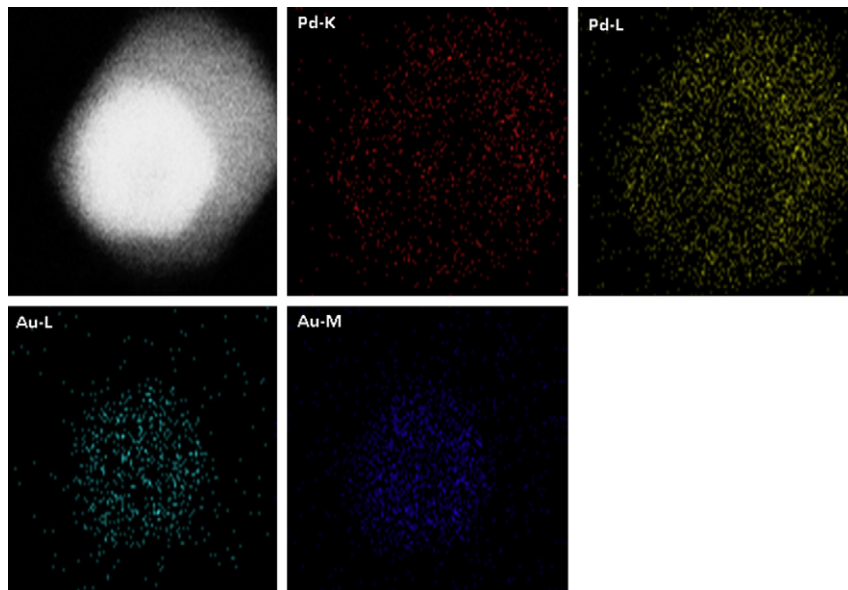


Figure 4.23 Elemental maps of the nanoparticles for Pd-K and Pd-L (top) and Au-L and Au-M (bottom). (Reprinted with permission from Deepak et al. (2011a). Copyright (2011) Elsevier). (See the color plate).

The distribution of the chemical elements of the three-layer nanoparticle (Figure 4.24a) was investigated by EELS; Figure 4.25b shows the result for the EELS line profile of Pd-M_{4,5}. For purposes of comparison, the figure also shows the HAADF intensity line profile of the same particle (Figure 4.24d). From the EELS profile (Figure 4.24c) it can be noted that the distribution of palladium appears to be in accordance with the presence of palladium in the core and in the outermost shell as is the case for a trilayer particle. However, the EELS Au-M_{4,5} signal at 2206 eV turns out to be weak, as expected for a heavy element, but high enough to show the presence of gold in the particle.

From the comparison between the palladium EELS profile and the HAADF profile, it can be inferred that a palladium-rich region exists close to the center of the particle, and another in the outermost shell. The corresponding EELS map of palladium clearly reveals the presence of palladium in the core and the outermost shell of the tri-layered nanoparticles (Figure 4.25).

It is important to note that in case of these nanoparticles a four-layered structure is seen occasionally. Figure 4.26 shows such a four-layer structure

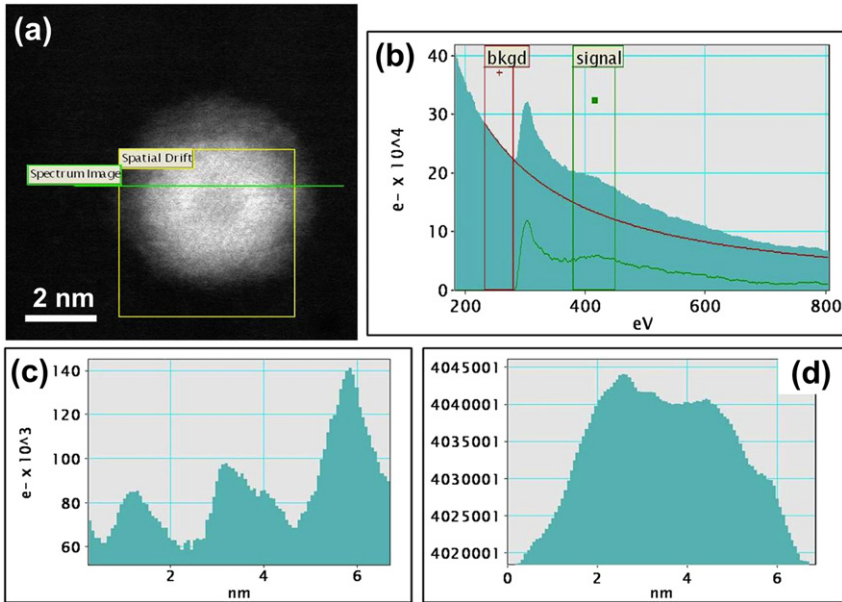


Figure 4.24 The distribution of the chemical elements of the three-layer nanoparticles. (a) Investigated by EELS; (b) the result for the EELS line profile of Pd-M_{4,5}; (c) Linear palladium EELS profile performed on the particles; (d) its corresponding HAADF intensity profile. (Reprinted with permission from Deepak *et al.* (2011a). Copyright (2011) Elsevier). (See the color plate).

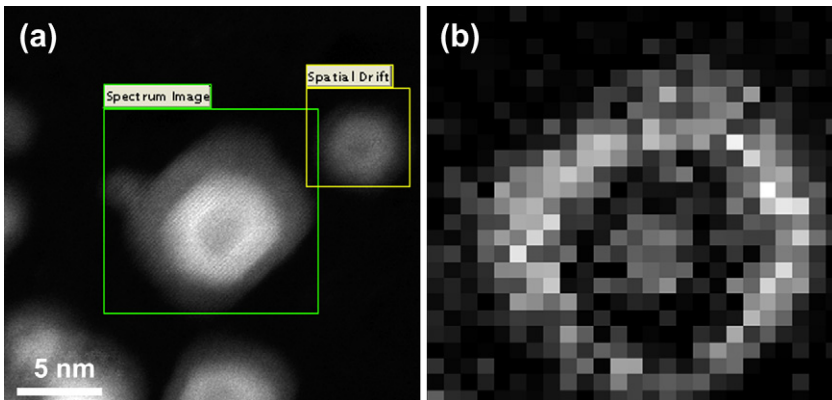


Figure 4.25 EELS map of palladium clearly reveals its presence in the core and in the outermost shell of the trilayered nanoparticles. (Reprinted with permission from Deepak *et al.* (2011a). Copyright (2011) Elsevier). (For color version of this figure, the reader is referred to the online version of this book).

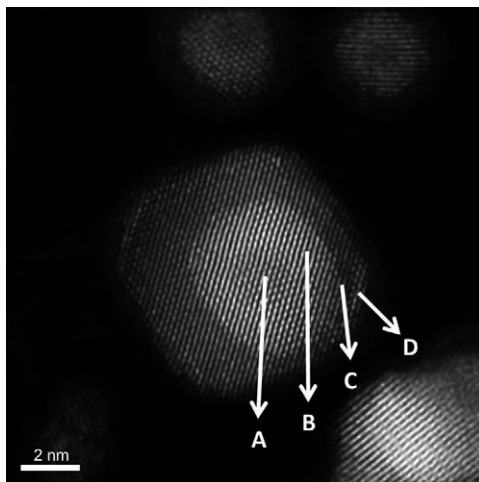


Figure 4.26 Aberration-corrected STEM images of the four-layer Au/Pd nanoparticles. The contrast of the four distinct regions (marked A, B, C, and D) can be clearly seen. (Reprinted with permission from Deepak *et al.* (2011a). Copyright (2011) Elsevier).

where an extra layer of gold atoms can be seen near the surface, which suggests the four layers. This is a different case from the previously mentioned three-layered nanoparticles and has not previously been reported.

The three-layered nanoparticles were investigated individually using nanobeam electron diffraction (NBD). This technique allows investigating the crystal structure in an area down to the nano scale by using a concentrated yet still nearly parallel electron beam with the probe size as small as a few nanometers or less (Ferrer *et al.*, 2009). The analysis of the crystal structure using TEM NBD and a typical NBD pattern from a nanoparticle are shown in Figure 4.27a. This NBD pattern can be indexed using the hexagonal close-packed (HCP) structure. The NBD is oriented in the zone axis [21.1]. The experimentally (and theoretically) calculated values of the diffraction spots along with their respective angles are shown in Tables 1 and 2. The lattice parameters calculated using the HCP structure are $a = b = 0.4105$ nm and $c = 0.6647$ nm ($c/a = 1.619$). The palladium-gold-palladium nanoparticles were analyzed by using weak-beam dark-field (WBDF) technique, which allowed obtaining topological information of the nanoparticles. Figure 4.27b shows a WBDF image of a palladium-gold-palladium nanoparticle. The width and separation of thickness fringes is directly related to the angle of incidence between the electron beam and the sample. The thickness fringes produced by the stacking fault can be observed, which can be interpreted as a band of HCP stacked material produced at the interface. The sequence of

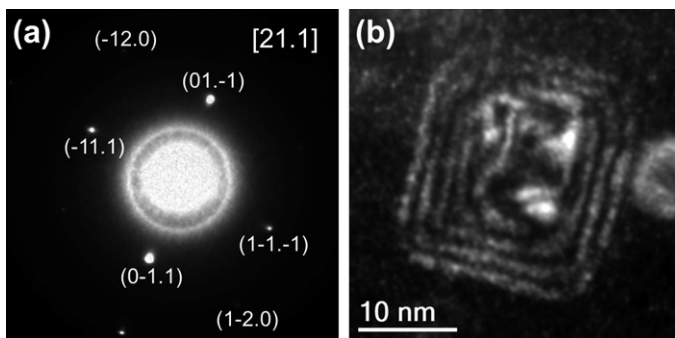


Figure 4.27 (a) Nanodiffraction pattern of an individual Au/Pd nanoparticle. (b) High-resolution weak-beam Dark-Field images of the nanoparticles. (Reprinted with permission from Deepak *et al.* (2011a). Copyright (2011) Elsevier).

the thickness fringes is not homogeneous, which is due to the presence of lattice defects (Mayoral *et al.*, 2010).

Figures 4.28a and 4.28b show a three-layered gold-palladium particle in its $\langle 110 \rangle$ orientation in the HAADF and BF-STEM modes, respectively. Profiles of the first and second layers of the particle are shown in Figures 4.28c and 4.28d, respectively. The profiles show a very rough surface; this can only be explained if we consider two factors. First, atoms of gold migrated to the surface, causing an increase in signal in those particular columns. Second, there are incomplete columns of atoms (e.g., steps) on the surface.

The BF-STEM images of the three-layer nanoparticle (Au_1Pd_3) are shown in Figures 4.29a and 4.29b; the corresponding HAADF images are shown in Figure 4.29c. The incident electron beam direction is along $[110]$. The side surfaces of the particles can be indexed as $\{111\}$ and $\{100\}$ planes (labeled in Figures 4.29a and 4.29d). The center of the nanoparticles is round, but the exterior surface is square-shaped. The real shape of these particles can be associated with a truncated octahedron. This is extremely interesting since the individual metals themselves will tend to form icosahedral or decahedral shapes. Thus, the structure can be changed with the chemical composition. The nanoparticles have defects at the $\{111\}$ surface in all directions (Figure 4.29a). A higher magnification of the BF-STEM image in Figure 4.29b shows the defects clearly, and along with the HAADF image shown in Figure 4.29c, gives a clear indication of the variation in the stacking sequence that leads to the stacking faults. Although the standard stacking sequence is ABCABC in FCC structures, in the regions marked in the images (see Figures 4.29b and c), this sequence is not followed. Instead, the sequence becomes ABCAB... (FCC-HCP structure, as seen in

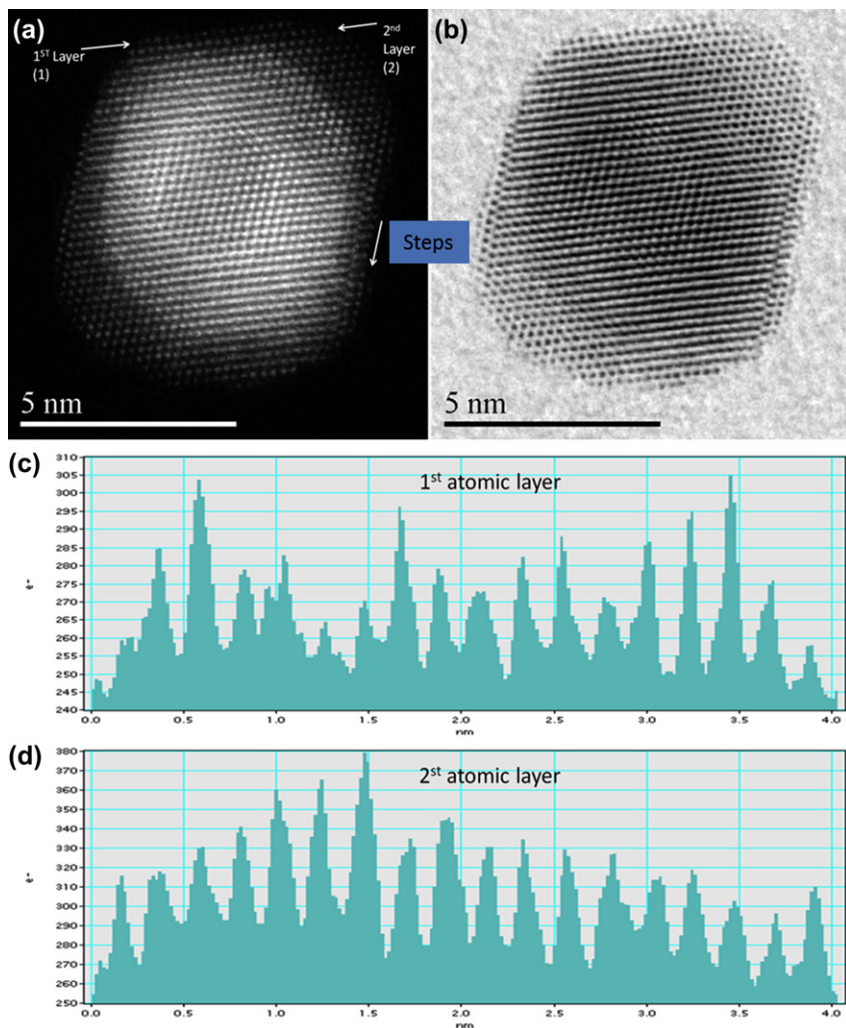


Figure 4.28 (a) HAADF- and (b) BF-STEM images of a Au_1Pd_4 nanoparticle; the images in (c) and (d) show the intensity of the first two atomic layers of the nanoparticle. (Reprinted with permission from Deepak et al., (2011a). Copyright (2011) Elsevier). (See the color plate).

Figure 4.29b) and ABCAB... (Figure 4.29c). This corresponds to stacking faults. In addition, the presence of Shockley partial dislocations (SPDs) can be observed (see Figure 4.29a). The formation of stacking faults in gold-palladium core-shell structures has been shown to be linked to SPDs (Ding et al., 2010). A partial dislocation is accompanied by the presence of a stacking fault. It may be noted here that the large strain involved in the

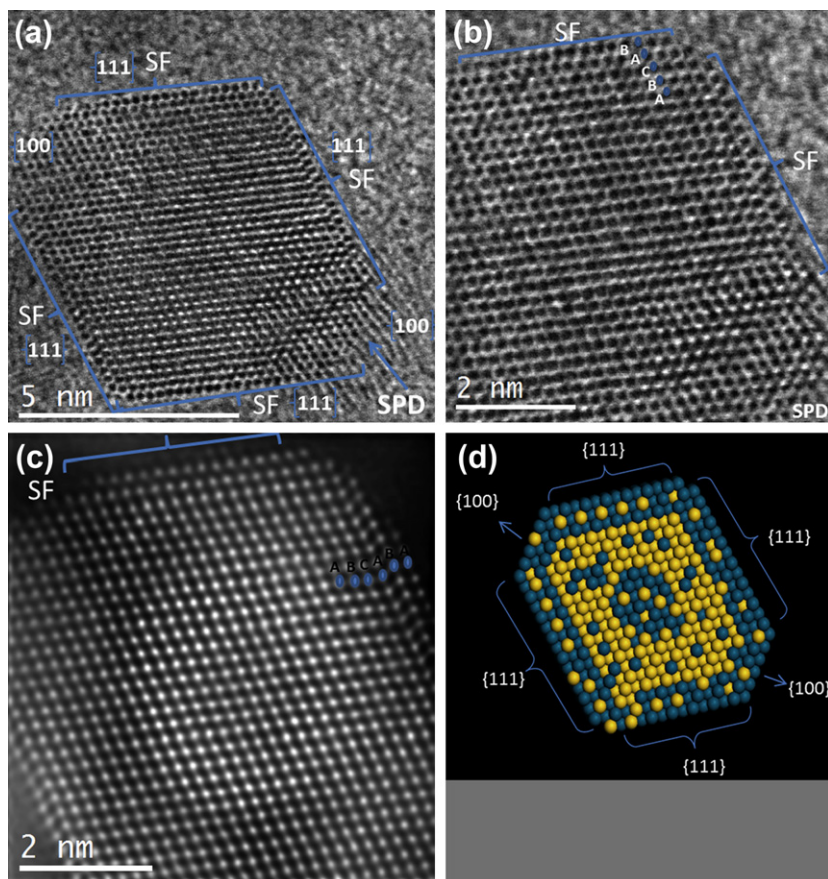


Figure 4.29 The BF-STEM images of the three-layer nanoparticle (a) and (b) and (c) the HAADF image. A higher magnification of the BF-STEM image of (a) is shown in (b) and the HAADF image shown in (c) clearly indicates the variation in the stacking sequence leading to the stacking faults, which is in combination with Shockley partial dislocations. (d) Atomistic model of Au/Pd modified cuboctahedron with the three layers and showing the $\{100\}$ and $\{111\}$ facets: a palladium-rich inner core, a gold-rich intermediate shell, and a palladium-rich exterior shell. (Reprinted with permission from Deepak *et al.* (2011a). Copyright (2011) Elsevier). (See the color plate).

formation of the three-layer structures may be alleviated to some extent by the formation of such stacking faults and related defects. The stacking faults are also evident for the Au_1Pd_4 trilayer particles.

Figures 4.30a and 4.30b are the HAADF-STEM and the BF-STEM images, which show a variation in the stacking sequence from the previously mentioned case. Here the stacking sequence of ABCBA is produced by twinning and layer C corresponds to the twinning mirror plane.

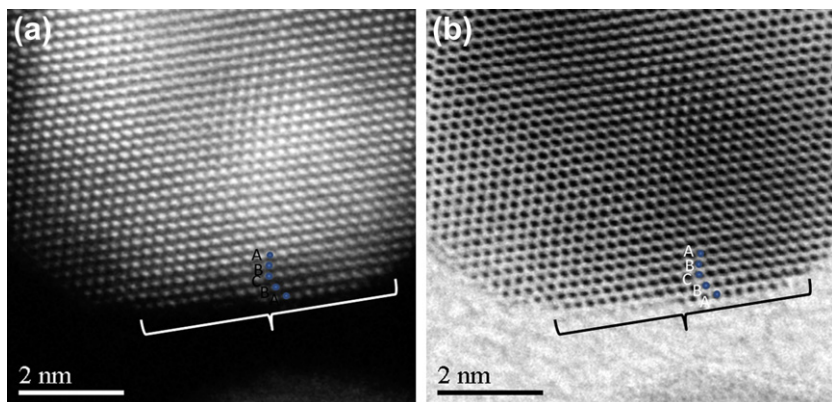


Figure 4.30 HAADF and BF-STEM images of Au_1Pd_4 nanoparticle showing the presence of twinning. (Reprinted with permission from Deepak et al. (2011a). Copyright (2011) Elsevier). (For color version of this figure, the reader is referred to the online version of this book).

It is indeed interesting to note that the ultimate resolution of observing individual atoms/small clusters has been achieved using probe aberration-corrected STEM. Figure 4.31 shows the very small bimetallic clusters of palladium-iridium (inside the circle). The size of the cluster is just about ~ 2 nm. It is interesting to note that based on the Z-contrast, the two different atoms can be distinguished very clearly (palladium, $Z = 46$; iridium $Z = 77$). In addition, it is also possible to locate individual atoms of iridium

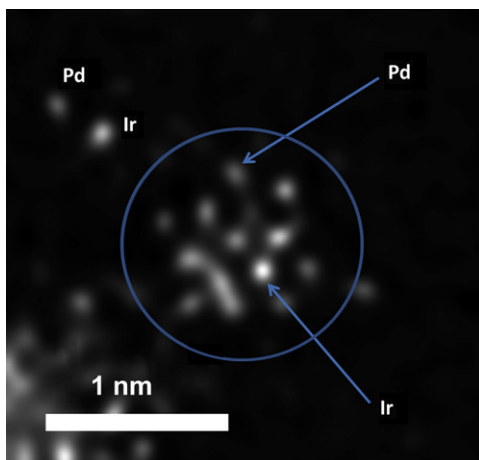


Figure 4.31 Clusters palladium-iridium are shown (inside the circle). It is possible to distinguish each element based on the Z-contrast (palladium = 46, iridium = 77). Notice also the presence of individual atoms (outside and close to the circle). (For color version of this figure, the reader is referred to the online version of this book).

and palladium in the vicinity of these small clusters (outside the circle) (Mayoral *et al.*, 2011).

3.6. *In Situ* Heating Experiments of Bimetallic Nanoparticles and Clusters

One of the most exciting experiments performed in an electron microscope uses the *in situ* heating method. This method provides a great deal of information on the behavior of catalysts and other nanomaterials. With the advent of aberration-corrected electron microscopes that provide sub-Ångstrom image resolution, it is of great interest to study the behavior of materials at high temperatures while maintaining the resolution capabilities of the microscope. The *in situ* heating experiments help overcome several performance problems usually associated with standard heating stage technologies.

A typical example of the heating stage experiments is shown for the three-layered palladium-gold-palladium nanoparticles. Figure 4.32 shows a series of HAADF and BF images recorded at magnifications from 500 kx to 8 Mx as temperatures gradually increased from 350 °C to 900 °C in steps of 50 °C. Figures 4.32a–c show the behavior of a cluster of gold-palladium particles during this heating sequence. The core-shell structure is clear in Figure 4.32a at 350 °C but has disappeared in Figure 4.32b at a temperature of 550 °C as the particles homogenize by diffusion. Particle A shows little change in size, whereas particle B shows a suggestion of growth; however, these effects are small and may simply result from a small rearrangement in shape at this temperature. Two small clusters of gold-palladium atoms appear at the positions marked with arrows; these are probably a result of the migration of atomically dispersed species not seen at this magnification. Figure 4.32c shows the particle grouping at 700 °C. Remarkably, the center particle diminishes greatly in size, with the growth of a new grain on the adjacent surface of the larger particle. The two particles did not sinter together, even though they were apparently in contact at the higher temperature. New particle 1 grew also, but new particle 2 did not change appreciably after its initial formation at the lower temperature. The core-shell structure was not apparent in any particle, suggesting full alloying occurred after time at the higher temperature. The set of BF images in Figures 4.32d–f, corresponding to the above HAADF set, provides additional information to the characterization of the behavior. Crystal lattice can be resolved in BF images at orientations somewhat farther away from the precise orientation required for HAADF images. In Figure 4.32b the

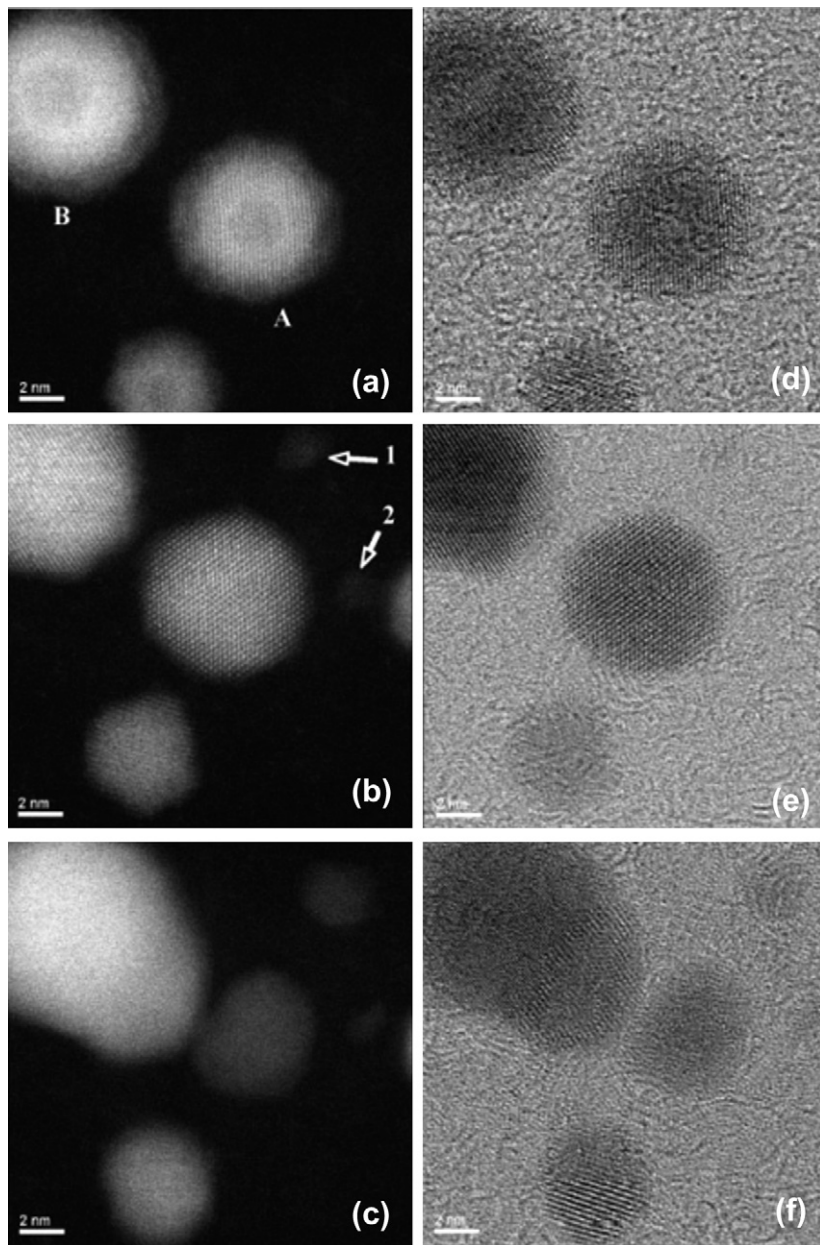


Figure 4.32 Series of HAADF and BF image pairs showing heating effects on three-layer Au-Pd particles at 350 °C [(a) and (d)], 550 °C [(b) and (e)], and 700 °C [(c) and (f)]. (Reprinted with permission from Allard et al. (2009). Copyright (2009) Wiley).

beginning of growth of particle B is apparent, where the new material is not at the same crystal orientation as the original particle, in which the lattice is visible. At 700 °C (Figure 4.32c), particle B shows crystal lattice fringes and is apparently two separate grains. Changes in lattice structure visible from one image to the next are largely the result of slight shifts in orientation of the particles because of the thermal effects (Allard *et al.*, 2009). In the presented example, the clear homogenization of the three-layer gold-palladium particles was an expected result, explained by a diffusion mechanism. This suggests that a direct diffusive reconstruction of an alloy particle has been directly observed. The reasons for the unexpected failure of two primary particles to sinter but instead to show growth of one particle at the expense of the other have not been well understood. One possibility is that particles acquire some charge during the observations, thereby affecting the surface energy. The growth behavior is reminiscent of Ostwald ripening effects, although the system involves particle behavior on a uniform surface, whereas Ostwald ripening generally involves particle coarsening in solid or liquid solutions.

3.7. Multimetallic Systems

Although bimetallic systems are widely produced and studied for various applications, it may also be possible to form multimetallic nanoparticles under specific experimental conditions by careful control of the experimental parameters. A typical example is the case of multimetallic Pd-Au-FePt. Figure 4.33a and 4.33b show the TEM and HAADF-STEM images of the Pd-Au-FePt nanoparticles. The HAADF-STEM images reveal the darker palladium core and the brighter Au-FePt shells. The thickness of the individual layers themselves are core, palladium 5 nm; shell, gold 2 nm; and shell FePt 2 nm. EDS line scans reveal the various layers present in the nanoparticle (Figure 4.33c). The EDS line scans also reveal that there is no interatomic diffusion between the gold and FePt layers, proving indeed that the structure is multilayered. The catalytic properties of such systems in the case of the oxygen reduction reaction have been studied and have been shown to have increased tremendously compared to the corresponding monometallic systems (Ding *et al.*, 2012).

3.8. Conclusions

With the advent of aberration-corrected electron microscopy the elucidation of the structure of bimetallic and even multimetallic nanoparticles down

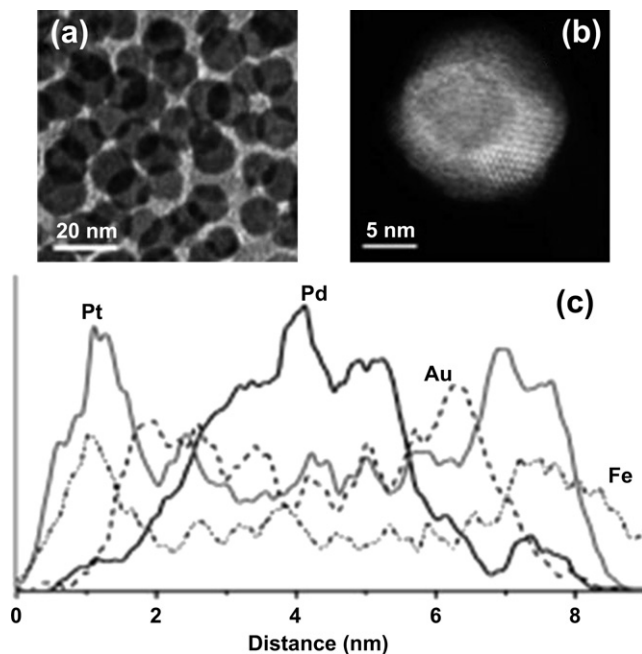


Figure 4.33 (a) TEM and (b) HAADF-STEM image of a single Pd-Au-FePt nanoparticle. (c) High-resolution line scan EDS analysis across the nanoparticle. (Reprinted with permission from Mazumder et al. (2010). Copyright (2010) Wiley).

to a single atom is now possible. Combined with spectroscopic techniques such as EDS and EELS the information obtained on the structure, stoichiometry, chemical composition, and the nature of core-shell/alloy formation of bimetallic nanoparticles is now unprecedented. More recent and exciting trends based on *in situ* dynamic experiments such as the heating stage studies, definitely promise an exciting future for the case of bimetallic nanoparticles and their enhanced understanding toward various applications including catalysis. It is hoped that with all the intricacies associated with the elucidation of various applications such as catalysis, a realistic progress in this area of research is now truly possible.



4. ELECTRON MICROSCOPY OF LAYERED MATERIALS

4.1. Introduction

Transition metal chalcogenides such as MoS_2 and WS_2 are quasi-2D compounds. Atoms within a layer are bound by strong covalent forces,

whereas individual layers are held together by van der Waals interactions. Although a large number of polytypes are observed for the transition metal chalcogenides, the most notable experimentally observed polytypes for MoS₂ and WS₂ based on the stacking sequence of the layers are a hexagonal polymorph with two layers in the unit cell, 2H (P6₃/mmc) symmetry; rhombohedral with three molecular layers in the unit cell, 3R (R3 m) symmetry; or the less common trigonal with one layer, 1T. For instance, MoS₂ is a widely used compound with many applications in catalysis and as solid lubricants mainly because of the weak interlayer interaction of the material (Tye and Smith, 2004; Lince, 2004; Wu *et al.*, 2010). More recent applications are hydrogen storage, as host-guest compounds, scanning tunneling microscope tips, and solid-state secondary lithium battery cathodes (Chen *et al.*, 2001; Zak *et al.*, 2002; Remskar *et al.*, 2000; Homyonfer *et al.*, 1997). The most promising and most pursued of all these applications is their use as industrial catalysts for hydrodesulfurization (HDS) of crude oil. Elimination of sulfur from petroleum feedstocks is necessary to meet the severe restrictions on the sulfur concentrations in fuels (Frey *et al.*, 1999; Babich and Moulijn, 2003). The HDS of polyaromatic sulfur compounds or deep HDS is especially difficult for heavy oils containing high concentrations of sulfur (2–3 wt%). Catalysts based on molybdenum sulfide are widely used in oil refineries for the HDS, hydrodenitrogenation (HDN), and hydrodeoxygenation (HDO) reactions of petroleum-derived feedstocks (Song, 2003; Li and Delmon, 1997; Gates, 1992). Because the stringent environmental legislation sets the sulfur level at <15 ppm, new catalysts with significantly improved catalytic performance are being developed. Sulfur compounds that are known to remain in fuels such as diesel at sulfur levels below 500 ppm include dibenzothiophene (DBT) and alkyl-substituted DBTs such as 4,6-dimethyldibenzothiophene (4,6-DMDBT) (Whitehurst *et al.*, 1998; Turaga *et al.*, 2003) and ongoing efforts using different Mo- and W-based catalysts are directed toward removing sulfur. MoS₂ is also combined with other metals, such as cobalt, nickel, and iron, for use in HDS (Byskov *et al.*, 1999).

4.2. MoS₂ Nanowire Catalysts

One of the challenges in working with catalysts is obtaining direct atomic-scale insights to understand their structure better, thereby enabling direct coordination with their activity. For MoS₂-based catalysts this has proved elusive so far since the location of the active sites and their chemical affinity to HDS reactions is poorly understood without atomic-resolution imaging

techniques. A solution to this provided is provided with the use of aberration-corrected (C_s) STEM-HAADF imaging. HAADF-STEM imaging was performed previously for model MoS_2 -based catalysts by Brorson *et al.* (2007). However, the resolution obtained in terms of imaging these catalysts was not sufficient enough (Brorson *et al.*, 2007). Hence probe aberration-corrected STEM imaging has been performed to image MoS_2 nanowire-based catalysts to better understand the atomic structure of these MoS_2 -based catalysts. This technique allows the identification of direct atomic locations and hence enhances the understanding of the various catalysts, especially identifying the active sites at which catalysis occurs.

Figure 4.34a shows the HAADF-STEM image of the MoS_2 nanowire catalysts supported on alumina. The MoS_2 nanowire catalysts vary in stacking and range between one and three layers. Also noticeable is that the nanowires appear to be twirled or twisted. The figure shows the filtered image of the MoS_2 catalyst, where the bright atom contrast arises from the Mo atoms in the individual layers of the MoS_2 nanowires. The presence of the sulfur atoms, which show less contrast compared with the molybdenum atoms can be also inferred from the image. Thus the sulfur-molybdenum-sulfur chevron can be identified along the entire length of the nanowire. Measuring the distance between the molybdenum-molybdenum atoms (from the bright atom contrast) shows that they correspond to a distance of 2.7 Å (Figure 4.35b shows the line profile along the length of the entire individual MoS_2 nanowire).

Figure 4.35 shows the MoS_2 nanowires with a helical structure obtained by the twirling or twisting of the individual as well as the double or triple MoS_2 layers. Figures 4.35a and 4.35b show the HAADF-STEM image and the BF-STEM images of these helical MoS_2 catalysts. Figure 4.36c shows the filtered HAADF-STEM image of the MoS_2 catalyst. Interestingly, the catalytically inert basal planes of the nanowires are folded onto themselves to expose the highly active catalytic edge sites (surface atoms seen along the entire length of the nanowire as viewed along the c -axis). Figure 4.35d is the line profile corresponding to the interatomic distances of the molybdenum-molybdenum atoms (bright atom contrast), with distances of 2.7 Å between the atoms. The white arrow shows the sulfur atoms that make up the sulfur-molybdenum-sulfur chevron (Deepak *et al.*, 2011b).

Combinated with experimental insights, theoretical simulations have contributed significantly to the fundamental understanding of MoS_2 -based catalysts. In the past decade, several reports have focused on the detailed edge structure, location of active sites, slab-size effects (width and thickness),

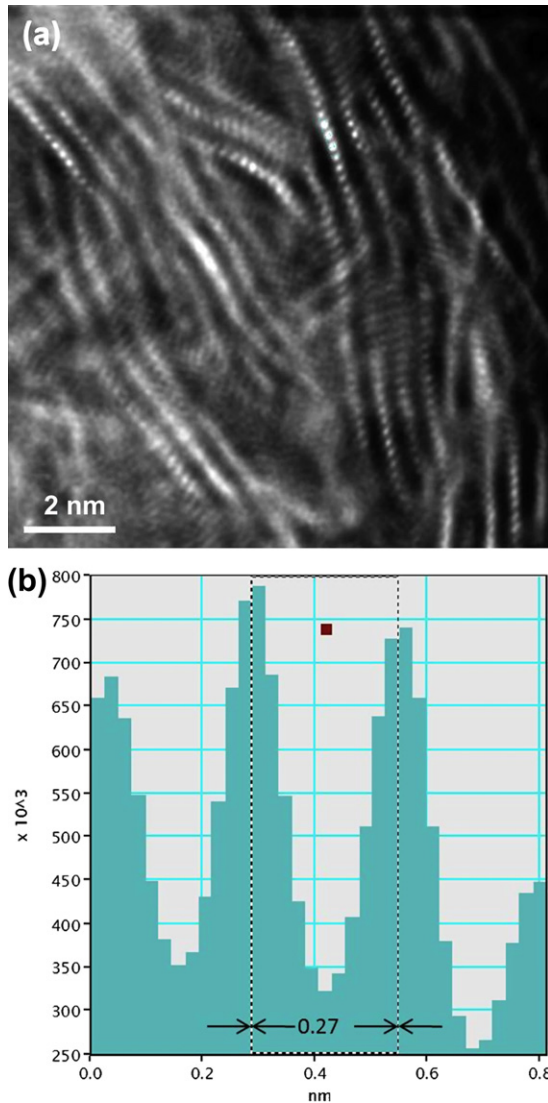


Figure 4.34 MoS₂ nanowire catalysts (on Al₂O₃ support). (a) Filtered HAADF-STEM image of the MoS₂ catalyst. (b) The line profile corresponding to the interatomic distances of the Mo–Mo atoms (bright atom contrast); the distances between the atoms are 2.7 Å. The presence of the sulfur atoms with a lesser contrast can also be seen from the image. (Reprinted with permission from Deepak *et al.* (2011b). Copyright (2011) Springer). (See the color plate).

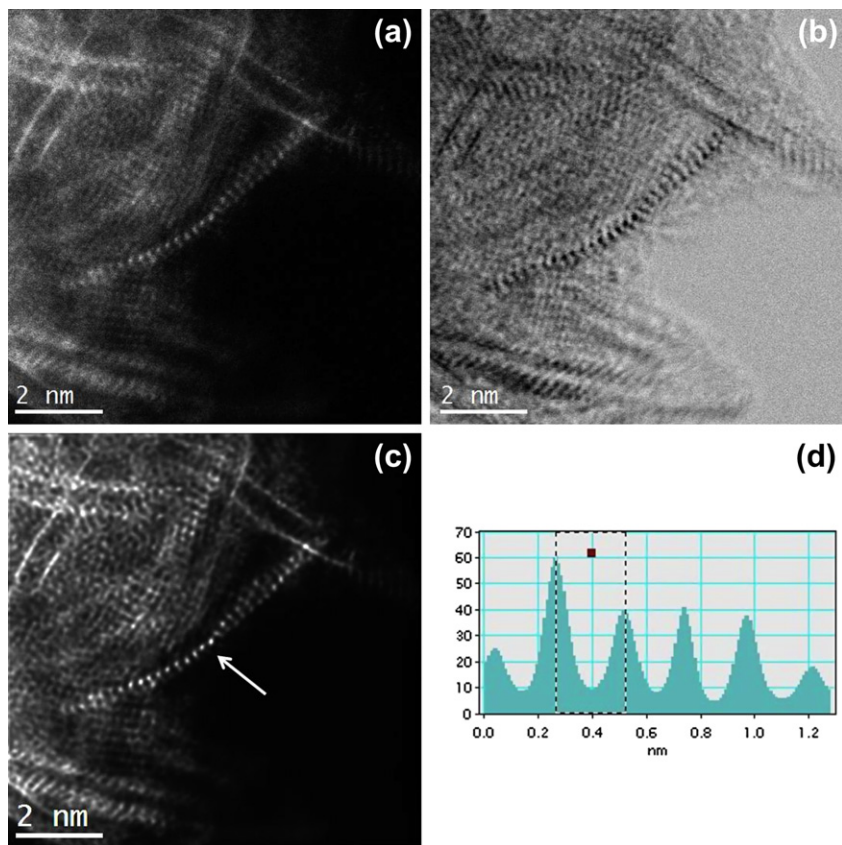


Figure 4.35 MoS₂ nanowire catalysts supported on Al₂O₃. (a) HAADF-STEM image. (b) BF-STEM image of the MoS₂ catalysts. (c) Filtered HAADF-STEM image of the MoS₂ catalyst. (d) The line profile corresponding to the interatomic distances of the Mo–Mo atoms (bright atom contrast), the distances between the atoms are 2.7 Å. The white arrow shows the sulfur atoms that make up the S–Mo–S chevron. (Reprinted with permission from Deepak et al. (2011b). Copyright (2011) Springer). (See the color plate).

the effect of the hydrogen passivation, the magnetic order edge states, and the vacancies formation (Shidpour and Manteghian, 2010; Li *et al.*, 2008; Ionescu *et al.*, 2003; Iglıc *et al.*, 2005). In a majority of these studies, the MoS₂ catalyst has been modeled through MoS₂ sheets where the molybdenum appears in the forms of ions sandwiched by sulfur atoms in a trigonal prismatic coordination. Disregarding the inactive basal plane (0001), the (10 $\bar{1}$ 0) molybdenum edge (zigzag-terminated morphology) and (2 $\bar{1}$ $\bar{1}$ 0) Mo–S edge (armchair-terminated morphology) are of particular importance because they contain the “active sites” through the existence of sulfur

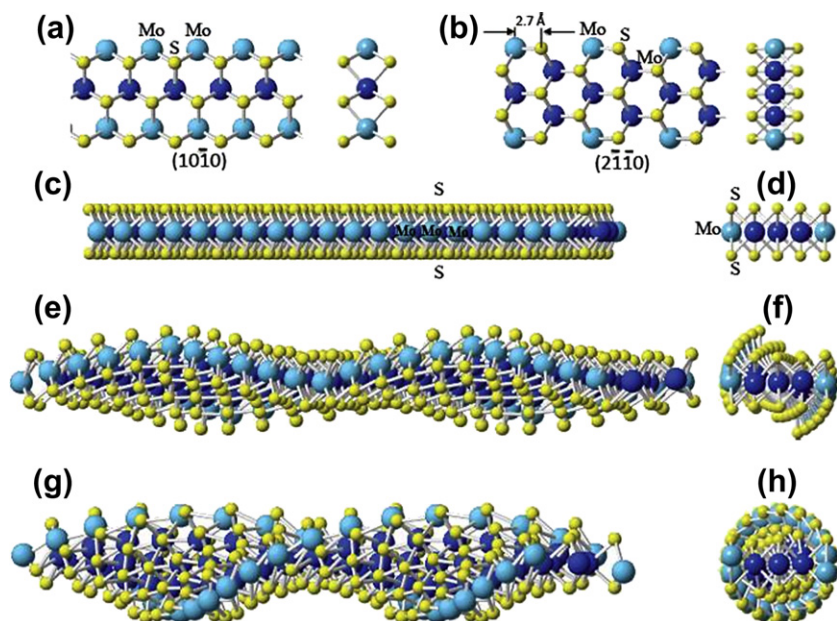


Figure 4.36 (a) and (b) show the side and transversal views of a single-sheet zigzag and armchair-terminated MoS_2 nanowire. (c) Perspective top and transversal (d) views of an armchair-terminated MoS_2 nanowire similar to (b). (e) and (g) Perspective side views, and (f) and (h) transversal views of a rippled (helical) armchair nanowire. The Mo-edge atoms appear light-colored in the figure compared with the other Mo-atoms (dark-colored). (Reprinted with permission from Deepak *et al.* (2011b). Copyright (2011) Springer). (See the color plate).

vacancies. The vacancies on the edges and the intrinsic magnetic order certainly play a key role on the catalytic properties of MoS_2 clusters and nanoribbons. Armchair nanoribbons could be metallic and exhibit a magnetic moment. However, when passivated with hydrogen, they become semiconducting. Zigzag nanoribbons, on the other hand, are metallic and exhibit unusual magnetic properties regardless of their passivation (Botello-Mendez *et al.*, 2009; Shidpour and Manteghian, 2010; Li *et al.*, 2008; Ionescu *et al.*, 2003). It has been suggested that the presence of the vacancies plays a much more substantial role on the magnetization creation, while the magnetic properties can be drastically affected by the size of the nanostructures themselves. In this connection, it must also be noted that electronic properties and edge states in stacked MoS_2 multilayer nanowires and found them to exhibit metallic behavior (Igljic *et al.*, 2005). State-of-the-art simulations indicate that the existence of the metallic edge

states seems to be crucial in order to raise the catalytic activity of MoS₂ nanostructures. Iglic *et al.* (2005) have proposed the possibility of MoS₂ structures with helical and twisted morphologies but did not study their electronic or magnetic properties or consider them of importance because of its unproven existence in nature so far (Kralj-Iglic *et al.*, 2004). Thus, the presence of rippled and twisted or helical morphologies of MoS₂ has not been observed previously (Iglic *et al.*, 2005; Kralj-Iglic *et al.*, 2004; Kisielowski *et al.*, 2011), and advanced electron microscopic techniques have been used until recently to image such catalyst systems with unprecedented structural details (Hansen *et al.*, 2011; Galvan *et al.*, 2011).

Based on the HAADF-STEM images, various atomic models were built to illustrate the different morphologies found in the experimentally observed MoS₂ catalysts discussed previously. Figures 4.36a and 4.36b show the side and transversal views of ziggag- and armchair-terminated MoS₂ sheets, respectively. It has been shown that the $[\bar{1}0\bar{1}0]$ edge plane is more stable than the $[2\bar{1}\bar{1}0]$ edge plane. However, according to the experimental images, the molybdenum atoms are aligned along the $[2\bar{1}\bar{1}0]$ direction, a characteristic that it is possible only for an armchair-terminated slab. For this reason, the first model corresponds to a single-layer armchair-terminated MoS₂ nanowire. Figures 4.36 a–d show different views of an armchair nanowire consisting of a five-atomic layer S–Mo–S sandwich. The relative distance between the molybdenum edge atoms in our model is 2.7 Å, very similar to the experimental value. The experimentally observed nanowires are found mostly in bundles with thicknesses ranging from two to eight single-sheet MoS₂ layers, a varying width ranging from two to six atomic layers, and a length ranging from 20 to 50 nm. The slightly distorted quasi-planar nanowire structures appear to be stabilized by the neighboring layers and are configured almost as in the bulk, with a distance between the single-sheet layers ranging from 5.3 to 6.2 Å. In some bundles the bending/tilting of some nanowires is observed, a fact that leads to a second model. Figures 4.36e and 36f show a perspective and transversal view of a rippled nanowire. These nanostructures are indeed considerably elongated and can also be found in bundles or isolated (Figure 4.36a). In contrast with the previous model, the distances between the edges of two neighboring nanowires is affected by the tilting and therefore are not uniform. Interestingly, the distance between the axes of two neighboring rippled nanowires is nearly the same as for the flat nanowires. When the bending of the nanowires is more pronounced, we observed the irregular twisting of the MoS₂ nanostructures. Figures 4.36 g and 4.36 h show a perspective and

transversal view of the third experimentally observed morphology that corresponds to a helical or twisted nanowire. Indeed, some of the distorted nanowires are a mixture between the rippled and the helical ones. DFT calculations of the electronic structure of the MoS₂ spirals suggest that the twisting produces a transition from semiconductor to semimetal behavior. This effect could be attributed to a distortion produced by the rotation applied to the nanowire; due to this the MoS₂ spirals should have improved catalytic activity. The existence of this new atomic structure changes completely the landscape of the location of the catalytically active sites, opening up the possibility for new MoS₂-based nanocatalysts (Galvan *et al.*, 2011).

4.3. Co-Doped MoS₂/WS₂ Nanowire Catalysts

While unpromoted MoS₂ (WS₂) catalysts do not possess high catalytic activity, a very significant increase in their activity can be achieved by adding cobalt or nickel. The use of metal nanoparticles in HDS reactions has been studied by incorporating a variety of transition metals, such as molybdenum, nickel, Ni/Fe, Ni/W, Mo/W, and Mo/Co, which are able to hydrodesulfurize thiophene and DBT in good yields (Yoosuk *et al.*, 2008; Senevirathne *et al.*, 2007; Escalona *et al.*, 2006; Olivas *et al.*, 2006; Dhas and Suslick, 2005; Farragher, 1979). Of particular interest is the case of Co-promoted MoS₂/WS₂-supported catalysts. Several investigations have been directed toward understanding the nature and function of the Co-promoter atoms in MoS₂/WS₂-based catalysts. The difficulty for many years was to understand in detail the catalytic properties of the different types of cobalt-molybdenum-sulfur structures since direct atom-resolved insight was not available previously. Techniques such as extended X-ray absorption fine structure and X-ray photoelectron spectroscopy have been used to obtain information on the promoter atoms (example: Ni/Co) incorporated within the catalysts previously (example: MoS₂/WS₂ on Al₂O₃). Only recently has such insight provided by scanning tunneling microscopy along with density functional theory; this has contributed greatly to improve fundamental knowledge of the MoS₂ and cobalt-molybdenum-sulfur catalyst structures (Topsøe, 2007). A direct solution to this is now provided using aberration-corrected HAADF-STEM imaging, which can be used to image individual cobalt atoms present in the lattice of MoS₂/WS₂ nanowire catalysts directly. The identification is also supported by performing atomic-resolution energy dispersive X-ray analysis (STEM-EDAX), which can provide reliable and precise chemical

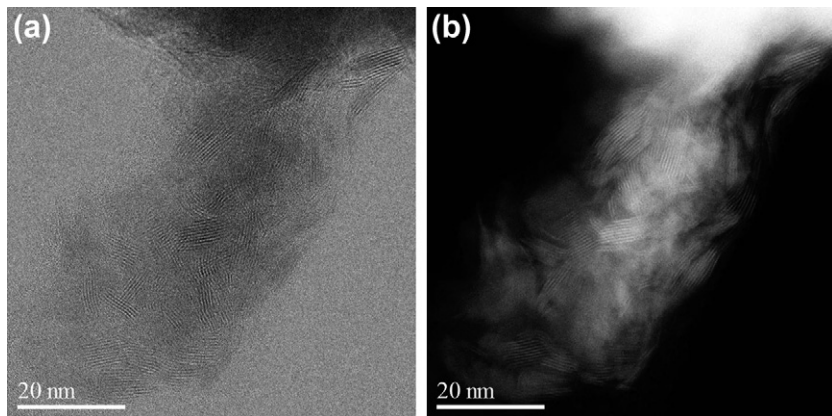


Figure 4.37 (a) and (b) show the low-magnification BF-STEM and HAADF-STEM images of the Co-doped MoS_2 nanowire catalysts. (Reprinted with permission from Deepak *et al.* (2011b). Copyright (2011) Springer).

information to distinguish the presence of the individual promoter/dopant atoms in the lattice of the host (Deepak *et al.*, 2011c). Figures 4.37a and 4.37b show the low-magnification BF-STEM and HAADF-STEM images of the Co-doped MoS_2 nanowire catalysts.

A closer look at the nanowires is provided by the high-resolution STEM images in Figure 4.38. Figures 4.38a and 4.38b show the BF-STEM and HAADF-STEM images of the Co-doped MoS_2 nanowires. Interesting variations in the atomic spacing are revealed from the image (Figure 4.39b) and the line profile (Figure 4.38c) drawn along the row of the bright atomic columns. The spacing between the atoms varies from 2.34 \AA ($\pm 0.1 \text{ \AA}$) to 2.7 \AA ($\pm 0.1 \text{ \AA}$) (atoms A and B vs. B and C) (bright atom contrast revealing the molybdenum-cobalt-molybdenum interatomic distances). The final molybdenum-molybdenum interatomic distance is 2.70 \AA ($\pm 0.1 \text{ \AA}$) (atoms C and D). This is indeed interesting and can be explained in terms of the substitution of cobalt into the lattice of molybdenum, occupying the molybdenum sites. In addition, the difference in the atom contrast (between molybdenum and cobalt, Figure 4.39b), which decreases upon going from the $\text{Mo} \rightarrow \text{Co}$ and subsequently increases from $\text{Co} \rightarrow \text{Mo}$, is also notable. The interlayer distance as measured from the line profile of the individual layers is 5.84 \AA . The variations on the HAADF contrast cannot be explained on the basis of thickness changes. Therefore, the most important contributions should originate from compositional variations, revealed by the difference in atomic number (Z) that exists among molybdenum (atomic number = 42) and cobalt (atomic number = 27) (HAADF intensity is

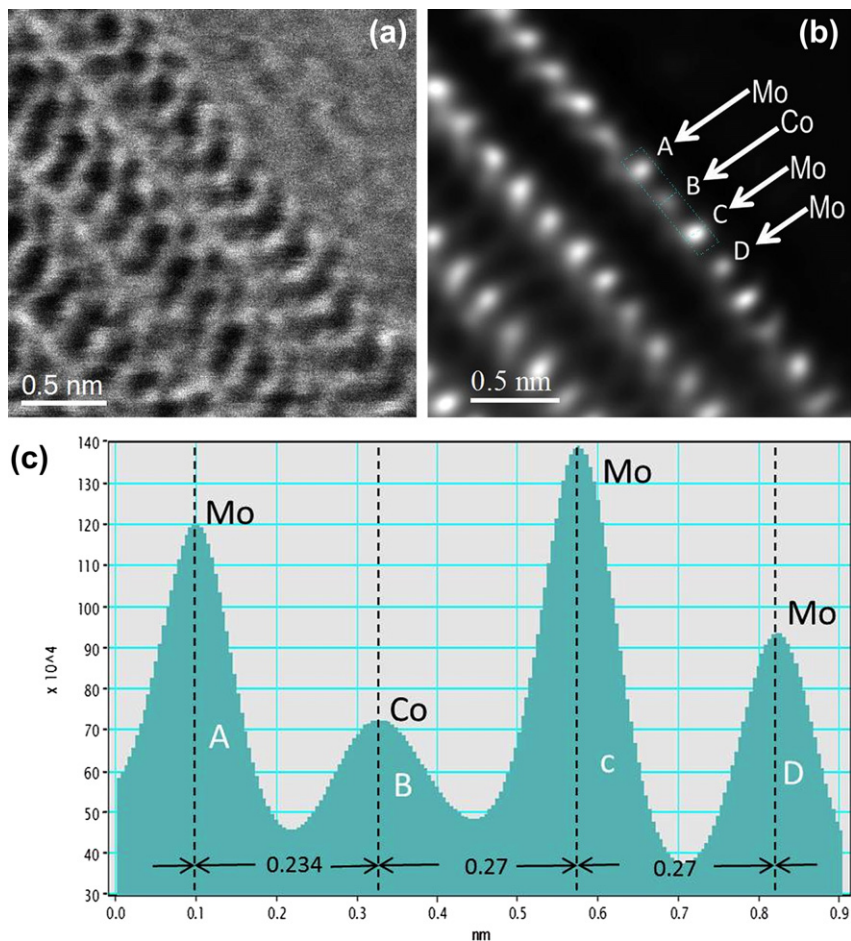


Figure 4.38 (a) and (b) BF-STEM and HAADF-STEM images of the Co-doped MoS₂ nanowire catalysts (unsupported catalyst). (c) Corresponding line profiles. The spacing between the Mo → Co → Mo → Mo atoms as revealed by the line profile is $2.34 \text{ \AA} \pm 0.1 \text{ \AA}$ (Mo-Co); $2.7 \text{ \AA} \pm 0.1 \text{ \AA}$ (Co-Mo); and $2.7 \text{ \AA} \pm 0.1 \text{ \AA}$ (Mo-Mo) (atoms A-B-C-D). The cobalt atoms have a lesser intensity compared the molybdenum atoms as a consequence of the difference in their respective atomic numbers. (Reprinted with permission from Deepak *et al.* (2011b). Copyright (2011) Springer). (See the color plate).

considered to be proportional to $Z^{1.7}$). Finally, it should be noted that in between the layers, the presence of the sulfur atoms that make up the sulfur-molybdenum-sulfur structure can be inferred from their lighter contrast compared with the brighter Mo and Co atoms. Figures 39a and 39b shows the low-magnification BF-STEM and HAADF-STEM images of the

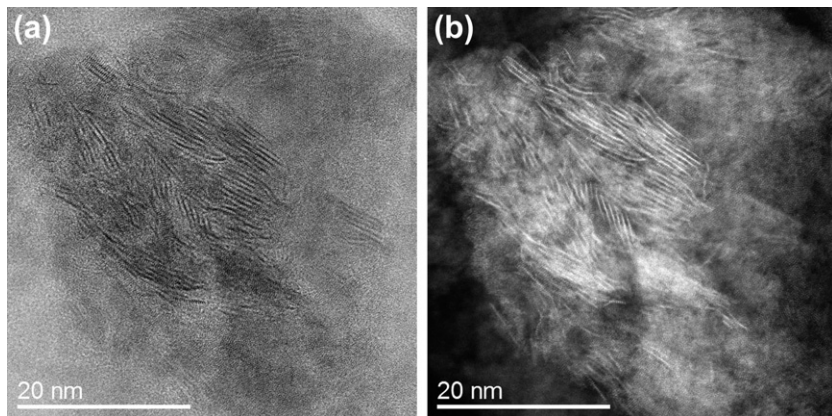


Figure 4.39 (a) and (b) Low-magnification BF-STEM and HAADF-STEM images of the Co-doped WS_2 nanowire catalysts supported on alumina. (Reprinted with permission from Deepak et al. (2011b). Copyright (2011) Springer).

Co-doped WS_2 nanowire catalysts supported on alumina. Large amounts of the nanowires can be clearly seen in the images.

Figure 4.40 shows the high-resolution BF-STEM and HAADF-STEM images of the Co-doped WS_2 nanowire catalyst. Variations in the interatomic spacing are observed from the image (Figure 4.40b) and the line profile (Figure 4.40c) drawn along the row of the bright atomic columns. The spacing between the atoms varies as follows: 2.24 \AA ($\pm 0.1 \text{ \AA}$ for spacing A-B), -2.72 \AA ($\pm 0.1 \text{ \AA}$) for spacing B-C, -2.72 \AA ($\pm 0.1 \text{ \AA}$) for spacing C-D, and -2.24 \AA ($\pm 0.1 \text{ \AA}$) for spacing D-E.

This variation in the interatomic distances can be explained in terms of the substitution of cobalt in the lattice of tungsten (akin to the case of cobalt atoms substituting molybdenum as explained above). In addition, the difference in the atom contrast (between tungsten and cobalt (Figure 4.41b) atoms W-Co-W-Co-W [A-B-C-D-E]) can be noted. The variations are due to the difference in atomic number (Z) between tungsten (atomic number = 74) and cobalt (atomic number = 27). Also, the intensity variations in the HAADF line scans is dependent on the thickness of the atomic layers themselves (whether it is one, two, or three layers). This is also the reason that the Mo/W bright atom contrast appears elongated (two or more layers are twirled and hence produce this type of effects; see for example Figure 4.40b [for the Co: WS_2 case] and Figure 4.40b [for the Co: MoS_2 case], where this entanglement of the WS_2/MoS_2 layers can be clearly seen).

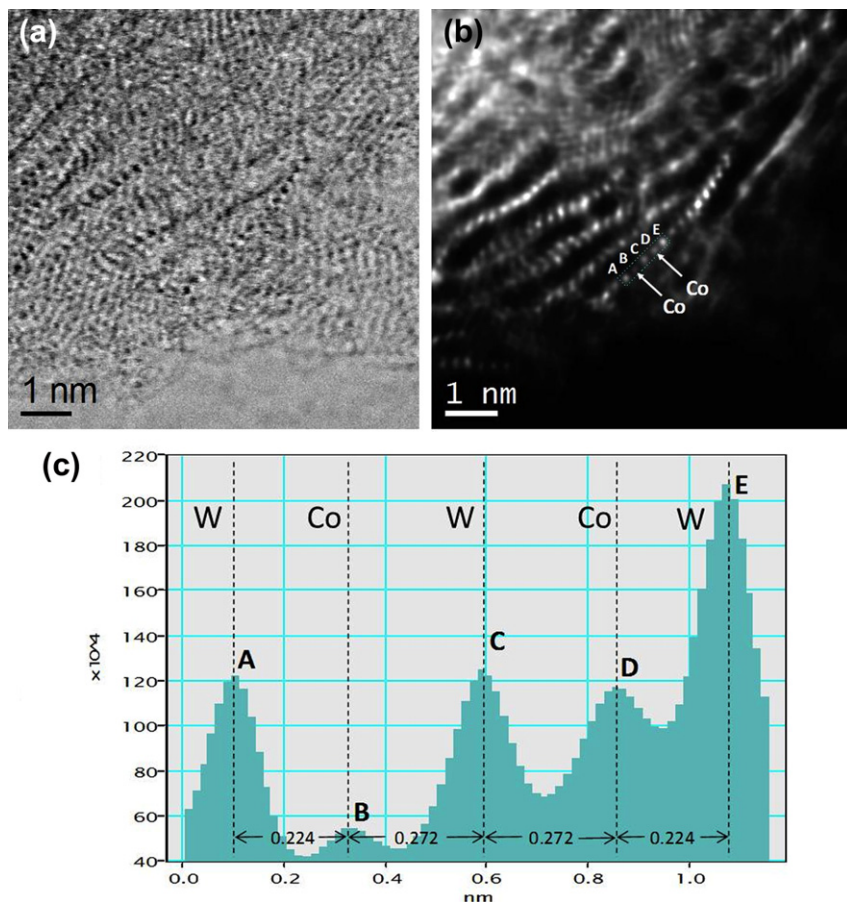


Figure 4.40 (a) and (b), BF-STEM and HAADF-STEM images of the Co-doped WS_2 nanowire catalysts (supported on Al_2O_3) and (c) corresponding line profiles. The spacing between the W-Co-W-Co-W atoms as revealed by the line profile is 2.24 ± 0.1 Å (W-Co), 2.72 ± 0.1 Å (Co-W), 2.72 ± 0.1 Å (W-Co), 2.24 ± 0.1 Å (Co-W), (atoms $A \rightarrow B \rightarrow C \rightarrow D \rightarrow E$). The Co atoms have a lesser intensity in comparison with the W atoms because of the difference in their respective atomic numbers. (Reprinted with permission from Deepak *et al.* (2011b). Copyright (2011) Springer). (See the color plate).

Figure 4.41b shows the EDAX line scan for one of the individual Co-doped WS_2 nanowires (the image is shown in Figure 4.41a). The characteristic W (M) and the Co (K) signals are obtained from the line scans indicating the presence of tungsten and cobalt in the individual WS_2 nanowire (cobalt incorporated at the tungsten sites). The EDAX spectra thus support the previous HAADF-STEM observations that cobalt is indeed present in the lattice of WS_2 . The identification of cobalt present uniformly

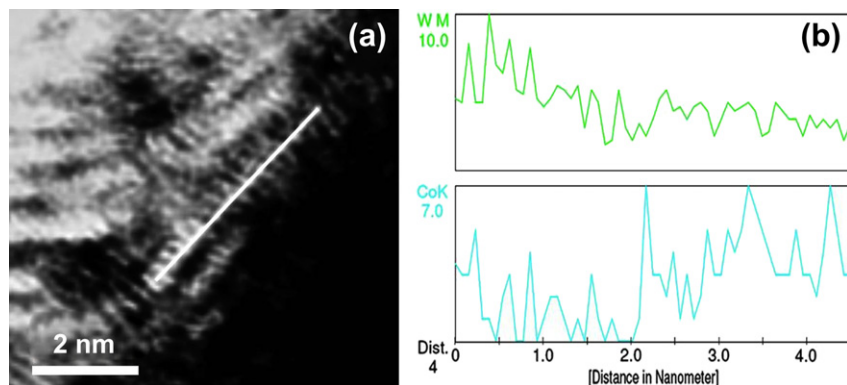


Figure 4.41 EDAX line scans carried out on an individual Co-doped WS_2 nanowire catalyst. The presence of the characteristic and distinct signals of W (M) and Co (K) have been identified from the line scan (Co present at the W-sites). (Reprinted with permission from Deepak et al. (2011b). Copyright (2011) Springer). (See the color plate).

throughout the WS_2 catalysts was ascertained by EDAX spectra and line scans over the entire catalyst in order to eliminate CoS_2 as a possible secondary phase and conclude that cobalt is indeed present only as a dopant in the MoS_2/WS_2 systems studied here.

MoS_2 is a layered material consisting of weakly bounded sulfur-molybdenum-sulfur sheets and a single layer can be terminated by two different edges: the molybdenum-terminated edge ($10\bar{1}0$) (Mo-edge) and the sulfur-terminated ($\bar{1}010$) edge (S-edge). The Mo-edge exposes a row of molybdenum atoms with a coordination of only four sulfur atoms. The S-edge corresponds to an edge where the Mo atoms are fully saturated with sulfur atoms. Density functional theory calculations concentrate on the adsorption of sulfur on the molybdenum-terminated edges and the formation of vacancies on the sulfur-terminated edges to investigate the nature of the catalytic properties of MoS_2 (Byskov et al., 1997; Raybaud, 2000). In the past two decades, numerous configurations for the sulfur-adsorption and the cobalt-promoter distribution at the molybdenum and sulfur active edges of MoS_2 have been intensively investigated by different theoretical and experimental groups. One of the most relevant density functional theory simulation results shows that, for typical HDS conditions, the energy of the S-edge with 100% cobalt is lower than the Mo-edge with 100% cobalt (Krebs et al., 2009; Schweiger et al., 2002; Byskov et al., 2000; Sun et al., 2004a). However, in addition to the affinity of cobalt for the S-edge under such reaction conditions, a 50% cobalt-promoter decoration of the Mo-edge reduces considerably the edge energy of the Mo-edge to

a value close to the S-edge value. Such a new feature had important consequences on the morphologies considered to date and opened a new landscape of possibilities on the location and nature of active sites at the edges of the Co/Mo/S phase. In particular, density functional theory calculations showed that the 50% cobalt partial occupation with the Mo-edge covered by 25% sulfur is stable. Furthermore, the simulations also indicated the existence of two configurations with such sulfur saturation that are close in energy—namely, the alternate configuration Mo-Co-Mo-Co- and the paired configuration Mo-Mo-Co-Co. Figures 4.42a and 4.42b show a perspective view of these configurations together with their respective top views of the Mo-edge. In both cases, the Mo-edge structure exhibits mixed

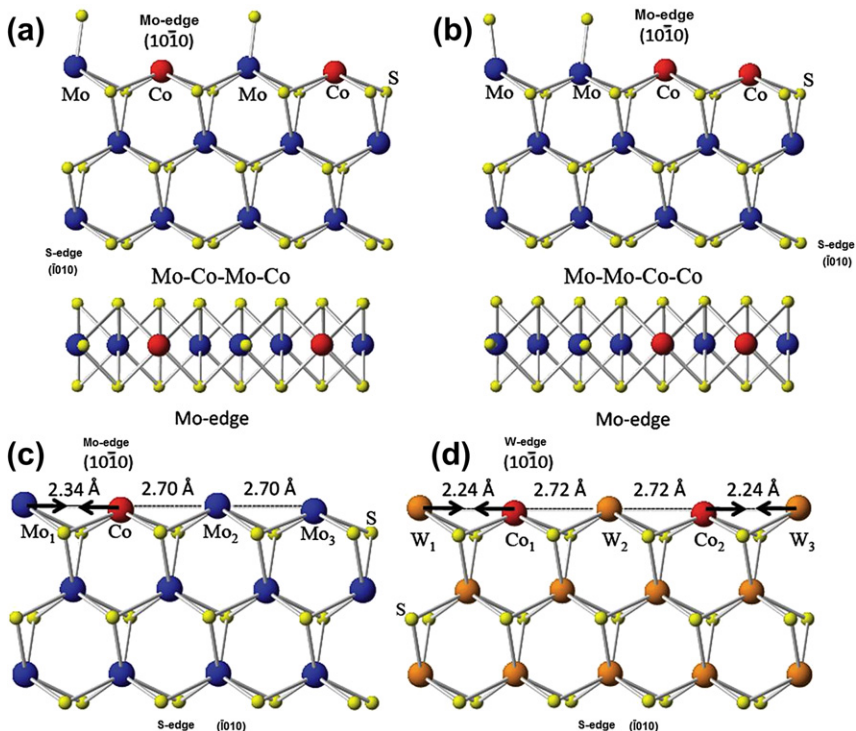


Figure 4.42 Perspective and top views of (a) Mo-edge with 50% cobalt in an alternate position and 25% sulfur. (b) Mo-edge with 50% cobalt in a pairing configuration and 25% sulfur. (c) and (d) Perspective views of CoMoS (CoWS) structure for the experimentally observed Mo-Co-Mo-Mo (W-Co-W-Co-W) sequence at the Mo/W-edge. Molybdenum atoms are in blue, tungsten ornaments are in orange, and sulfur atoms are in yellow. (Reprinted with permission from Deepak *et al.* (2011b). Copyright (2011) Springer). (See the color plate).

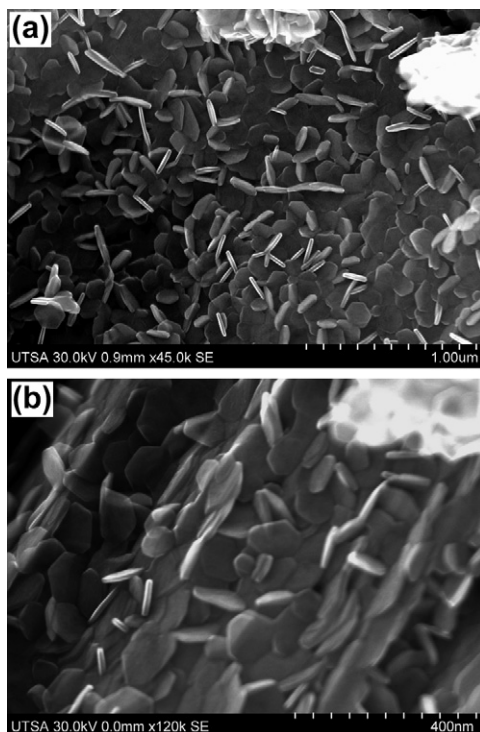


Figure 4.43 SEM micrographs of the MoS₂ plates. (Reprinted with permission from Castro-Gerrero *et al.* (2011). Copyright (2011) Royal Society of Chemistry).

Co–Mo sites while the sulfur atom is located at the top of the molybdenum atoms. Nevertheless, it was also found that sulfur atoms might also be located in bridging positions, which indicated that the mobility of sulfur atoms on the Mo–edge is high (Krebs *et al.*, 2009; Schweiger *et al.*, 2002). To illustrate the experimentally observed morphologies, two models for the cobalt–molybdenum–sulfur and cobalt–tungsten–sulfur catalysts were built (see Figures 4.42c and 4.42d). Figure 4.42c shows the atomic model for the MoS₂ doped with cobalt for the experimentally found –Mo–Co–Mo–Mo– sequence indicated previously in Figure 4.39b. In contrast to the simulations, where the optimized local cobalt–molybdenum distances are comprised between 2.74 Å and 2.84 Å, the pairing of the Mo₁– and Co₁–edge atoms (2.34 Å) is observed, followed by a 2.70-Å separation for both Co₁–Mo₂ and Mo₂–Mo₃ atoms. Interestingly, this structure appears to be a combination of the alternate and paired configuration, which are both very close in energy. The 100% cobalt–50% sulfur and 100% cobalt–62.5% sulfur configuration at

the S-edge (not shown) were not experimentally observed. Figure 4.42 shows the atomic model for the cobalt-tungsten-sulfur catalysts for the W-Co-W-Co-W sequence presented in Figure 4.40. This model supports the idea that the cobalt-promoter atoms incorporate into the MoS₂ structure by substituting Mo-edge atoms in an alternating configuration as previously mentioned. Previous density functional theory calculations indicate that under reaction conditions, 50% S coverage on the promoted W-edge and S-edge are the most energetically stable configurations. In contrast to the CoMoS model, the sulfur atoms are located at the bridging positions according to Sun *et al.* (2004b). Additional density functional theory calculations are desirable to reveal in detail the sulfur-saturation configuration at the W-edge. In general, the exact location of the sulfur atoms, and as a consequence the location of the active edges, remains an issue at the experimental level since it is not yet possible to distinguish between 25% or 50% of sulfur saturation at the Mo-edge when sulfur atoms are located on top of the Mo-edge atoms.

4.4. MoS₂ Nanoplates

Of the various morphologies of MoS₂ explored for its catalytic applications, an interesting morphology is the platelike structure. Nanohexagonal plates are particularly exciting because of the hexagonal shape and nanometric scale, which make them an ideal material in catalysis due to their high surface area. Figure 4.44 shows the SEM micrographs of the MoS₂ plates synthesized at 700 °C and further annealed at 900 °C and 1000 °C. Both images show the presence of hexagonal plates with nanometric size in the sample. The size of the plates is approximately 30–35 nm in diameter. The agglomerates consist of individual plates stacked together.

Figure 4.44a presents an ultra-high-resolution BF-STEM image of a single MoS₂ nanoplate. The Mo–Mo distances in the a_1 , a_2 , and a_3 directions are measured as 2.76 Å, 2.8 Å, and 2.87 Å (the line profile is shown in the inset); these distances correspond to the Mo–Mo interatomic distances (bright atom contrast arising from the molybdenum atoms). Figure 4.44b shows the electron diffraction pattern revealing the a_1 , a_2 , and a_3 directions as well as the hexagonal structure of the MoS₂.

Figure 4.45 shows a moiré pattern formed by the superimposition of the individual plates of MoS₂. The upper inset in the figure shows an HR-TEM micrograph wherein a moiré pattern of a moiré lattice is observed. The lower inset shows the fast Fourier transform (FFT) of the plates: Three sets of hexagonal spots can be seen, corresponding to the three individual plates.

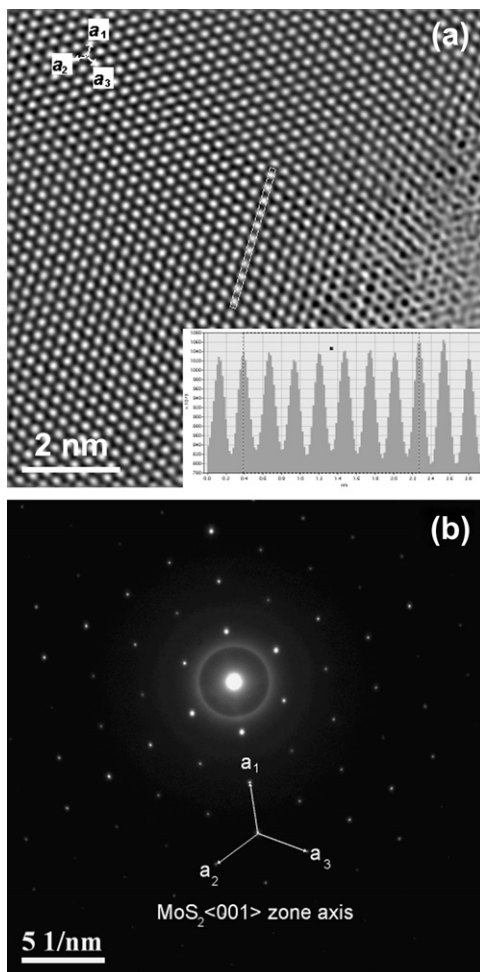


Figure 4.44 (a) BF-STEM image of a MoS_2 plate (bright atom contrast shows the molybdenum atoms). The insets show the a_1 , a_2 , and a_3 directions in the sixfold zone axis as well as the measurements of the Mo–Mo interatomic distances. (b) Selected area electron diffraction pattern of the MoS_2 plates showing the hexagonal symmetry in the $\langle 001 \rangle$ direction. (Reprinted with permission from [Castro-Gerrero et al. \(2011\)](#). Copyright (2011) Royal Society of Chemistry).

The angles measured between the plates correspond to 19° between the first two plates and 16° between the next two plates; these are the rotational angles of the plates. A moiré pattern is observed with the superimposition of the three plates. Moiré patterns of three plates (see the boxed area, plate 3) and two plates (plate 2) are seen in the figure.

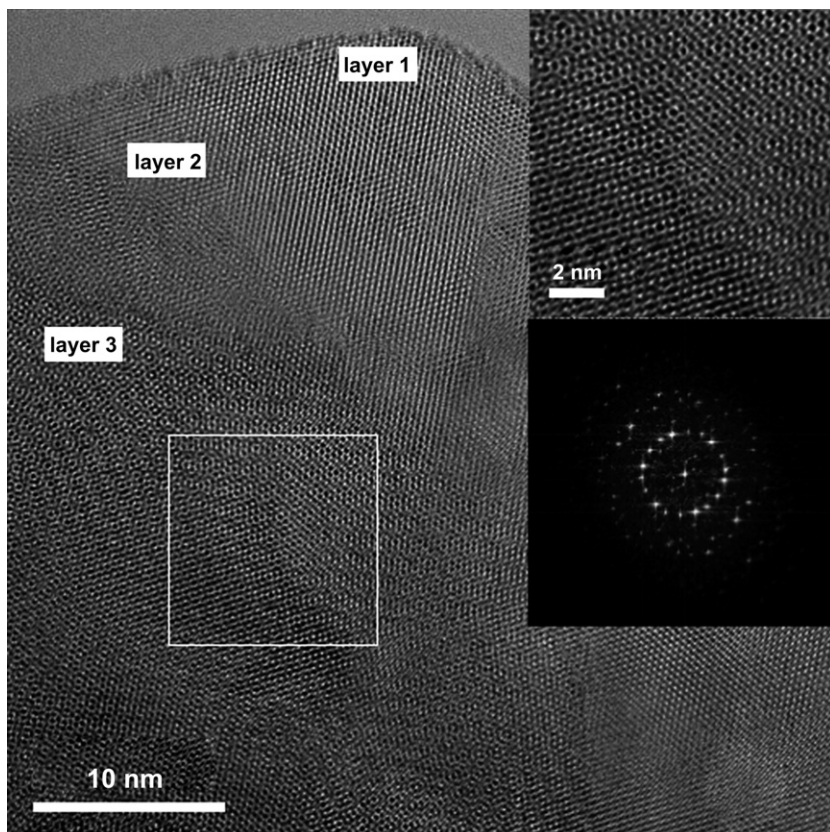


Figure 4.45 Image showing the superimposition of three plates of MoS_2 and the formation of a moiré pattern. The upper inset shows moiré lattice. The lower inset shows the fast Fourier transform pattern with three sets of spots corresponding to the three plates, the angles between the plates being 19° and 16° . (Reprinted with permission from Castro-Gerrero *et al.* (2011). Copyright (2011) Royal Society of Chemistry).

Figure 4.46 shows an HR-TEM micrograph of a MoS_2 plate showing a lateral view. The left inset shows the diffraction pattern revealing the direction of the crystal, which is $[000n]$, where n is even. The right inset shows an amplification of the boxed area in the main image. It shows several bands of different sizes; the broad lines are molybdenum (as it has a high atomic number and a high atomic weight), whereas the thin lines are sulfur. The lines are regular and consist of alternating sulfur-molybdenum-sulfur layers forming a sandwich. These sulfur-molybdenum-sulfur layers form the unit cell in MoS_2 (seen in the inset). The distance measured

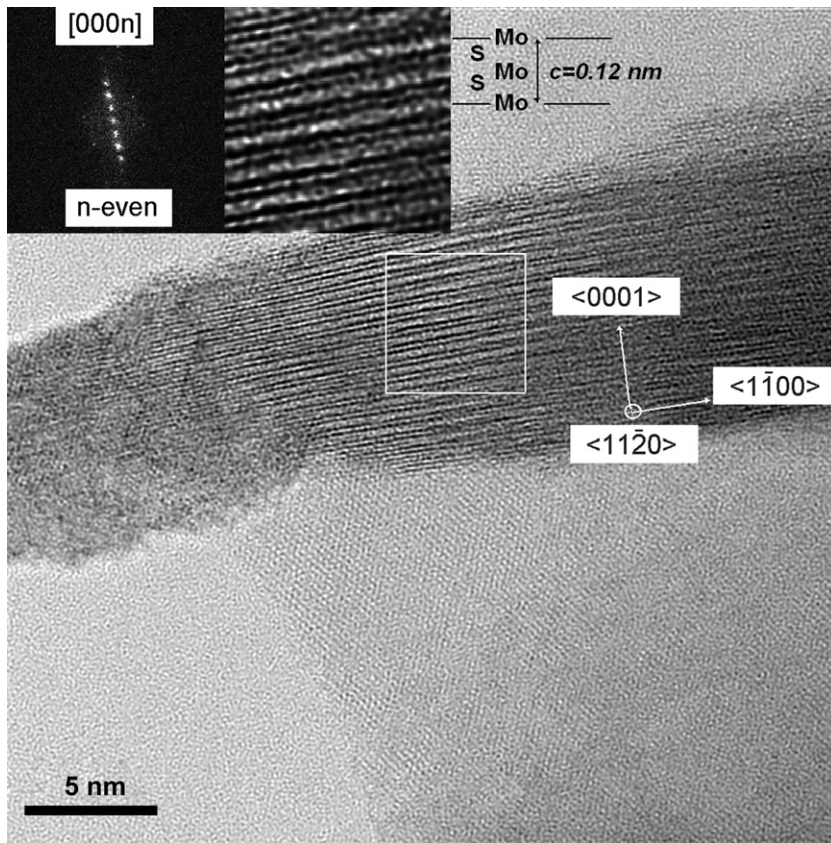


Figure 4.46 BF-STEM image of a plate showing the individual molybdenum and sulfur layers in MoS_2 . The left inset shows the fast Fourier transform in the $\langle 11\bar{2}0 \rangle$ zone axis, whereas the right inset shows a magnified view of the unit cell ($c = 1.2 \text{ \AA}$). The individual stripes are the stacks of molybdenum and sulfur. (Reprinted with permission from Castro-Gerrero et al. (2011). Copyright (2011) Royal Society of Chemistry).

between three atoms of molybdenum forming the cell unit shows $c = 1.2 \text{ \AA}$, which agrees with the values obtained with X-ray diffraction (reported value of $c/2 = 6.53 \text{ \AA}$).

4.5. Conclusions

Elucidation of the structure and properties associated with a truly industrial catalyst such as MoS_2 based on the recent advances in advanced electron microscopy promises to open new avenues in this ever-expanding area of catalysis of layered materials. Having overcome the shortcomings of the lack of understanding of structure and catalytic active sites associated with such

catalysts before such techniques were available, the future seems quite promising in this area. Indeed, the challenges associated with solving environmental issues based on catalysis are more realistic and closer than ever before.

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INDEX

Note: Page numbers followed by “f” and “t” indicate figures and tables, respectively

A

- Aberrations, 195–196, 287–290
 - contrast transfer function (CTF), 287
 - optical aberrations, 196–197
- Absolute convergence, 63–64
- Accelerator system, 262
- ADF. *See* Annular dark-field
- Adjoint dilation, 92
- Adjoint erosion, 92
- Adjoint signal dilation, 128
- Adjoint signal erosion, 127
- Adjunction, 52–53, 92
 - flat erosion, 94
 - Minkowski flat dilation, 94
 - Minkowski set dilation, 93
 - Minkowski set erosion, 94
 - Minkowski weighted erosion, 95
 - properties, 93
 - real-valued functions, 94
 - supremal convolution, 95
- Algebraic decomposition, 72
 - algebraic complement, 72
 - linear space, 72
- Algebraic isomorphism, 71
- Alternating sequential filter (ASF), 108–109
- Amoeba filters, 97
- Annular dark-field (ADF), 283, 285–286
- Anti-isomorphism. *See* Dual isomorphism
- Antitone. *See* Decreasing operators
- Area filters
 - area opening, 104–105
 - attribute openings, 105–106
- ASF. *See* Alternating sequential filter
- Atom, 82

B

- Banach space, 63
- Bas (ψ), 157
- Benzécri algorithm, 17. *See also*
 - Two-dimensional algorithm (2D algorithm)

- image size, 18
- Pseudo-code, 18f
- Benzécri HAC. *See* Benzécri hierarchical ascendant classification
- Benzécri hierarchical ascendant classification (Benzécri HAC), 14–15
 - hierarchy
 - dissimilarity index, 16
 - parts and levels, 15
 - property, 15
 - using remarks, 16
 - segmentations, 15
 - stratified hierarchy, 16
 - image segmentation, 15
 - using 2D algorithm, 15
 - 2D images, 17
 - ultrametrics, 16
 - circle's diameter, 17
 - properties, 16–17
 - ultra metric, 17
 - ultrametric space, 17
- BF images. *See* Bright-field images
- Bimetallic nanoparticles, 304
 - using advanced electron microscopic techniques
 - aberration-corrected STEM images, 307f
 - Au₁Pd₄ nanoparticle, 312, 313f
 - BF-STEM images, 312–314, 314f
 - characterization, 308, 308f
 - chemical maps, 309f
 - clusters of opalladium-iridium, 315–316, 315f
 - EDAX, 307–308
 - EELS map, 309, 310f
 - factors, 306–307
 - four-layer Au/Pd nanoparticles, 309–311, 311f
 - gold-palladium, 306–307
 - HAADF and BF-STEM images, 314, 315f
 - HAADF images, 306f

- Bimetallic nanoparticles (*Continued*)
 using HR-TEM, 305
 NBD, 311–312, 312f
 palladium core, 307–308
 structures, 305, 305f
 three-layer nanoparticle, 309, 310f
in situ heating experiments, 316
 HAADF and BF image pairs, 317f
 Ostwald ripening effects, 316–318
 palladium-gold-palladium nanoparticles, 316–318
- Boolean algebra. *See* Boolean lattices
- Boolean filter, 162–163
- Boolean functions
 binary filter, 163
 binary indicator function, 162–163
 binary signal, 163–164
 increasing functions, 162
 minimal true and maximal false vector, 162, 164
 representation theory, 161–162
 stack filters, 164
- Boolean lattices, 83
 Boolean algebra, 83
 Boolean functions, 84
 field of sets, 83
 finite, 83
n-dimensional Boolean vectors, 83–84
- Boolean operator. *See* Boolean filter
- Bounded linear operators space, 69–70
- Bright-field images (BF images), 283
- British Thomson Houston Co. (BTH), 191
- C**
- Cambridge high-voltage microscope project
 accelerator system, 262
 acceptance tests and delivery, 263–264
 bulky item cases, 264
 forming process, 265–266
 high-voltage set, 267
 Minkner and Bach, 266–267
 Reinhold report, 264
- Cavendish, 245–246
- Cockcroft–Walton generator, 247–248
 construction work, 247
- Coslett's plan, 247
 departure from Cavendish
 EM group, 270–271
 HVEM, 269–270
 Professor Ratcliffe, 268–269
 ramifications, 269
 reminiscences, 271
 William Du Bois Duddell Medal, 271f
- electron lenses, 263
 first test report, 267–268
 micrographs, 269f
 using forklift trolley, 252–253
 freighter aircraft, 248
- Haefely equipment, 250
- high-voltage generator, 247
- high-voltage room
 aluminum panels, 259
 annual garden party, 262
 finished and fully operational, 265f
 Millpool, 261–262
 normal tea-room hum conversation, 261
 Ray Dolby, 259–261
 Ron Pryor and Richard Donoghay
 polishing, 260f
- injector system, 262
- microscope complex, 254f
- operating an electron microscope, 246
- Paul Instrument Fund Committee, 249
- radiation protection, 253
- repairs to Whitegates, 250–251
 CEGB, 251
 high-voltage set, 251f
 after removing cable and rethatching, 252f
 showing electricity cable strung, 252f
- structural alterations
 emergency exit, 256f
 establishment, 258–259
 face-to-face meeting, 255
 high-voltage power transmission, 256–257
 installing earthing rods, 255f
 magnetic shielding, 257
 sightseeing, 257–258
 university estate management service, 254–255
 vibration-isolating block, 253–254
- vibration transmission, 253

- X-ray microscope, 249–250
 Cambridge Western, 274
 Carbon fullerene onion (CNO), 299
 Catalyst characterization
 bimetallic nanoparticles, 304
 using advanced electron microscopic techniques, 305–316
 structure, 305–316
 clusters, 304
 metal catalysts
 on γ -Al₂O₃, 301–304
 on crystalline substrate, 294–299
 on noncrystalline substrate, 299–301
 multimetallic systems, 318–319
 in situ heating experiments
 bimetallic nanoparticles, 316
 clusters, 316–318
 Catalytic systems, 280
 Cauchy sequence, 63
 Cauchy-Schwarz inequality, 64
 CBED. *See* Convergent beam electronic diffraction
 Chain, 78, 81
 Chapman, A. H., 213
 Charles Oatley, EM at Cambridge University. *See also* Ellis Cosslett, EM at Cambridge University
 applications, 219–220
 etched germanium surface, 220f
 plastic scintillator, 221
 PPRIC, 222
 sailing, 223–224
 silver azide crystals, 222–223
 silver azide needle, 223f
 spruce wood fiber, 222f
 TEM, 220–221
 informal contacts
 conversation, 203
 sanatron, 204
 personal affairs, 205
 at Cambridge, 205–206
 fairwell to crew, 206–207
 Sheila, motorcycling, 205f
 time for music, 208–209
 personal interlude, 230–231
 Alvis Speed 20, 230f
 announcement, 232
 Cambridge in one day's driving, 236–237
 journey, 231
 magical experience, 234
 old fisherman posing, 235f
 Peggy McLean, 234–236, 235f
 Pru Woodman, 233, 233f
 stomach-churning experience, 231
 SU carburetors, 231f
 problems with microscope, 209
 electron beam, 210–211
 elementary error cost, 211
 frustrating experience, 210
 Oliver Wells and author confer, 211f
 SEM, 214
 SEM3, 213–214
 stigmator, 210
 wireless receivers, 212
 scanning electron microscope
 detector system, 197
 electron optical projects, 200–201
 electron spot, 196
 electron trajectory tracer, 203
 Ellis Cosslett's electron microscopy, 202f
 improvement in efficiency, 199
 limitation, 194–195
 magnification, 196
 McMullan's original incarnation, 198f
 practical electronics work, 198
 principles, 195–196
 proceedings, 202
 schematic diagram, 195f
 Sheila Smith at controls, 201f
 technical problems, 199
 TEM invention, 193–194
 transmission microscope, 193
 visual acuity, 202
 SEM1, 224–225, 225f
 SEM2, 225
 SEM3, 226, 228f
 AEI, 226
 construction, 228–230
 cross section, 229f
 electromagnetic lenses, 226
 EM4, 226–227
 Everhart-Thornley detector, 227–228

- Charles Oatley, EM at Cambridge University (*Continued*)
 for export to Canada, 237
 “KCA passed this way,” 238f
 preparation and manipulation, 227
 sumptuous first-class fare, 237–239
 specimen chamber, 214–215, 216f
 applications, 216
 Glasgow conference, 217
 Oliver in diving gear, 218f
 point-contact rectifiers, 215
 publication, 216
 SEM, 217
 testing, 215–216
 weather, 219
- Clodum, 56–57, 110
 bounded lattice-ordered group, 113–114
 dual addition, 112
 dual multiplication, 112
 lattice arithmetic algebraic structure, 112–113
 nonlinear spaces, 114–119
 complete weighted lattices of function, 118–119
 general algebraic structure, 114–116
 sup/inf span, independence, basis, dimension, 116–117
 self-conjugate element, 114
- Clusters, 304
in situ heating experiments, 316
 HAADF and BF image pairs, 317f
 Ostwald ripening effects, 316–318
 palladium-gold-palladium nanoparticles, 316–318
 of opalladium-iridium, 315–316, 315f
- CNO. *See* Carbon fullerene onion
- CNR. *See* French National Centre for Scientific Research
- Co-doped MoS₂/WS₂ nanowire catalysts, 326–327
 BF-STEM and HAADF-STEM images, 327f, 328f
 density functional theory calculations, 331–334
 EDAX line scans, 330–331, 331f
 high-resolution, 329, 330f
 low-magnification, 327–329, 329f
 perspective and top views, 332f
 SEM micrographs, 333f
- Cockcroft–Walton generator, 247–248
- Complete weighted lattice space (CWL space), 114–115
 image operators on, 119
 signal translations, 123
- Complex linear space. *See* Hilbert space;
 Real linear space
- Computational theory, 49
- Condenser system, 194
- Connected filters, 104
- Continuous functions, 67
- Contrast transfer function (CTF), 287
- Conventional electron microscope, 194
- Conventional transmission electron microscopy (CTEM), 283
- Convergence
 continuity on topological image spaces, 98
 hit-miss topology, 98
 image signal space, 99
 set sequence, 98–99
 u.s.c., 99
 order convergence
 continuity on lattices, 99
 erosions and dilations, 101
 limsup and liminf combinations, 100
 minimax inequality, 100
 monotonic convergence, 100
 order continuity, 100
 sequence, 63
- Convergent beam electronic diffraction (CBED), 293
- Convex analysis and optimization, 54
 digital geometry, 54
 Legendre–Fenchel conjugate transform, 54
- Convolution adjunctions, scalar dilations, 127
- Cosslett, Ellis
 AEI EM7 lenses, 273
 EM7, 272
 Institute of Electron Optics, 272–273
 John Catto’s contribution, 273–274
 start-up companies, 274
 Cambridge Western, 274

Granta Electronics, 274
 SDI, 275
 synoptics origins, 275
 Whitegates again, 276
 Coventry City boundary, 191
 CTEM. *See* Conventional transmission
 electron microscopy
 CTF. *See* Contrast transfer function
 CWL space. *See* Complete weighted lattice
 space

D

Dark-field mode (DF mode), 283
 DBT. *See* Dibenzothiophene
 Decreasing operators, 90
 class, 92
 anti-dilations, 92
 anti-erosions, 92
 dilations, 92
 erosions, 92
 complete lattices, 91
 dual homomorphisms, 90
 dual isomorphism, 91
 grey-level images, 91
 signal operators, 91
 thresholding operators, 91
 DEDS. *See* Discrete-event systems control
 Definite matrix, 144
 Detector system, 197
 DF mode. *See* Dark-field mode
 DFT. *See* Discrete Fourier transform
 Dibenzothiophene (DBT), 319–320
 Digital geometry, 54
 Digital image processing, 49
 Dilation translation-invariant system (DTI
 system), 126
 Dilation V-translation invariant operator
 (DVI operator), 122
 Dilations, 48
 4,6-Dimethyldibenzothiophene
 (4, 6-DMDBT), 319–320
 Discrete Fourier transform (DFT), 298–299
 Discrete linear filter, 167
 Discrete space. *See* Euclidean space
 Discrete version. *See* Euclidean domain
 Discrete-event systems control (DEDS), 55
 Dissimilarity index, 16

Distance transform, 54
 Distributive lattice, 79–80
 4,6-DMDBT. *See* 4,6-
 Dimethyldibenzothiophene
 DTI system. *See* Dilation translation-
 invariant system
 Dual atoms, 82
 Dual automorphism, 79
 Dual isomorphism, 91
 Dual poset, 78
 Dual semi-atoms, 82
 Duality principle, 78
 DVI operator. *See* Dilation V-translation
 invariant operator

E

ED. *See* Electron diffraction
 EDAX. *See* Energy dispersive analysis of
 X-ray
 EDS. *See* Energy-dispersive spectroscopy
 EDX spectroscopy. *See* Energy-dispersive
 X-ray spectroscopy
 EELS. *See* Electron energy-loss spectroscopy
 Eigenmode, 144
 Eigenvalue, 144
 Eigenvectors, 144–145
 Electron diffraction (ED), 283
 Electron energy-loss spectroscopy (EELS),
 283
 Electron lenses, 263
 Electron microscope 3 (EM3), 213–214
 Electron microscope 7 (EM7), 272
 Electron trajectory tracer, 203
 Ellis Cosslett, EM at Cambridge University
 with
 Cambridge high-voltage microscope
 project, 245–246
 acceptance tests and delivery, 263–268
 departure from Cavendish, 268–271
 design concepts, 252–253
 electron lenses, 263
 first test report, 267–268
 high-voltage room, 259–262
 injector and accelerator system, 262
 repairs to Whitegates, 250–251
 structural alterations, 253–259
 post in Cavendish laboratory, 239

- Ellis Cosslett, EM at Cambridge University
with (*Continued*)
arrangements, 239–240
British Airways Vickers Viscount
turboprop, 239
cash transaction, 242
commercial side, 245
convenience and flexibility, 240
double garage, 241
encyclopedia, 244
entrance to Whitegates, 240–241
image intensifiers, 243
interim measure, 244
modern microscopy, 243
Tiplady's, 245
- EM3. *See* Electron microscope 3
EM7. *See* Electron microscope 7
Emile Haefely & Co., 255–256
Energy dispersive analysis of X-ray (EDAX),
307–308
Energy-dispersive spectroscopy (EDS),
285–286
Energy-dispersive X-ray spectroscopy
(EDX spectroscopy), 283
Erosion translation-invariant system (ETI
system), 126
Erosions, 48
ETI system. *See* Erosion translation-
invariant system
Euclidean distance, 19
Euclidean domain, 59
Euclidean metric, classical, 33
Euclidean morphological operators.
See Minkowski operators
Euclidean space, 60
Euclidean topology, 99
Everhart–Thornley detector, 227–228
- F**
- Fast Fourier transform (FFT), 334–335
FEG. *See* Field emission gun
FFT. *See* Fast Fourier transform
Field emission gun (FEG), 282–283
Finite impulse response filters (FIR filters),
156, 165–166
Finite-dimensional image spaces
continuous domain, 66–67
discrete domain, 65–66
Finite-dimensional linear spaces, 57, 62, 68
Finite-dimensional nonlinear vector spaces,
119
Finite-dimensional spaces, 65
Finite-dimensional vector spaces, 62
linear operators on
matrix representation of, 74–75
spectral representation of, 76–78
weighted minimax spaces, 139–142
FIR filters. *See* Finite impulse response filters
Flat operators
grey-level median, 161
set generator, 161
signal operator, 159–160
stack filters, 161
Forming process, 265–266
French National Centre for Scientific
Research (CNR), 247–248
Function lattice, 84–85
pointwise partial ordering, 84
power lattice, 84–85
signal lattices, 85
vector lattices, 85
Fuzzy dilation, 134–135
Fuzzy norms, 131–132
dual-translated dual impulses, 133–134
fuzzy convolutions, 133
fuzzy operations, 136, 137f
image analysis, 138–139
intersection norm, 133
lattice image processing, 131–132
lattice-fuzzy openings and closings,
135–136
mathematical morphology, 132
morphological flat dilation and erosion,
136–138, 138f
t-conorms, 132
t-norms, 132, 135
union norm, 133
- G**
- Gold
nanoparticles, STEM micrographs, 291f
nanostructure, HR-TEM simulations,
288f
Gold-iridium alloy, 298–299
Gold-palladium nanoparticles, 304,
306–308

- core-shell structures, 312–314
- energy dispersive analysis, 308
- intercalation, 307f
- Gold-palladium-gold nanoparticles, 311–312, 316–318
 - orientation, 312
- Granta Electronics, 274
- Graphispot chart recorder, 264–265
- Gravitational clustering, 25
 - adaptation
 - aggregation, 26–27
 - gravitational interaction, 25f
 - grey-level image, 26
 - histogram, 26
 - to image processing, 25–26
 - LIP framework, 26
 - implementation
 - algorithm, 27
 - grey-level axis, 27f
 - heart, 28–30
 - initialization, 27–28
 - SM algorithm, 27
 - metrics selection
 - applications, 34
 - classical Euclidean metric, 33
 - logarithmic metric, 33
 - SM and OA algorithms, 33
 - notations, 25
 - principle, 25
 - results, 34, 35f, 37f
 - RGB components, 36–37
- Grey-level area opening, 104–105, 105f
- Grey-level images, 50–52
- Grey-level median, 161
- H**
- HAADF detector. *See* High-angle annular dark-field detector
- HAADF-STEM. *See* High-angle annular dark-field scanning transmission electron microscopy
- HAC. *See* Hierarchical ascendant classification
- Hamel basis, 62, 117
- HCP structure. *See* Hexagonal close-packed structure
- HDN. *See* Hydrodenitrogenation
- HDO. *See* Hydrodeoxygenation
- HDS. *See* Hydrodesulfurization
- Heijman's monograph, 57
- Hexagonal close-packed structure (HCP structure), 311–312
- Hierarchical ascendant classification (HAC), 2–3
 - Benzécri algorithm, 17–18
 - Benzécri HAC, 14–15
 - hierarchy, 15–16
 - ultrametrics, 16–17
 - building steps
 - with Euclidean metric, 20f
 - with logarithmic metric, 20f
 - classical quad tree decomposition, 24f
 - color, 22f, 23f
 - comparison, 23f
 - dendrogram representation, 20f
 - grey-level, 21f, 22f
 - initial image values, 19f
 - intermetric comparison, 23f
 - random color LUT, 22f, 24f
 - results and examples, 21–24
 - specific approach, 19–21
 - 2D images, 17
- High-angle annular dark-field detector (HAADF detector), 280–281, 285–286
- High-angle annular dark-field scanning transmission electron microscopy (HAADF-STEM), 285–286
- High resolution electron microscope (HREM), 272–273
- High-resolution transmission electron microscopy (HR-TEM), 281
- High-voltage electron microscope (HVEM), 245–246
- High-voltage power transmission, 256–257
- Hilbert space, 64, 73
- Hit-miss transformation, 90, 155
- Hölder inequality, 66
- Homomorphisms, 88–89
- HR-TEM. *See* High-resolution transmission electron microscopy
- HREM. *See* High Resolution Electron Microscope

- HVEM. *See* High-voltage electron microscope
- Hydrodenitrogenation (HDN), 319–320
- Hydrodeoxygenation (HDO), 319–320
- Hydrodesulfurization (HDS), 319–320
- I**
- ILTI operator. *See* Increasing linear translation-invariant operator
- Image algebra, 54–55
- Image function model, 65
- Image lattices
 - distributive lattices, 85–86
 - grey-level image signals, 86
 - l.s.c. functions, 86
 - set lattice, 85–86
 - shapes and images, 85
 - spatiotemporal image signals, 85
 - u.s.c. functions, 86
 - vector-valued images, 86
- Image operators, 119
 - on CLW, 119
 - image signals, 119
 - matrix representations
 - basis vectors, 140
 - CWL, 139
 - dual vector representation, 140–141
 - finite-dimensional function lattice, 139
 - linear vector space, 141
 - min*-*matrix product, \boxtimes , 141
 - pulse vectors, 140
 - V-translations, 139
 - semi-atoms, 119–120
 - V-translations, 120
- Increasing linear translation-invariant operator (ILTI operator), 166
- Increasing operators, 88–89
 - automorphisms, 89
 - hit-miss transformation, 90
 - homomorphisms, 88–89
 - lattice-based image analysis, 89
 - structuring element, 90
- Infimal convolution, 54
- Infimum, 78
- Infinite-dimensional image spaces
 - continuous-domain, 66–67
 - discrete-domain, 65–66
- Infinite-dimensional linear spaces, 57, 62, 68
- Injector system, 262
- Invariance domain, 102
- Isometry isomorphism, 71
- Isomorphic linear spaces, 68
- Isomorphism, 71. *See also* Dual automorphism
 - algebraic isomorphism, 71
 - isometry isomorphism, 71
 - topological isomorphism, 71
 - unitary operator, 71
- Isotone. *See* Increasing operators
- J**
- Janus structure, 305f
- Jet propulsion Laboratory, 275
- Jolly Miller pub, 261–262
- K**
- K-means algorithm. *See also* Multithresholding; Region growing method
 - comments, 6–7
 - Köhler's approach, 4
 - La Rochelle port, 6f
 - Nuées dynamiques, 4
 - principle, 4–6
- Kernel, adaptive, 97
- Kernel elements
 - translation invariant operators, 146
 - Bas (ψ), 157
 - denoising, 157–158
 - dual set operator, 147
 - Hamel basis, 62, 158–159
 - increasing set operators, 146
 - kernel property, 146
 - minimal kernel elements, 147–148
 - minimal subcollection, 149
 - morphological basis, 159
 - non-flat, 159
 - nondegenerate operators, 146
 - set dilation, 146
 - set erosion operator, 146
 - set operator bases, 150
 - signal operator, 156–157
 - TI filters, 158
 - u.s.c. function, 148–149

- weighted erosions and dilations, 157
- Kernel operators, 145–146
- Kernel representation theory, 145, 156
- Köhler's approach, 3–4
- k th rank set operator, 152
 - closed formula, 153
 - dual set operator, 153
 - 5-pixel discrete rhombus, 152–153, 153f
- L**
- l.s.c.* function. *See* Lower semi-continuous function
- Lattice, 78–79
 - adjunctions, 57–58
 - atomic, 82
 - chain, 81
 - distributive, 79–80
 - isomorphism, 88–89
 - linear space, 81
 - modular, 80
 - morphology, 52
 - operations, 79t
 - operators, 57–58
 - power set, 81
 - projections, 57–58
 - ring of sets, 81
- Lattice automorphism.
 - See* Lattice—*isomorphism*
- Lattice spaces, 78
 - adjoint dilation, 92
 - adjoint erosion, 92
 - adjunction, 92
 - Boolean lattices, 83
 - convergence, 98
 - duality in lattices, 79
 - duality principle, 78
 - function lattices, 84
 - image lattices, 85
 - isomorphism, 79
 - monotone lattice operators, 88
 - order projections, 101
 - partial ordering, 78
 - properties, 79
 - semilattices, 80
 - shift-varying operators, 95
 - signal operators, 87
 - sublattices, 80
- sup-generators, 82
- Layered material electron microscopy, 319–320
 - co-doped MoS_2/WS_2 nanowire catalysts, 326–327
 - BF-STEM images, 327f, 328f
 - density functional theory calculations, 331–334
 - EDAX line scans, 330–331, 331f
 - HAADF-STEM images, 327f, 328f
 - high-resolution, 329, 330f
 - low-magnification, 327–329, 329f
 - perspective and top views, 332f
 - SEM micrographs, 333f
 - MoS_2 nanoplates
 - FFT plates, 334–335
 - HR-TEM micrograph, 336–337, 337f
 - nanohexagonal plates, 334
 - superimposition, 336f
 - ultra-high-resolution BF-STEM image, 334, 335f
 - MoS_2 nanowire catalysts, 320–321
 - HAADF-STEM image, 321, 322f
 - helical structure, 321
 - side and transversal views, 324f
 - slab-size effects, 321–325
 - supported on Al_2O_3 , 323f
 - ziggag-and armchair-terminated MoS_2 sheets, 325–326
 - transition metal chalcogenides, 319–320
- Left adjoint. *See* Adjoint erosion
- Legendre–Fenchel conjugate transform, 54
- Levelings
 - object-oriented filters, 109
 - self-dual reconstruction filter, 109–110
- Linear convolution, 76
- Linear isometry. *See* Isometry isomorphism
- Linear operators
 - algebraic definitions, 68
 - isomorphism, 71, 79
 - normed spaces, 69
 - bounded, 69
 - continuous linear maps, 69
 - infinite linear superposition principle, 69
 - representation, 74
 - finite-dimensional vector spaces, 74

- Linear operators (*Continued*)
 - linear combination, 74
 - ring of linear operators, 75
 - Riesz representation theorem and linear convolution, 75
 - self-adjoint operator, 70
 - spectral representation, 76
 - Linear projections
 - algebraic decomposition, 72
 - algebraic complement, 72
 - linear space, 72
 - orthogonal projections, 72–73
 - least square approximation, 73–74
 - orthogonal complement, 72–73
 - properties, 73
 - Linear shift-invariant filter (LSI filter), 165
 - Linear signal processing, 57
 - Linear spaces, 81
 - algebraic structure, 61
 - conditions, 61–62
 - finite and infinite dimensional, 62
 - linear combination of points, 62
 - linear subspace, 62
 - linearly independent, 62
 - theorem, 62
 - continuous functions, 67
 - finite-dimensional spaces, 65
 - geometric structure
 - inner product linear spaces, 64
 - orthogonal, 64
 - properties, 64
 - Pythagorean theorem, 64
 - infinite-dimensional image spaces
 - continuous-domain, 66–67
 - discrete-domain, 65–66
 - linear operators
 - algebraic definitions, 68
 - isomorphisms, 71
 - normed spaces, 69
 - self-adjoint operator, 70
 - linear projections
 - algebraic decomposition, 72
 - orthogonal projections, 72–74
 - topological structure
 - Cauchy test, 63–64
 - convergent sequence, 63
 - equivalent metrics, 63
 - metric space, 63
 - norm, 63
 - viewpoints, 61
 - LIP model. *See* Logarithmic image processing model
 - Lipschitz continuous functions, 67, 87
 - Logarithmic image processing model (LIP model), 3, 7
 - digitized images, 2
 - grey-scale digitization, 2
 - HAC, 2–3
 - homogeneity or texture, 2
 - image segmentation, 2
 - reflections
 - grey-level images, 40
 - optical vector space, 41
 - using remarks, 42
 - transmittance law, 40
 - transmittances formula, 41
 - Logarithmic metrics, 33
 - Lower semi-continuous function (l.s.c. function), 86
 - LSI filter. *See* Linear shift-invariant filter
- M**
- Matrix rank, 143
 - Max- \star dependent combination, 117
 - Max- \star independent combination, 117
 - Max-plus algebra, 55. *See also* Minimax algebra; Nonlinear matrix algebra
 - Max-plus convolution, 54
 - Max-plus image operators, 129
 - kernel, 130
 - max-plus case, 130
 - shift invariance, 130
 - Max-plus matrix algebra, 142
 - conjugate matrix, 142
 - definite and metric matrix, 144
 - eigenvalue, 144
 - eigenvectors, 144–145
 - graph of matrix, 143–144
 - matrix rank, 143
 - optimization problem, 142–143
 - Max-product image operators, 130–131
 - isomorphism, 131
 - sup-product convolution, 130–131
 - Mean squared error (MSE), 73–74

- Median, 152
 - adaptive, 170–171
- Metal catalysts
 - on γ -Al₂O₃, 301–304
 - metal-TiO₂, 304
 - Pt/ γ -Al₂O₃ catalyst, 303f
 - on crystalline substrate, 294–295
 - Au/Ir alloy support in TiO₂, 298f
 - Au/TiO₂ catalyst image, 297f
 - EELS analysis, 298–299
 - signal-to-noise ratio, 296–298
 - STEM-HAADF image, 296f
 - on noncrystalline substrate, 299
 - aberration corrected TEM, 302f
 - CNO, 299
 - DF and BF, 301f
 - iridium support on Vulcan carbon, 300f
 - Z-contrast images, 300–301
- Metric matrix, 144
- Minimal kernel elements, 147–148
- Minimax algebra, 55, 110
 - clodum, 110
 - lattice-ordered monoids, 111
 - lattice-ordered group, 111
 - lattice-ordered monoid, 111–112
 - poset, 111
 - semilattice-ordered monoid, 111
 - max-plus mathematical morphology, 110
 - nonlinear space, 110
- Minkowski operators, 50–52, 90
- Minkowski set dilation, 93
- Minkowski set erosion, 94
- Minkowski weighted erosion, 95
- Modular lattice, 80
- Monotone lattice operators
 - decreasing operators
 - complete lattices, 91
 - dual homomorphisms, 90
 - dual isomorphism, 91
 - grey-level images, 91
 - signal operators, 91
 - thresholding operators, 91
 - increasing operators, 88–89
 - automorphisms, 89
 - hit-miss transformation, 90
 - homomorphisms, 88–89
 - lattice-based image analysis, 89
 - structuring element, 90
- lattice structures, 88
- Morphological filters, 101
- Morphological operators
 - developments, 50–52
 - algebraic structure, 52–53
 - classic mathematical morphology, 50–52
 - clodum, 56–57
 - convex analysis and optimization, 54
 - finite-dimensional case, 55–56
 - image algebra, 54–55
 - image analysis applications, 52
 - lattice framework, 53
 - lattice operators, 52
 - minimax algebra, 55
 - nonlinear dynamical systems, 53–54
 - linear spaces, 61
 - minimax algebra, 110
 - notation, 60
 - representation theory, 47
- Morphological set operators, 150
 - constraints, 166
 - discrete linear filter, 167
 - erosions supremum, 166–167
 - k*th rank set operator, 152
 - closed formula, 153
 - dual set operator, 153
 - 5-pixel discrete rhombus, 152–153, 153f
 - median, 152
 - Minkowski closing, 150–151
 - Minkowski dilation, 150
 - Minkowski erosion, 150
 - Minkowski opening, 150–151
 - moving average filter, 167
 - opening and closing basis sets, 151, 152f
 - upper support, 166
 - window transformations, 153
- Morphology, adaptive, 97–98
- Morrison air-raid shelter, 191–192
- MoS₂ catalysts, 319–320
 - nanoplates
 - FFT plates, 334–335
 - HR-TEM micrograph, 336–337, 337f
 - nanohexagonal plates, 334

- MoS₂ catalysts (*Continued*)
 superimposition, 336f
 ultra-high-resolution BF-STEM image, 334, 335f
 nanowire catalysts, 320–321
 armchair-terminated MoS₂ sheets, 325–326
 HAADF-STEM image, 321, 322f
 helical structure, 321
 side and transversal views, 324f
 slab-size effects, 321–325
 supported on Al₂O₃, 323f
 zigzag- terminated MoS₂ sheets, 325–326
- MSE. *See* Mean squared error
- Multimetallic systems, 318–319
- Multithresholding, 3. *See also* K-means algorithm
 contrast curve, 4
 Köhler's approach, 3–4, 5f
 techniques, 3
- N**
- Nanobeam electron diffraction (NBD), 311–312
- Nanoribbons, 280
- National Autonomous University of Mexico (UNAM), 294–295
- NBD. *See* Nanobeam electron diffraction
- Neighborhoods, adaptive, 97–98
- Nonlinear functional analysis, 50
- Nonlinear matrix algebra, 55
- Nonlinear spaces
 algebraic structure, 114
 clodum, 114
 CWL space, 116
 WL, 114–115
 complete weighted lattices functions
 CWL space, 118
 pointwise functions, 118
 self-conjugate element, 119
 sup- \star combination, 116–117
 Hamel basis, 117
 max- \star and min- \star 'combination, 117
- Normed spaces, 69
 bounded, 69
 continuous linear maps, 69
 infinite linear superposition, 69
- Notation
 image domain, 60
 image operators, 60–61
 linear operators, 60
 morphological operators, 60
- Null element, 78–79
- Null space, 68
- O**
- Optimized automated algorithm (OA algorithm), 31, 36f. *See also* Sampling of mechanical model algorithm (SM algorithm)
 acceptable solutions, 32
 amalgamation, 31–32
 flowchart, 32f
 initialization, 31
 moving bodies, 32–33
- Order continuity, 100
- Order projections, 101
 alternating sequential filters, 108–109
 lattice theoretic properties, 101
 extensive and anti-extensive operators, 102
 openings and closings, 102–103
 levelings, 109
- Orthogonal projections, 72–73
 least squares approximation, 73–74
 orthogonal complement, 72–73
 properties, 73
- Ostwald ripening effects, 316–318
- P**
- Palladium-gold-palladium nanoparticles, 311–312
- Partial differential equation (PDE), 53–54
- Partial ordering, 78
- Parts hierarchy, 15
- PDE. *See* Partial differential equation
- Peppers image, 21
- Planar set operators, 170
- Polyvinylpyrrolidone (PVP), 304
- POS. *See* Product-of-sum
- Power lattice. *See* Function lattice
- Power set, 81
- PPRIC. *See* Pulp and Paper Research Institute of Canada

- Prime implicant, 161–162
- Product-of-sum (POS), 161–162
- Pseudonorm. *See* Seminorm
- Pulp and Paper Research Institute of Canada (PPRIC), 222
- PVP. *See* Polyvinylpyrrolidone
- Q**
- Quantization error effects, 99
- R**
- Radial openings, 103–104, 104f
- Real linear space, 62
- Reconstruction
- closing
 - grey-level reconstruction filterings, 108f
 - image simplification, 107–108
 - opening, 106
 - conditional dilation, 106, 107f
 - grey-level reconstruction opening, 107
 - marker, 107
- Red-green-blue image (RGB image), 6–7
- Reflection microscope, 193
- Region growing method. *See also* K-means algorithm
- classical
 - aggregation process, 8
 - equivalence relation, 8
 - grey-level distribution, 11
 - using pixels, 8
 - using remarks, 9
 - single linkage effects, 9, 11f
 - 3D image segmentation, 9–11
 - transitivity saturation, 9
 - LIP version
 - using commands, 12
 - efficiency, 11
 - using formula, 11–12
 - logarithmic single linkage, 12f
 - objectives, 13
 - 3D region growing segmentation, 12f
 - notations
 - grey-level image, 7
 - LIP model, 7
 - multiplication calculation, 8
 - space of images, 7–8
- systolic approach, 14f
- classical version, 13
 - using remarks, 13–14
 - Revol's approach, 13
 - seed's exclusion, 14
- Representation theory, 47
- computational theory, 49
 - digital image processing, 49
 - dilations and erosions, 48
 - finite-dimensional case, 58–59
 - image operators, 47–48
 - image representations, 47
 - image-processing tasks, 50
 - lattice adjunctions, 57–58
 - lattice structure, 58
 - linear and morphological image simplification, 51f
 - linear signal processing, 57
 - minimal kernel elements collection, 59
 - Minkowski openings, 60
 - morphological filterings, 50
 - morphological operators, 48–49
 - theory, 57
 - nonlinear functional analysis, 50
 - non-monotone TI operator, 59
 - signal algebra, 58
- Research Department, 192
- Revol's approach, 13
- RGB image. *See* Red-green-blue image
- RHS. *See* Right-hand side
- Riesz's representation theorem, 57
- discrete-time linear convolution, 76
 - impulse response, 76
 - linear convolution, 76
 - linear transformation, 75
 - time signals, 75
- Right adjoint. *See* Adjoint dilation
- Ring of sets, 81
- Rolls-Royce Merlin engines, 192
- Ronchigram, 293
- calculated, 294f
 - for different focus conditions, 295f
 - experimental, 294f
 - focus spot, 293

S

- Sailing, 223–224
- Sampling of mechanical model algorithm (SM algorithm), 27, 34–36, 34f.
See also Optimized automated algorithm (OA algorithm)
- flow chart, 27, 29f
- gravitational clustering, 27, 39f
- initialization
- integer positions, 27
 - optimal number search, 32f
- merging trees, 38f, 39f
- steps, 28–30
- using cases, 30–31
 - using loop equations, 30
 - movement quantity normalization, 29–30
 - velocities and positions, 30
- Sanatron, 204
- Sash window, 254–255
- Scale parameter, 51f
- Scanning electron microscope (SEM), 193–194. *See also* Transmission electron microscope (TEM)
- detector system, 197
 - electron optical projects, 200–201
 - electron spot, 196
 - electron trajectory tracer, 203
 - Ellis Cosslett's electron microscopy, 202f
 - imaging, 280–281
 - improvement in efficiency, 199
 - limitation, 194–195
 - magnification, 196
 - McMullan's original incarnation, 198f
 - practical electronics work, 198
 - principles, 195–196
 - proceedings, 202
 - schematic diagram, 195f
 - Sheila Smith at controls, 201f
 - technical problems, 199
 - transmission microscope, 193
 - visual acuity, 202
- Scanning transmission electron microscopy (STEM), 221, 280–281
- aberrations, 287
 - correction, 288
 - CTF, 287
 - gold particles, 290, 291f
 - HR-TEM simulations, 288f
 - using image metal nanoparticles, 290
 - intensity profiles, 290f
 - Scherzer defocus, 287–288
 - simulation TEM micrographs
 - calculation, 289f
 - Z-contrast technique, 288–290
 - bimetallic gold-palladium nanoparticles, 281f
 - EDS spectrum detector, 286f
 - HAADF-STEM, 285–286
 - information transfer, in phase-contrast imaging, 281
 - operational modes, 281, 282f
 - optical arrangement, 282
 - practical guide, 291
 - electron beam sketches, 291–292, 292f
 - electron beam trajectories, 293f
 - focus conditions, 295f
 - in-focus and underfocus, 293
 - resolution, 291
 - ronchigram, 293, 294f
 - spot size and aperture, 292–293
 - principles
 - BF images, 283
 - BF-CTEM, 283
 - FEG, 282–283
 - Fourier transform, 285
 - high-resolution electron microscopy, 284
 - operation modes, 283
 - relativistic Dirac equation, 284–285
- Scherzer condition, 287
- Scientific Digital Imaging plc (SDI), 275
- Self-adjoint operator, 70
- examples, 70–71
 - properties, 70
- Self-compositions, 88
- SEM. *See* Scanning electron microscope; Structuring element map
- Semi-atom, 82
- Semi-graphitic carbon, 280
- Semilattices, 60
- Seminorm, 63
- Set generator, 159–160

- Shift-varying operators, 95–97
 adaptive morphology, 97–98
 adaptive neighborhoods, 97–98
 amoeba filters, 97
 geometry adaptive filters, 97
 SV operators, kernel and basis representation for, 98
 SEM, 95–96
 adjoint erosion, 96
 grey-level image functions, 96
- Shockley partial dislocation (SPD), 312–314
- Signal operators, 87
- SM algorithm. *See* Sampling of mechanical model algorithm
- SMI. *See* Strongly max-plus independent
- Smith, Sheila Vernon, 201
 at Cambridge, 205–206
 Coach's prow, 207f
 Fairwell to crew, 206–207
 motorcycling, 205f
 time for music, 208–209
- SOP. *See* Sum-of-products
- Spatially varying operators (SV operators), 95
 adaptive median, 170–171
 erosions, 168
 image operators, 168
 increasing operator, 169
 planar set operators, 170
 polar coordinates, 170
 representations, 168
 SEM, 168–170
 SV kernel, 169
- Spatially varying operators. *See* Shift-varying operators
- SPD. *See* Shockley partial dislocation
- Spectral representation
 eigenvalues, 77
 finite-dimensional vector spaces on, 76
 resolution of the identity, 77
- Spruce wood fiber, 222f
- Stack filters
 basis representation, 164–165
 grey-level output signal, 164
- Standards Room, 192
- State-of-the-art simulations, 321–325
- STEM. *See* Scanning transmission electron microscopy
- Stratified hierarchy, 16
- Strongly max-plus independent (SMI), 143
- Structuring element, 90
- Structuring element map (SEM), 95–96
 adjoint erosion, 96
 grey-level image functions, 96
 adaptive kernel, 97
 adaptive window, 96
- Structuring function. *See also* Structuring element map (SEM)
- Subbasis, 177–178
- Sublattice, 80
 sup-closed lattice, 80–81
 underlattice, 80
- Sum-of-products (SOP), 161–162
- Sup- \star combination, 116–117
 Hamel basis, 117
 max- \star and min- \star combination, 117
- Sup-closed lattice, 80–81
- Sup-generators, 82
 atom, 82
 dual atom, 82
 dual semi-atoms, 82
 semi-atom, 82
- Sup-semilattice, 80
- Suphomomorphism, 88–89
- Supremal convolution, 54, 95
- Supremum norm, 66–67, 78
- SV operators. *See* Spatially varying operators
- Systolic approach, 14f
 classical version, 13
 using remarks, 13–14
 Revol's approach, 13
 seed's exclusion, 14
- T**
- TEM. *See* Transmission electron microscope
- Testing motorcycles, 190
- Thorne, Ken, 208
- Three-dimensional image segmentation (3D image segmentation), 9–11
- Three-layer nanoparticle, 309, 310f
- TI. *See* Translation-invariant
- Tiplady's, 245
- Topological isomorphism, 71

- Transition metal chalcogenides, 319–320
- Translation-invariant (TI), 50–52
- Bas (ψ), 157
 - denoising, 157–158
 - dual set operator, 147
 - dual subbasis, 178
 - flat area opening, 179, 179f
 - Hamel basis, 158–159
 - increasing operators
 - adjoint erosions, 176
 - adjunction, 175
 - CWL, 174–175
 - dual kernel, 176
 - kernel, 175
 - semi-atom, 175
 - T-invariant dilation, 176
 - increasing set operators, 146
 - kernel property, 146
 - minimal kernel elements, 147–148
 - minimal subcollection, 149
 - morphological basis, 159
 - non-flat, 159
 - non-increasing operators
 - closed interval, 171
 - hit-miss operations, 173–174
 - inf-generating operator, 172
 - inf-separable, 173
 - kernel maximal closed intervals, 174
 - sup-generating operator, 171–172
 - sup-separable, 173
 - TI set operator, 172
 - nondegenerate operators, 146
 - openings and closings, 177
 - set dilation, 146
 - set erosion operator, 146
 - set operator bases, 150
 - signal operator, 156–157
 - subbasis, 177–178
 - TI filters, 158
 - u.s.c., 148–149
 - weighted erosions and dilations, 157
- Translations
- CWL signal space, 126
 - horizontal and vertical translations, 125
 - impulse, 125–126
 - monoid of signal erosions, 125
 - polar motions, 124
- Transmission electron microscope (TEM), 193–194. *See also* Scanning electron microscope (SEM)
- aberrations, 287
 - correction, 288
 - CTF, 287
 - gold particles, 290, 291f
 - HR-TEM simulations, 288f
 - using image metal nanoparticles, 290
 - intensity profiles, 290f
 - Scherzer defocus, 287–288
 - simulation TEM micrographs
 - calculation, 289f
 - Z-contrast technique, 288–290
 - bimetallic gold-palladium nanoparticles, 281f
 - EDS spectrum detector, 286f
 - HAADF-STEM, 285–286
 - imaging, 280–281
 - information transfer in phase-contrast imaging, 281
 - operational modes, 281, 282f
 - optical arrangement, 282
 - practical guide, 291
 - electron beam sketches, 291–292, 292f
 - electron beam trajectories, 293f
 - focus conditions, 295f
 - in-focus and underfocus, 293
 - resolution, 291
 - ronchigram, 293, 294f
 - spot size and aperture, 292–293
 - principles
 - BF images, 283
 - BF-CTEM, 283
 - FEG, 282–283
 - Fourier transform, 285
 - high-resolution electron microscopy, 284
 - operation modes, 283
 - relativistic Dirac equation, 284–285
- Transmittance law, 40
- Triumph Twin Motorbike, 205
- Two-dimensional algorithm (2D algorithm), 15. *See also* Benzécri algorithm
- aggregation index, 18

- image grey scale, 18
 - pseudo-code, 18f
 - time-consuming part, 18
- Two-dimensional Gaussian function (2D Gaussian function), 50
- U**
- u.s.c. function. *See* Upper semi-continuous function
- Ultrametrics, 16–17
- Umbra function, 54
- UNAM. *See* National Autonomous University of Mexico
- Unconditional convergence, 63–64
- Underlattice, 80
- Uniform convergence, 66–67
- Unitary operator, 71
- Upper semi-continuous function (u.s.c. function), 86
- V**
- Vectors. *See also* Linear spaces
- Vertical translations (V-translations), 119–120
 - function dilations, 120–121
 - impulse response map, 122–123
 - invariant function, 121
 - linear superposition, 122
 - nonlinear superposition principle, 122
 - scalar erosions, 122
- W**
- WBDF technique. *See* Weak-beam dark-field technique
- Weak-beam dark-field technique (WBDF technique), 311–312
- Weighted lattice (WL), 114–115
- Window, adaptive, 96
- Window transformations, 153
 - application area, 156
 - comparison, 154–155
 - discrete set operator, 153
 - finite union of erosions, 155
 - grey-level image processing, 155–156
 - hit-miss transformation, 155
 - increasing window operator, 155
 - locally defined operator, 154
 - matched filter, 154
 - one-to-one correspondence, 154
 - shape collection, 153–154
- WL. *See* Weighted lattice
- WS₂ catalyst, 319–320
 - nanowire catalysts, 326–334
- X**
- X-ray detector, 285–286
- X-ray photoelectron spectroscopy, 326–327
- Y**
- Yarmouth, 205
- Yorkshire, 217–219
- Z**
- Z-contrast technique, 288–290
- Zigzag nanoribbons, 321–325

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Contents of Volumes 151-176

Volume 151¹

Claas Bontus and Thomas Köhler, Reconstruction algorithms for computed tomography
Laurent Busin, Nicolas Vandenbroucke and Ludovic Macaire, Color spaces and image segmentation
Glenn R. Easley and Flavia Colonna, Generalized discrete Radon transforms and applications to image processing
Tomáš Radlička, Lie algebraic methods in charged particle optics
Valerie Randle, Recent developments in electron backscatter diffraction

Volume 152

Nina S.T. Hirata, Stack filters: from definition to design algorithms
Sameen Ahmed Khan, The Foldy–Wouthuysen transformation technique in optics
Saverio Morfu, Patrick Marquié, Brice Nofielé and Dominique Ginhac, Nonlinear systems for image processing
Tohru Nitta, Complex-valued neural network and complex-valued backpropagation learning algorithm
Jérôme Bobin, Jean-Luc Starck, Y. Moudden and M.J. Fadili, Blind source separation: the sparsity revolution
Ray L. Withers, "Disorder": structured diffuse scattering and local crystal chemistry

Volume 153

Aberration-corrected Electron Microscopy
Harald Rose, History of direct aberration correction
Maximilian Haider, Heiko Müller and Stephan Uhlemann, Present and future hexapole aberration correctors for high-resolution electron microscopy

Ondrej L. Krivanek, Niklas Dellby, Robert J. Kyse, Matthew F. Murfitt, Christopher S. Own and Zoltan S. Szilagy, Advances in aberration-corrected scanning transmission electron microscopy and electron energy-loss spectroscopy
Philip E. Batson, First results using the Nion third-order scanning transmission electron microscope corrector
Andrew L. Bleloch, Scanning transmission electron microscopy and electron energy loss spectroscopy: mapping materials atom by atom
Florent Houdellier, Martin Hýtch, Florian Hüe and Etienne Snoeck, Aberration correction with the SACTEM-Toulouse: from imaging to diffraction
Bernd Kabius and Harald Rose, Novel aberration correction concepts
Angus I. Kirkland, Peter D. Nellist, Lan-yun Chang and Sarah J. Haigh, Aberration-corrected imaging in conventional transmission electron microscopy and scanning transmission electron microscopy
Stephen J. Pennycook, M.F. Chisholm, A.R. Lupini, M. Varela, K. van Benthem, A.Y. Borisevich, M.P. Oxley, W. Luo and S.T. Pantelides, Materials applications of aberration-corrected scanning transmission electron microscopy
Nobuo Tanaka, Spherical aberration-corrected transmission electron microscopy for nanomaterials
Knut Urban, Lothar Houben, Chun-lin Jia, Markus Lentzen, Shao-bo Mi, Andreas Thust and Karsten Tillmann, Atomic-resolution aberration-corrected transmission electron microscopy
Yimei Zhu and Joe Wall, Aberration-corrected electron microscopes at Brookhaven National Laboratory

¹ Lists of the contents of volumes 100–149 are to be found in volume 150; the entire series can be searched on [ScienceDirect.com](https://www.sciencedirect.com)

Volume 154

Henning F. Harmuth and Beate Meffert, Dirac's Difference Equation and the Physics of Finite Differences

Volume 155

Dmitry Greenfield and Mikhail Monastyrskiy, Selected Problems of Computational Charged Particle Optics

Volume 156

Vasileios Argyriou and Maria Petrou, Photometric stereo: an overview

Fred Brackx, Nele de Schepper and Frank Sommen, The Fourier transform in Clifford analysis

Niels de Jonge, Carbon nanotube electron sources for electron microscopes

Erasmus Recami and Michel Zamboni-Rached, Localized waves: a review

Volume 157

Mikhail I. Yavor, Optics of charged particle analyzers

Volume 158

Péter Dombi, Surface plasmon-enhanced photoemission and electron acceleration with ultrashort laser pulses

Brian J. Ford, Did physics matter to the pioneers of microscopy?

Jérôme Gilles, Image decomposition: theory, numerical schemes, and performance evaluation

Stina Svensson, The reverse fuzzy distance transform and its use when studying the shape of macromolecules from cryo-electron tomographic data

Marc van Droogenbroeck, Anchors of morphological operators and algebraic openings

Dong Yang, Shiva Kumar and Hao Wang, Temporal filtering technique using time lenses for optical transmission systems

Volume 159

Cold Field Emission and the Scanning Transmission Electron Microscope
Albert Victor Crewe, The work of Albert Victor Crewe on the scanning transmission electron microscope and related topics

Lyn W. Swanson and Gregory A. Schwind, A review of the cold-field electron cathode

Joseph S. Wall, Martha N. Simon and James F. Hainfeld, History of the STEM at Brookhaven National Laboratory

Hiroimi Inada, Hiroshi Kakibayashi, Shigeto Isakozawa, Takahito Hashimoto, Toshie Yaguchi and Kuniyasu Nakamura, Hitachi's development of cold-field emission scanning transmission electron microscopes

Peter W. Hawkes, Two commercial STEMs: the Siemens ST100F and the AEI STEM-1

Ian R.M. Wardell and Peter E. Bovey, A history of Vacuum Generators' 100-kV STEM

H. Sebastian von Harrach, Development of the 300-kV Vacuum Generators STEM (1985–1996)

Bernard Jouffrey, On the high-voltage STEM project in Toulouse (MEBATH)

Andreas Engel, Scanning transmission electron microscopy: biological applications

Kenneth C.A. Smith, STEM at Cambridge University: reminiscences and reflections from the 1950s and 1960s

Volume 160

Zofia Baranczuk, Joachim Giesen, Klaus Simon and Peter Zolliker, Gamut mapping

Adrian N. Evans, Color area morphology scale-spaces

Ye Pu, Chia-lung Hsieh, Rachel Grange and Demetri Psaltis, Harmonic holography

Gerhard X. Ritter and Gonzalo Urcid, Lattice algebra approach to endmember determination in hyperspectral imagery

Reinhold Rüdénberg, Origin and background of the invention of the electron microscope

H. Gunther Rudenberg and Paul G. Rudenberg, Origin and background of the invention of the electron microscope: commentary and expanded notes on Memoir of Reinhold Rüdénberg

Volume 161

- Marian Mankos, Vassil Spasov and Eric Munro, Principles of dual-beam low-energy electron microscopy
- Jorge D. Mendiola-Santibañez, Iván R. Terol-Villalobos and Israel M. Santillán-Méndez, Determination of adequate parameters for connected morphological contrast mappings through morphological contrast measures
- Ignacio Moreno and Carlos Ferreira, Fractional Fourier transforms and geometrical optics
- Vladan Velisavlevic, Martin Vetterli, Baltasar Beruffell-Lozano and Pier Luigi Dragotti, Sparse image representation by directionlets
- Michael H.F. Wilkinson and Georgios K. Ouzounis, Advances in connectivity and connected attribute filters

Volume 162

- Kiyotaka Asakura, Hironobu Niimi and Makoto Kato, Energy-filtered x-ray photoemission electron microscopy (EXPEEM)
- Eireann C. Cosgriff, Peter D. Nellist, Adrian J. d'Alfonso, Scott D. Findlay, Gavin Behan, Peng Wang, Leslie J. Allen and Angus I. Kirkland, Image contrast in aberration-corrected scanning confocal electron microscopy
- Christopher J. Edgcombe, New dimensions for field emission: effects of structure in the emitting surface
- Archontis Giannakidis and Maria Petrou, Conductivity imaging and generalised Radon transform: a review
- Olivier Losson, Ludovic Macaire and Yanqin Yang, Comparison of color demosaicing methods

Volume 163

- Wolfgang S. Bacsá, Optical interference near surfaces and its application in sub-wavelength microscopy
- Ruy H.A. Farias and Erasmo Recami, Introduction of a quantum of time ("chronon"), and its consequences for the electron in quantum and classical physics
- Andrew Neice, Methods and limitations of subwavelength imaging

- A. Sever Škapin and P. Ropret, Identification of historical pigments in wall layers by combination of optical and scanning electron microscopy coupled with energy-dispersive spectroscopy
- Markus E. Testorf and Michael A. Fiddy, Superresolution imaging—revisited

Volume 164

- Amos Bardea and Ron Naaman, Magneto-lithography: from the bottom-up route to high throughput
- Román Castañeda, The optics of spatial coherence wavelets
- Junchang Li, Yanmei Wu and Yan Li, Common diffraction integral calculation based on a fast Fourier transform algorithm
- Marcel Teschke and Stefan Sinzinger, A generalized approach to describe the interference contrast and phase contrast method
- Dokkyu Yi and Booyong Choi, Nonlinear partial differential equations for noise problems
- Henning F. Harmuth, Harmuth corrigenda

Volume 165

- Natalie Baddour, Two-dimensional Fourier transforms in polar coordinates
- Neil V. Budko, Superluminal, subluminal, and negative velocities in free-space electromagnetic propagation
- Rowan Leary and Rik Brydson, Chromatic aberration correction: the next step in electron microscopy
- Michele Marrocco, Methods for vectorial analysis and imaging in high-resolution laser microscopy
- Tomoya Sakai, Masaki Narita, Takuto Komazaki, Haruhiko Nishiguchi and Atsushi Imiya, Image hierarchy in Gaussian scale space
- Yusuf Ziya Umul, The theory of the boundary diffraction wave
- Emil Wolf, History and solution of the phase problem in the theory of structure determination of crystals from x-ray diffraction measurements

Volume 166

- Valeriy Syrovoy, Theory of Intense Beams of Charged Particles

Volume 167

- Emmanuel de Chambost, A history of Cameca (1954–2009)
- Johan Debayle and Jean-Charles Pinoli, Theory and applications of general adaptive neighborhood image processing
- Mohamed ben Haj Rhouma, Mohamed Ali Khabou and Lotfi Hermi, Shape recognition based on eigenvalues of the Laplacian
- Nicolas Loménie and Georges Stamon, Point set analysis
- Leonid P. Yaroslavsky, Image recovery from sparse samples, discrete sampling theorem, and sharply bounded band-limited discrete signals

Volume 168

- Luca Geretti and Antonio Abramo, The synthesis of a stochastic artificial neural network application using a genetic algorithm approach
- Michel Jurlin, Josselin Breugnot, Frédéric Itthirad, Mohammed Bouabdellah and Brigitte Closs, Logarithmic image processing for color images
- Rainer A. Leitgeb, Current technologies for high-speed and functional imaging with optical coherence tomography
- Sergej A. Nepijko and Gerd Schönhense, Analysis of optical systems, contrast depth, and measurement of electric and magnetic field distribution on the object's surface in mirror electron microscopy
- Chad M. Parish, Multivariate statistics applications in scanning transmission electron microscopy
- Hidetaka Sawada, Fumio Hosokawa, Takeo Sasaki, Toshikatsu Kaneyama, Yukihito Kondo and Kazutomo Suenaga, Aberration correctors developed under the Triple C project
- Tobias Schulz, Martin Albrecht and Klaus Irmischer, Spatially resolved thermoluminescence in a scanning electron microscope

Volume 169

- Erchan Aptoula and Sébastien Lefèvre, Morphological texture description of grayscale and color images

- Vera Guarrera and Herwig Ott, Electron microscopy of ultracold gases
- Konstantinos Konstantinidis, Ioannis Andreadis and Georgios Ch. Sirakoulis, Application of artificial intelligence to content-based image retrieval
- Xingwei Yang, Daniel B. Szyld and Longin Jan Latecki, Diffusion on a tensor product graph for semi-supervised learning and interactive image segmentation
- S.A. Nepijko and G. Schönhense, Electron holography for electric and magnetic field measurement and its application for nanophysics

Volume 170

- A.S. Eggeman and P.A. Midgley, Precession electron diffraction
- Ray Hill, John A. Notte and Larry Scipione, Scanning helium ion microscopy
- Hone-Ene Hwang and Pin Han, Signal reconstruction algorithm based on a single intensity in the Fresnel domain
- Kazuhisa Sato, Toyohiko J. Konno and Yoshihiko Hirotsu, Electron microscopy studies on magnetic L1₀ FePd nanoparticles
- D.A. Zanin, H. Cabrera, L. de Pietro, M. Pikulski, M. Goldmann, U. Ramsperger, D. Pescia and John P. Xanthakis, Fundamental aspects of near-field emission scanning electron microscopy

Volume 171

- Gregor Esser, Wolfgang Becken, Werner Müller, Peter Baumbach, Josep Arasa and Dietmar Uttenweiler, Derivation of the reflection equations for higher order aberrations of local wavefronts by oblique incidence
- Lila Iznita Izhar and Maria Petrou, Thermal imaging in medicine
- Jean-Michel Tualle, Derivation of the radiative transfer equation in a medium with a spatially varying refractive index: a review
- Kamlesh Shrivastava and Mitsutoshi Setou, Imaging mass spectrometry. Sample preparation, instrumentation and applications
- Robert T. Thompson and Steven A. Cummer, Transformation optics

Tobias Klein, Egbert Buhr and Carl Georg Frase,
TSEM – a review of scanning electron
microscopy in transmission mode and its
applications

Michel Jourlin, Maxime Carré, Josselin
Breugnot and Mohamed Bouabdellah,
Logarithmic image processing: additive
contrast, multiplicative contrast and
associated metrics

Volume 172

Jay Theodore Cremer, Neutron and x-ray
microscopy, Part 1

Volume 173

Jay Theodore Cremer, Neutron and x-ray
microscopy, Part 2

Volume 174

Silicon-based Millimeter-wave Technology.
Measurement, Modeling and Applications

M. Jamal Deen and Ognian Marinov,
Measurement techniques and issues
Guennadi A. Kouzaev, M. Jamal Deen and
Natalia K. Nikolova, Transmission lines and
passive components

Mohamed H. Bakr and Mohamed H. Negm,
Modeling and design of high-frequency
structures using artificial neural networks
and space mapping

Oana Moldovan, Antonio Lázaro, François
Danneville, Rodrigo Picos, Bogdan Nae,
Benjamin Iniguez and M. Jamal Deen,
Nanoscale FETs

M. Daneshmand and R.R. Mansour, RF MEMS
switches and switch matrices

Natalia K. Nikolova, Maryam Ravan and Reza K.
Amineh, Substrate-integrated antennas on
silicon

Volume 175

Jay Theodore Cremer, Small Angle Scatter with
Correlation, Scatter and Intermediate
Functions

Jay Theodore Cremer, Nuclear Scatter of
Neutron Spin States

Christian Dwyer, Atomic-Resolution Core-Level
Spectroscopy in the Scanning Transmission
Electron Microscope

Partha Pratim Mondal and Alberto Diaspro,
Point Spread Function Engineering for Super
Resolution Single- Photon and Multi Photon
Fluorescence Microscopy

P. Murray and S. Marshall, A Review of Recent
Advances in the Hit-or-Miss Transform

Stephen J. Sangwine, Perspectives on Colour
Images Processing by Linear Vector
Methods using Projective Geometric
Transformations

Volume 176

Katsushige Tsuno, Damaschin Ioanoviciu, Early
History of Wien Filters

Damaschin Ioanoviciu, Katsushige Tsuno,
Aberration Theory of the Wien Filter

Katsushige Tsuno, Damaschin Ioanoviciu, Wien
Filter Instrumentation

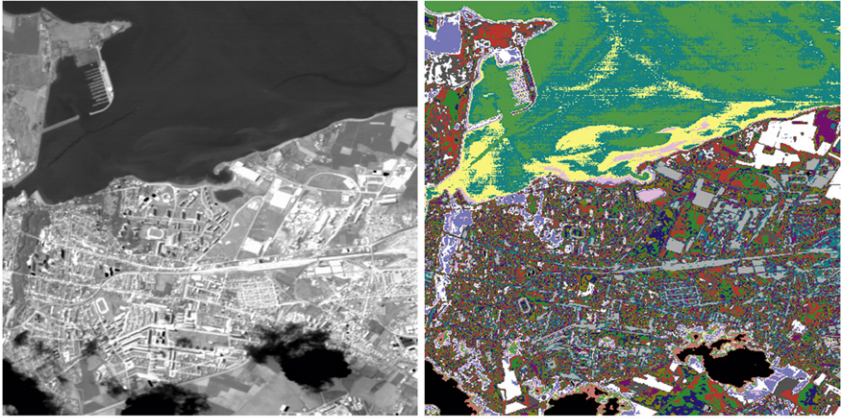
Katsushige Tsuno, Damaschin Ioanoviciu,
Simulation of Multipole Wien Filters

Damaschin Ioanoviciu, Katsushige Tsuno, Wien
Filter Applications to Ions

Katsushige Tsuno, Damaschin Ioanoviciu,
Application of Wien Filters to Electrons

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COLOR PLATES



(a)

(b)

PLATE 2b (Figure 2b on page 6 of this volume)

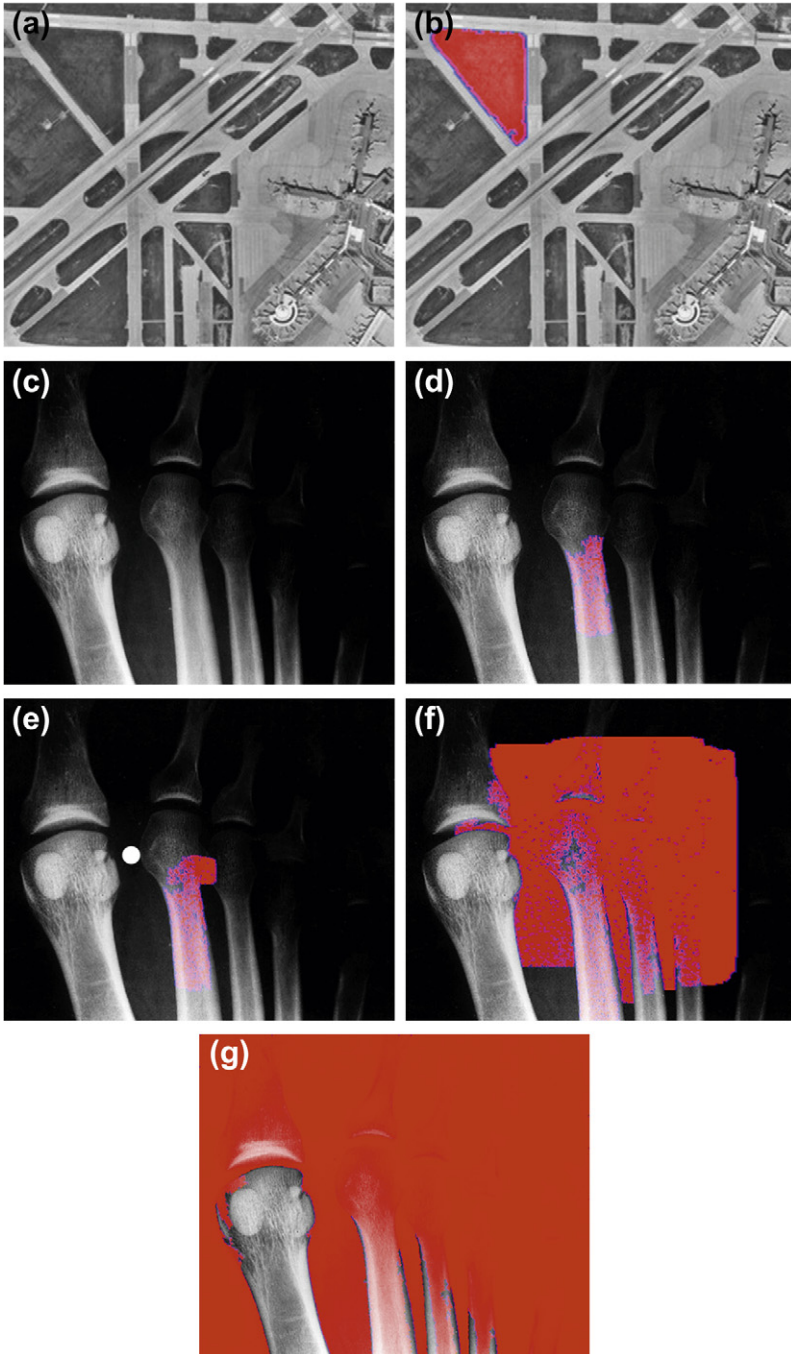
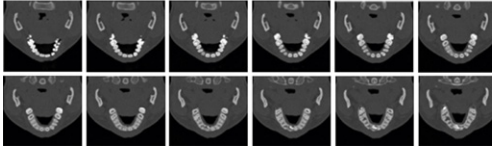


PLATE 3 (Figure 3 on page 10 of this volume)

(a)



(b)

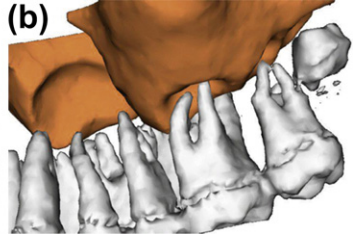


PLATE 4b (Figure 4b on page 12 of this volume)

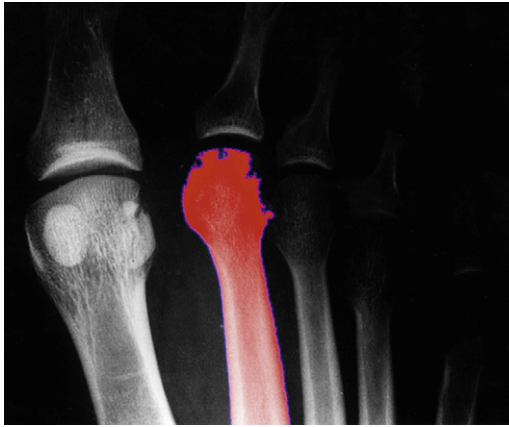
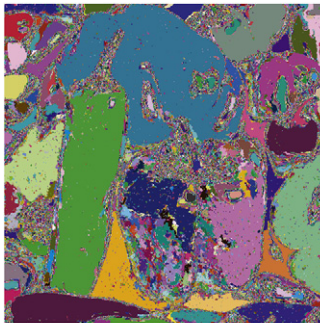


PLATE 5 (Figure 5 on page 12 of this volume)



(a)



(b)

PLATE 15 (Figure 15 on page 22 of this volume)



PLATE 16 (Figure 16 on page 22 of this volume)



PLATE 17 (Figure 17 on page 23 of this volume)

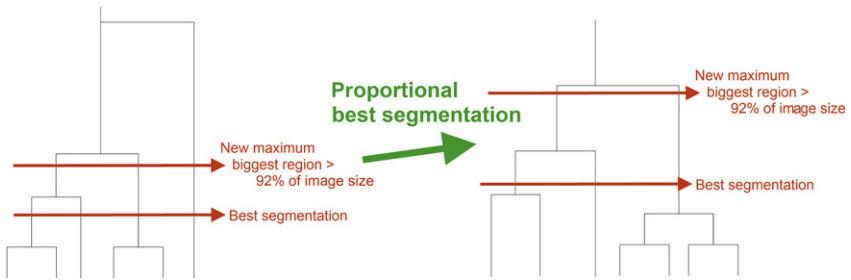


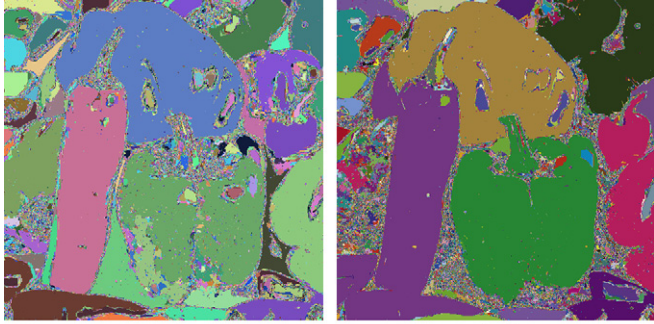
PLATE 18 (Figure 18 on page 23 of this volume)



(a)

(b)

PLATE 19 (Figure 19 on page 23 of this volume)



(a)

(b)

PLATE 20 (Figure 20 on page 24 of this volume)

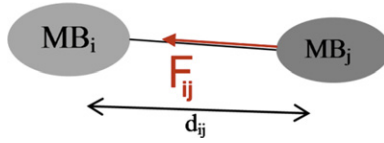
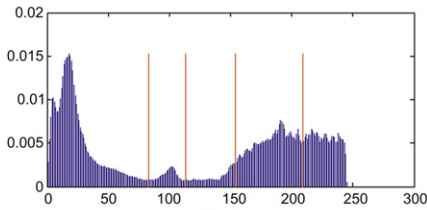


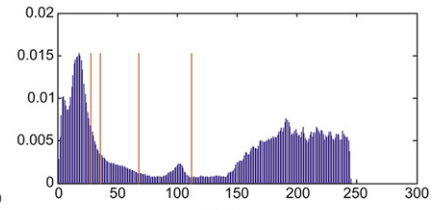
PLATE 22 (Figure 22 on page 25 of this volume)



(a)



(b)

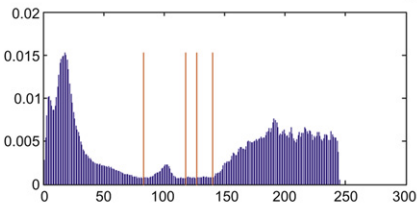


(c)

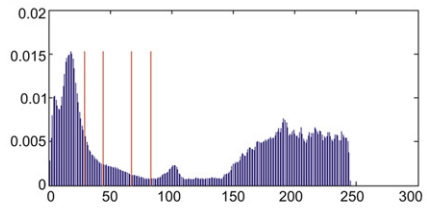
PLATE 27 (Figure 27 on page 34 of this volume)



(a)



(b)



(c)

PLATE 29 (Figure 29 on page 36 of this volume)



(a)



(b)

PLATE 33 (Figure 33 on page 39 of this volume)

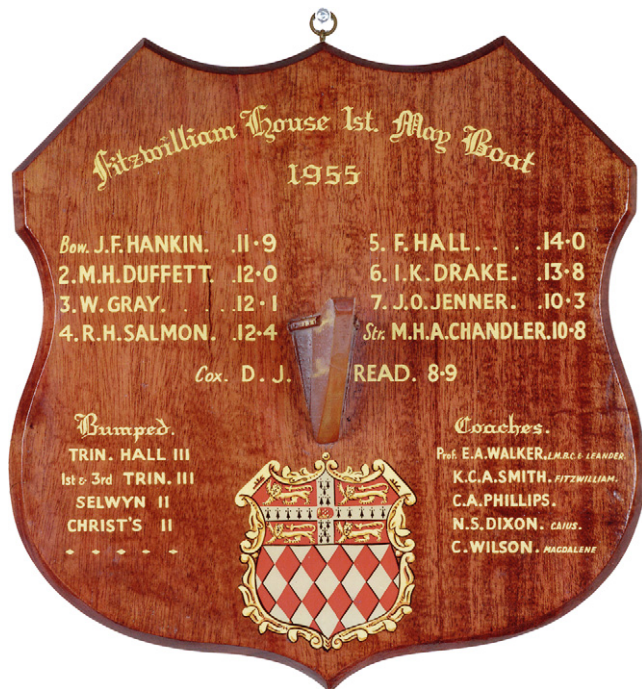


PLATE 6 (Figure 6 on page 207 of this volume)



PLATE 16 (Figure 16 on page 230 of this volume)



PLATE 18 (Figure 18 on page 233 of this volume)



PLATE 19 (Figure 19 on page 235 of this volume)



PLATE 20 (Figure 20 on page 235 of this volume)



PLATE 21 (Figure 21 on page 236 of this volume)



PLATE 24 (Figure 24 on page 252 of this volume)



PLATE 25 (Figure 25 on page 252 of this volume)



PLATE 28 (Figure 28 on page 256 of this volume)



PLATE 29 (Figure 29 on page 260 of this volume)



PLATE 32 (Figure 32 on page 271 of this volume)

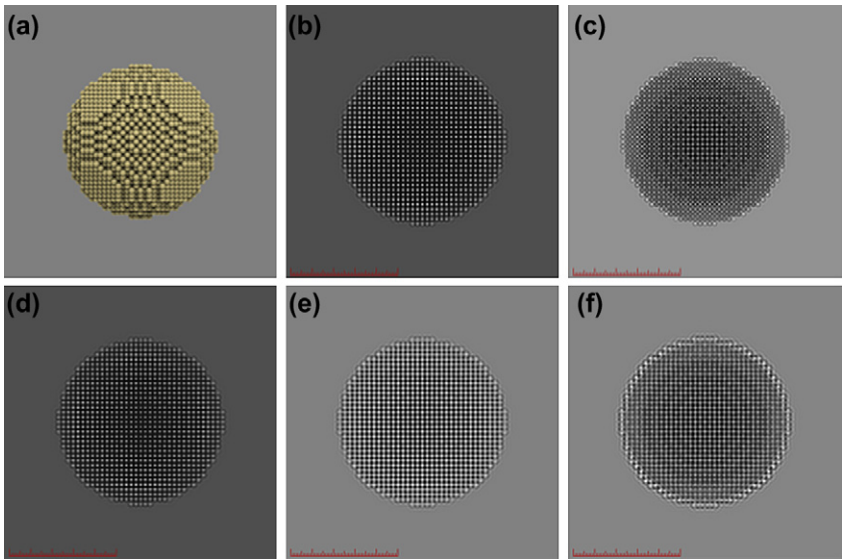


PLATE 4 (Figure 4 on page 288 of this volume)

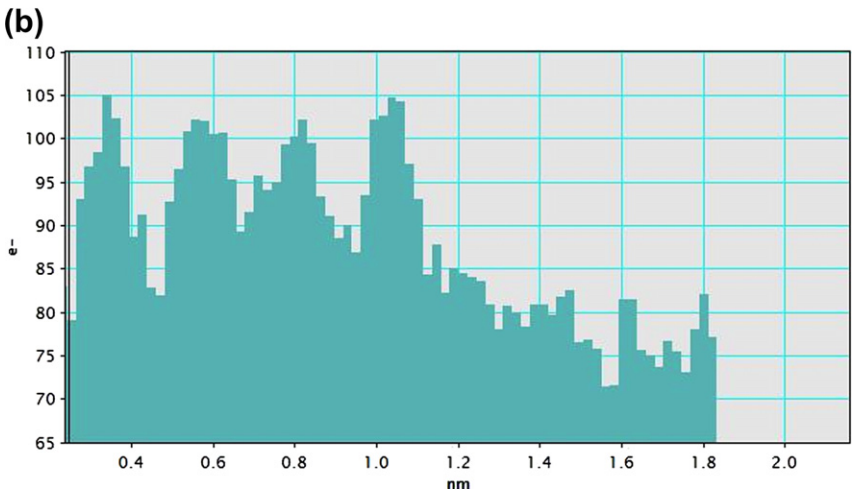
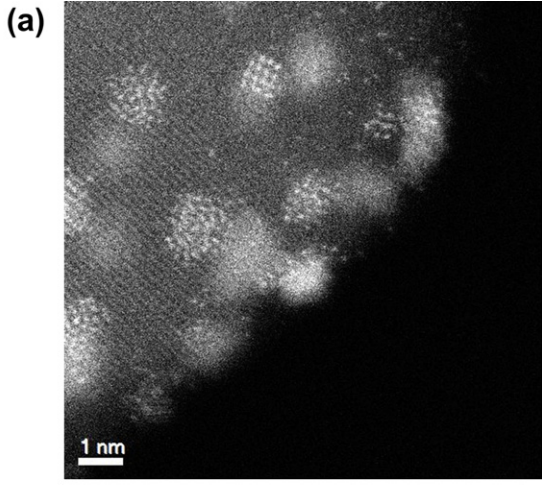


PLATE 12b (Figure 12b on page 296 of this volume)

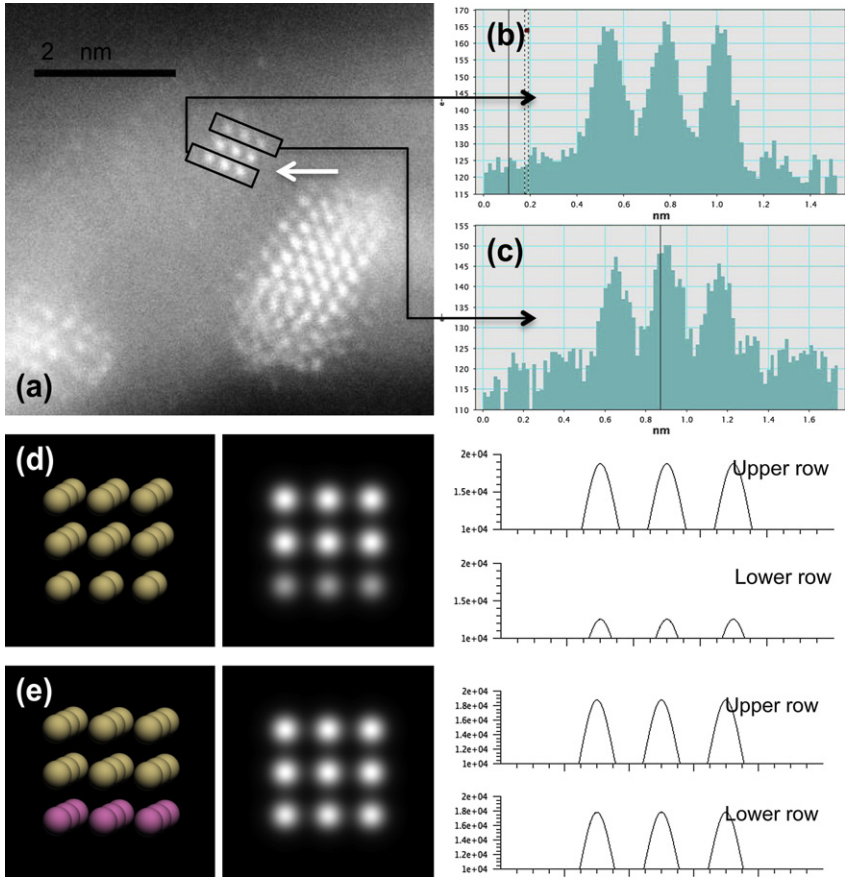


PLATE 14 (Figure 14 on page 298 of this volume)

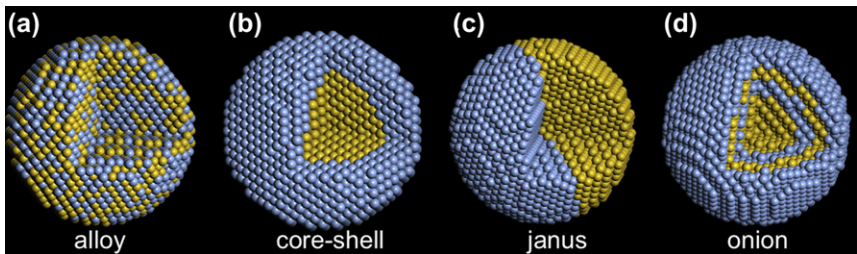


PLATE 19 (Figure 19 on page 305 of this volume)

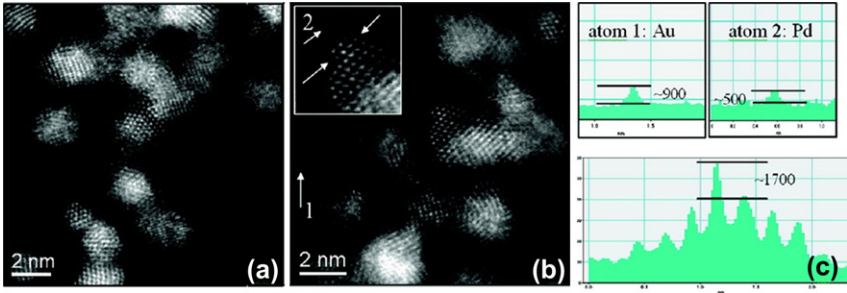


PLATE 20 (Figure 20 on page 306 of this volume)

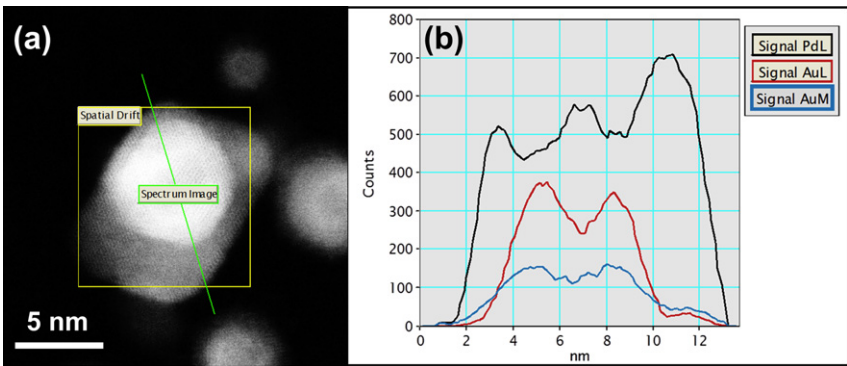


PLATE 22 (Figure 22 on page 308 of this volume)

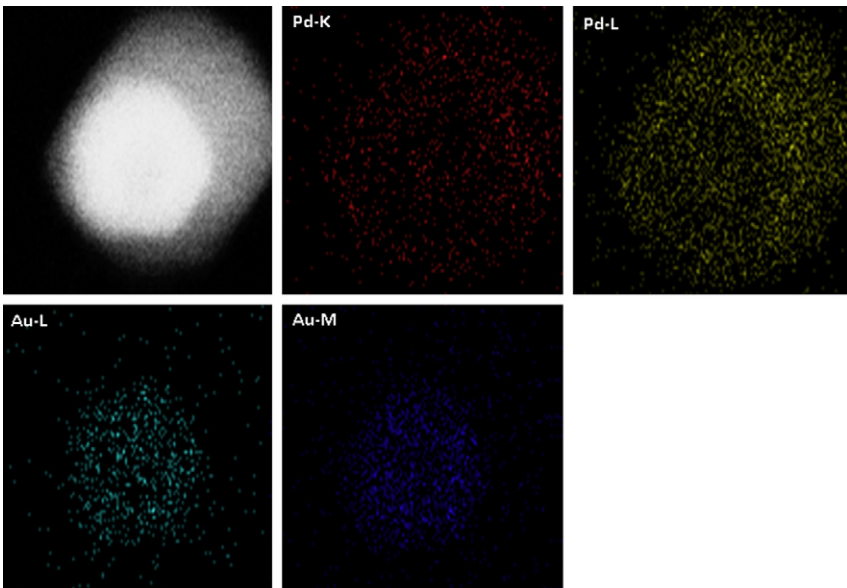


PLATE 23 (Figure 23 on page 309 of this volume)

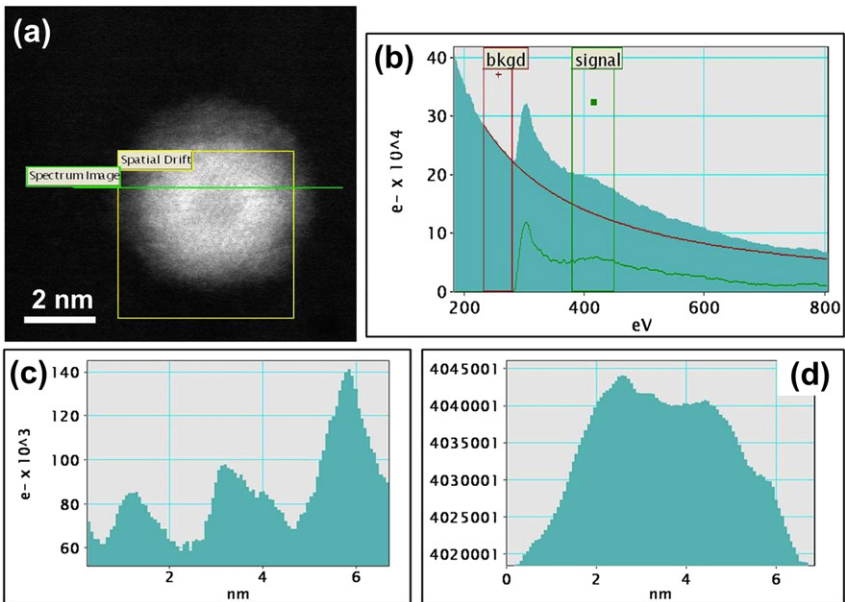


PLATE 24 (Figure 24 on page 310 of this volume)

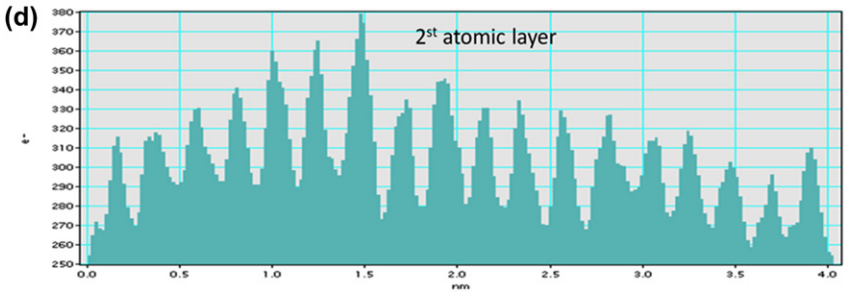
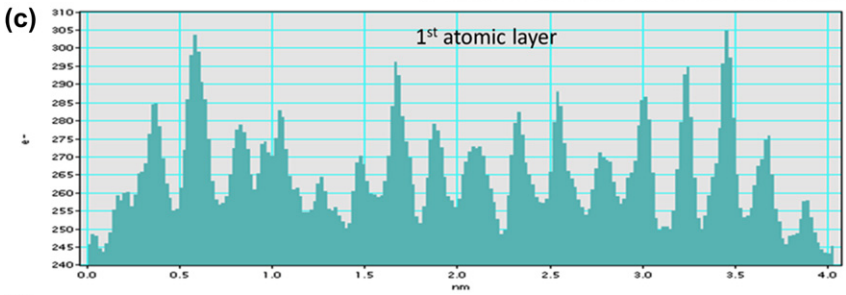
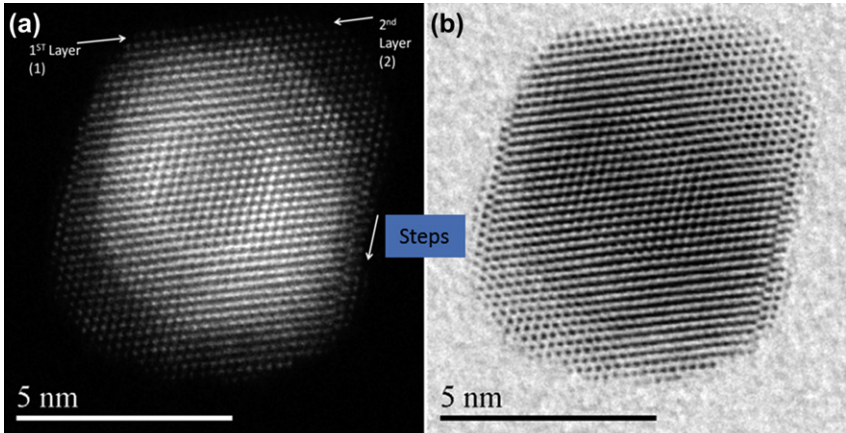


PLATE 28 (Figure 28 on page 313 of this volume)

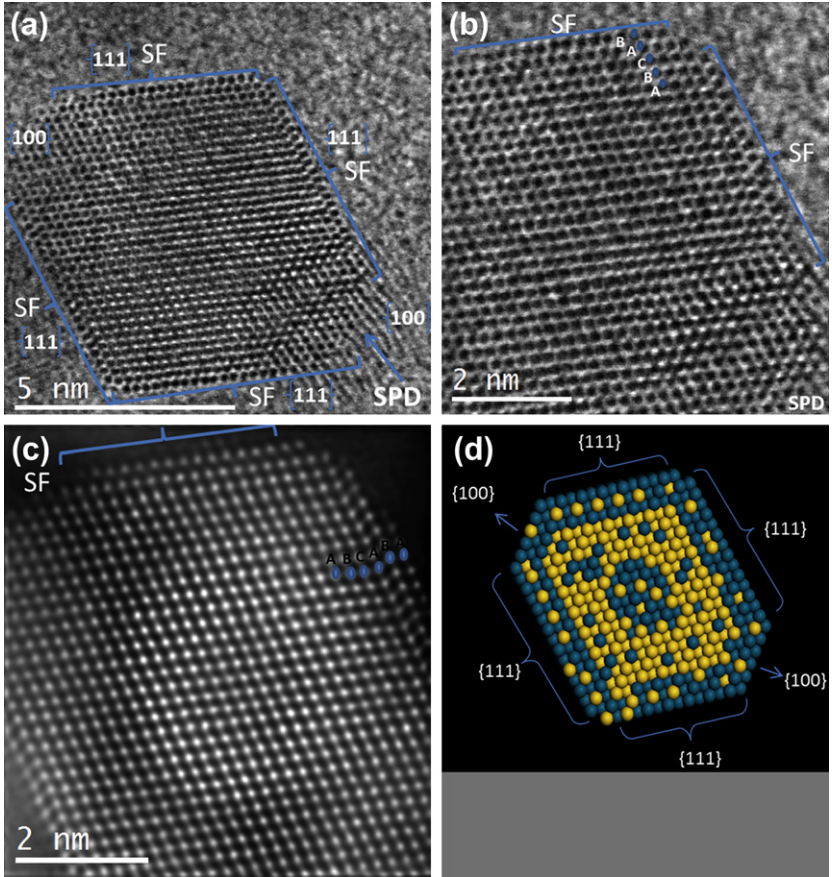


PLATE 29 (Figure 29 on page 314 of this volume)

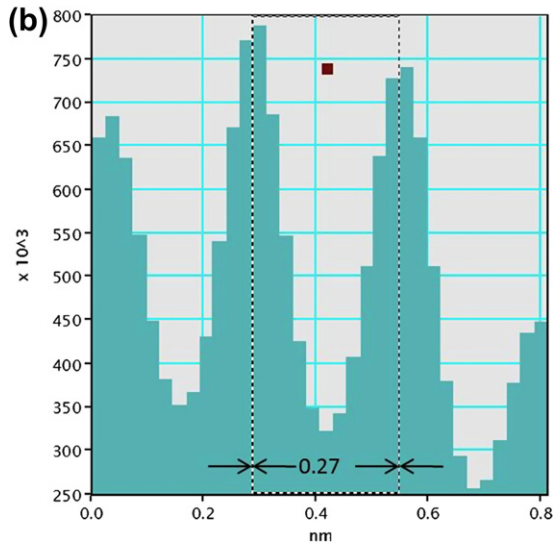
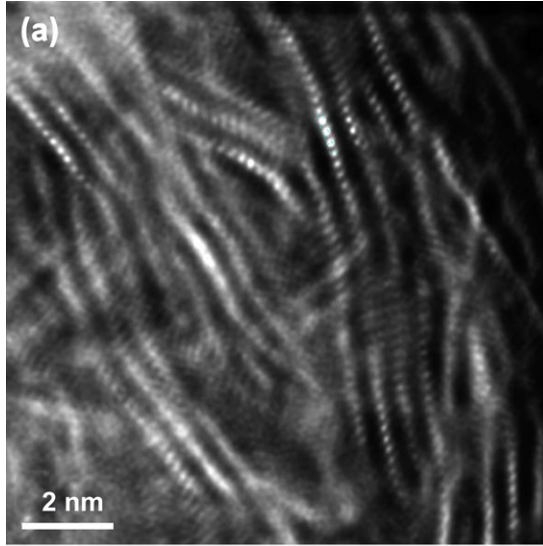


PLATE 34 (Figure 34 on page 322 of this volume)

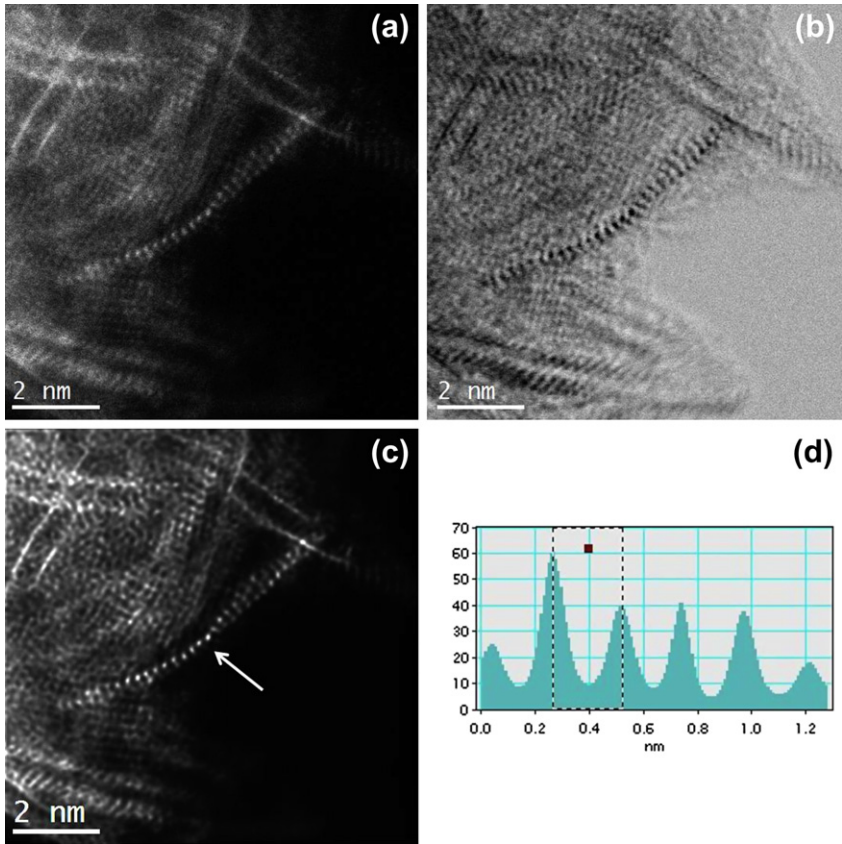


PLATE 35 (Figure 35 on page 323 of this volume)

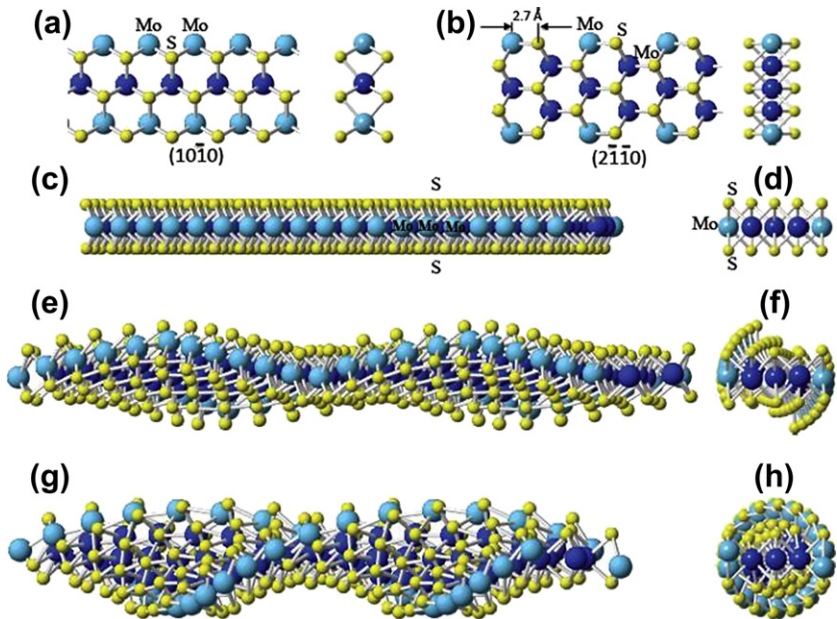


PLATE 36 (Figure 36 on page 324 of this volume)

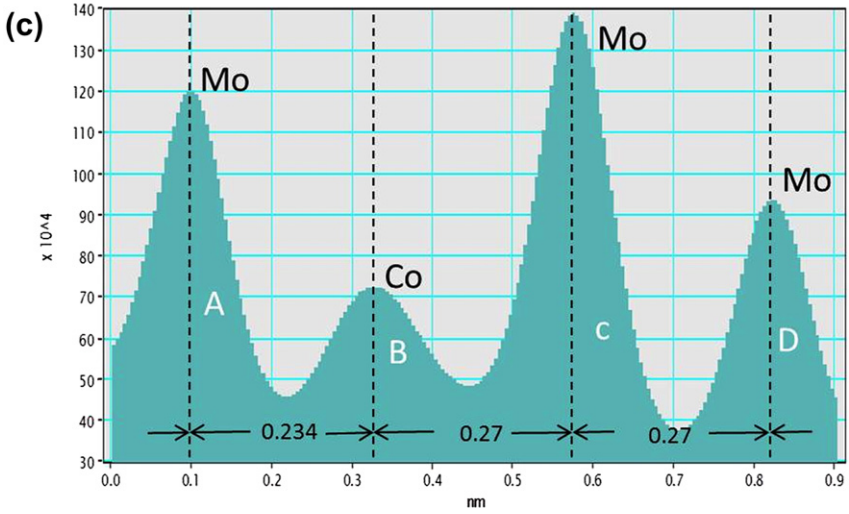
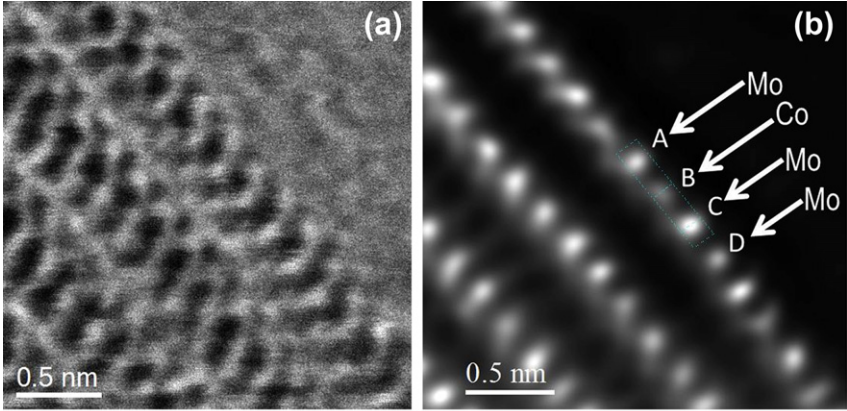


PLATE 38 (Figure 38 on page 328 of this volume)

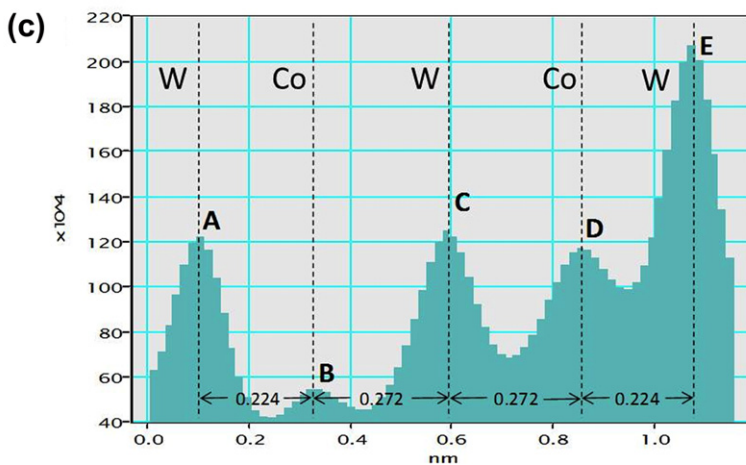
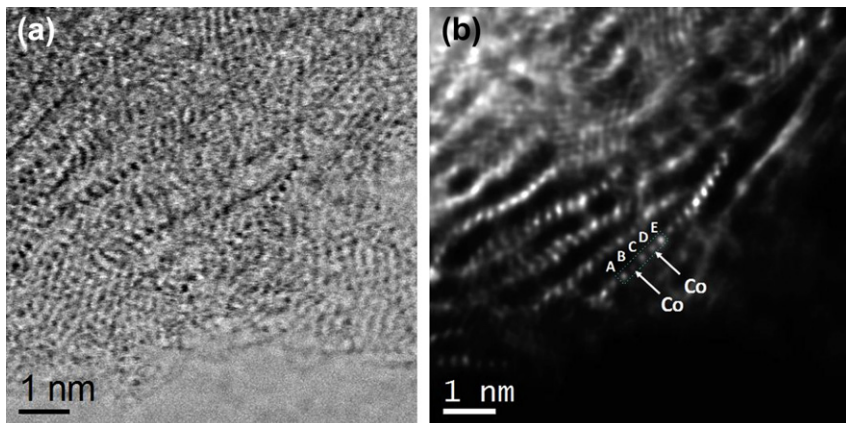


PLATE 40 (Figure 40 on page 330 of this volume)

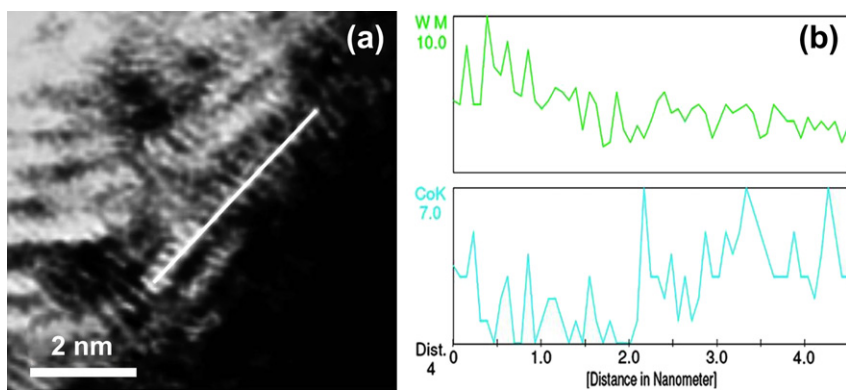


PLATE 41 (Figure 41 on page 331 of this volume)

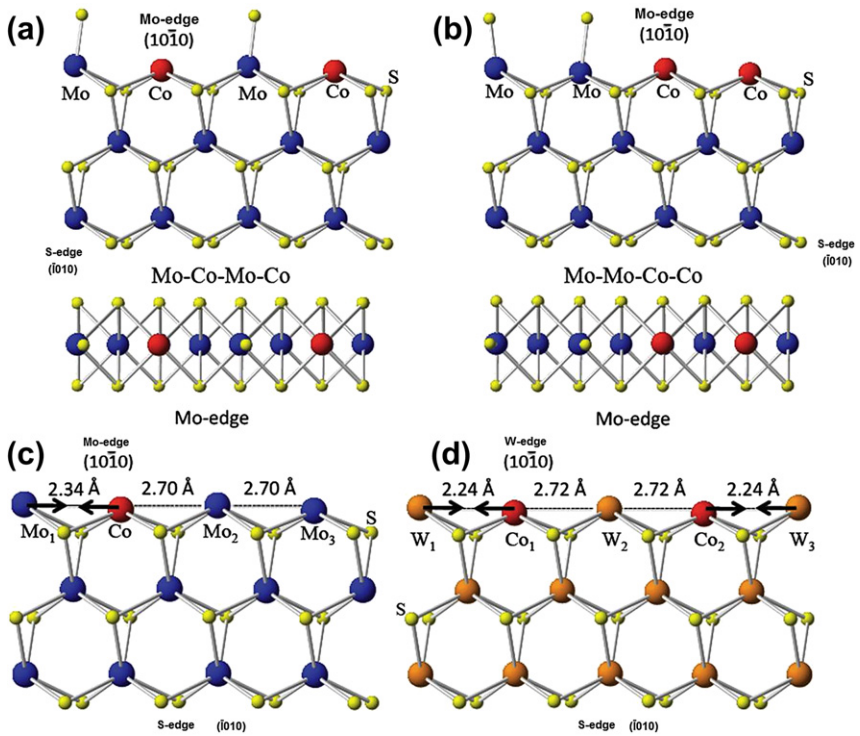


PLATE 42 (Figure 42 on page 332 of this volume)